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ACOUSTIC RECESSION GAGE DEVELOPMENT

J. O. Vindum, R. L. Eichorn, T. F. Foster, J. T. Kelly, T. K. Muller, R. E. Lundberg Acurex Corporation/Aerotherm Division 485 Clyde Avenue Mountain View, California 94042

20 January 1977

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Final Report for Period 30 June 1975 - 30 November 1976

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Prepared for

SPACE AND MISSILE SYSTEMS ORGANIZATION Air Force Systems Command/RSSE Los Angeles, California 90009

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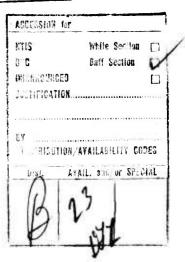
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NOTICE

This final report was submitted by the Aerotherm Division of the Acurex Corporation located in Mountain View, California, 94042, under Contract F04701-75-C-0164, with the Space and Missile Systems Organization, Los Angeles, California, 90009. Capt. Don Jackson was the SAMSO/RSSE Project Officer-in-Charge.

This technical report has been reviewed and is approved for publication.

DON E. JACKSON, Capt, USAF Project Officer

FOR THE COMMANDER:

JAMES M. MC CORMACK, Lt Col, USAF Chief, Reentry Technology Division Deputy for Reentry Systems Unclassified

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 χ^{20} . Abstract (Continued)

tests. Also included are details of the acoustical analysis performed using

several computer codes.

The main feature of the Resonant Acoustic Measurement Gage is that the object which is to be measured is acoustically excited at its resonant frequency or frequencies. It is from these frequencies that nosetip length and shape can be obtained.

Because of reduced funding levels in the instrumentation area, this program was temporarily halted. This report describes the status of the gages

at the time the contract was halted.

TABLE OF CONTENTS

Section		Page
1	INTRODUCTION AND SUMMARY	5
2	RECOMMENDATIONS FOR DESIGN AND HARDWARE CHANGES	9
	2.1 Bench Tests	9 9 9 10 10
3	HARDWARE CONFIGURATION	11
	3.1 Electronics	11
	3.1.1 Design Status	11 11 27 30 30 33
	3.2 Mechanical Hardware Development	33
	3.2.1 Sensor Construction	38 40 47 55 55
	3.3 50 MW Test Model Design	57
	3.3.1 Nosetip Configuration	57 58 58
4	DESIGN SUPPORT	61
	4.1 Bench Tests	61
	4.1.1 Bench Test Hardware	61 64 66
	4.2 1 MW Tests	69
	4.2.1 Test Objectives	69 69 74 74 75
	4.3 Analysis	75
	4.3.1 Methodology	83 110
	REFERENCES	125
	APPENDIX A — DETAIL HARDWARE DRAWINGS	127
	APPENDIX B — ELECTRONIC SCHEMATICS AND WIRING DIAGRAMS	185
	APPENDIX C — ELECTRONIC COMPONENTS PARTS LIST	211
	APPENDIX D — NONSTANDARD PARTS APPROVAL REQUEST	239

LIST OF ILLUSTRATIONS

Figure		<u>Page</u>
1	Flight electronics block diagram	12
2	Power supply	14
3	Input buffer	15
4	Phase comparator	17
5	Filter	18
6	Voltage controlled oscillator	19
7	Power amplifier	21
8	Lock detector	22
9	Noise detector	24
10	Package	25
11	System interconnects	26
12	Loop response	29
13	50 MW single mode test using flight electronics	35
14	Concentric transmitter/receiver	37
15	In-line flexural transmitter and receiver	39
16	Prototype accelerometer	41
17	Useful temperature range of various piezoelectric materials	43
18	Desired piezoelectric crystal shapes	45
19	Crystal test fixtures	46
20	Crystal clamping	48
21	Transmitter construction	51
22	Waveguide performance	53
23	50 MW test models	54
24	Bimorph test configuration	62
25	50 MW models 0 to 100 kHz sweep	71
26	1 MW Test 1 lock detection signal history	76
27	1 MW Test 2 lock detection signal history	77
28	1 MW Test 1 tracked frequency vs. time	78
29	1 MW Test 2 tracked frequency vs. time	79
30	Nosetip surface temperature	
31	Nosetip surface temperature	
32	Base temperature	82

LIST OF ILLUSTRATIONS (Concluded)

		Page
Figure		84
33	Schematic of SAP IV beam element applications to nosetip/waveguide system	
34	SAP IV beam analysis predictions of tungsten bar resonant frequencies	87
35	Comparison of 1 MW arc SAP IV beam analysis predictions and measurements for tungsten nosetip	94
36	Tungsten elastic modulus as a function of temperature	95
37	Predicted 1 MW arc tungsten temperature distributions as a function of time	97
38	Comparison of 50 MW arc SAP IV beam analysis predictions and measurements for a tungsten nosetip	98
39	Elastic modulus versus temperature for representative commercial graphites	99
40	One MW arc test results for a carbon/carbon nosetip	100
41	Comparison of 50 MW arc SAP IV beam analysis predictions and measurements for a carbon/carbon nosetip	102
42	First and fourth flexural resonant frequencies versus midpoint length	103
43	Shape uncertainty as a result of predicted frequency uncertainty	104
44	SAP IV quadrilateral brick element analysis	108
45	Fourth flexural beam type responses (DIAL code)	112
46	Elastic modulus of carbon/carbon material versus temperature	116
	First and fourth flexural resonant mode frequencies vs. midpoint length	119
47		120
48	First and fourth flexural resonant mode vs. corner length	121
49	Carbon/carbon nosetip geometry and material properties	121

LIST OF TABLES

Table		Page
1	Accuracy	28
2	Standard Parts Used (Passive)	31
3	Standard Parts Used (Active)	32
4	Nonstandard Parts Used	34
5	Physical Properties of Piezoelectric Materials	42
6	Acoustic Impedance of Various Materials	49
7	Material Properties	52
8	Adhesive Properties	56
9	50 MW Model Frequencies	70
10	1 MW Test Matrix	73
11	1 MW Model Frequencies	74
12	Comparison of SAP IV Beam Analysis and Measured Nosetip/Waveguide Resonant Frequencies	89
13	MSV Nosetip with Single Crystal Waveguide	92
14	Aluminum Nosetip First Compressional Resonant Mode Frequencies	93
15	Comparison of SAP IV Beam Analysis Resonant Mode Frequency Predictions and Data for Various Nose Shapes	106
16	Comparison of SAP IV Beam and Quadrilateral Brick Element Predictions	107
17	Comparison of Resonant Mode Predictions Utilizing SAP IV, DIAL and Shell Shock	109
18	Comparison of SAP IV Seam and DIAL Predictions and Measurements	111
19	Relative Costs of Predictions Utilizing SAP IV, DIAL, and Shell Shock	113
20	Effect of Temperature on Higher Order Modes	115
21	Sensitivity of Carbon/Carbon Flight Configuration Resonant Frequencies to Temperature	11
22	Nose Angle Uncertainty Due to Frequency Uncertainty	12

SECTION 1

INTRODUCTION AND SUMMARY

The purpose of this report is to describe all the engineering details of the Resonant Acoustic Measurement (RAM) gage. The design configurations, which were being developed at the time the program was temporarily halted and the design and test analysis which preceded the current gage configuration will be described. Because the gage program was halted during the developmental phase, the intent of this report is to serve as a detailed engineering report rather than an abbreviated final report. Appendices containing engineering details required for any subsequent startup of the program are included. These appendices contain reduced copies of blueprints, electronic schematics and layouts.

The Resonant Acoustic Measurement Gage was developed during the Passive Nosetip (PANT II) programs sponsored by the Space and Missile Systems Organization (SAMSO) under Contract F04701-75-C-0164. However, cutbacks in the funding level of the PANT III program resulted in the elimination of the gage developmental phase for 1977.

The two main objectives for the RAM gage program were to: (1) develop a flight-qualified recession gage for reentry vehicles, and (2) design and test a dual mode gage which would measure both recession and shape of an ablating nosetip.

Additionally, the RAM gage was developed to provide an instrument free from the disadvantages inherent in present (radioactive) gage designs and to also provide clear assessments of nosetip material performance in flight. This task was judged to be very important since advanced reentry system developments, including both flight tests and passive nosetip material evaluations, will continue during the next decade.

Specific material development activities considered were:

- 3-D carbon/carbon performance assessment
- Qualification of Rayon precursor substitute
- Qualification of low cost substitute of 3DCC
- Possible requirements for organometallic erosion resistant materials

Possible requirements for shape controlled (soft core) materials

Furthermore, in light of the increased accuracy required from future RV's, it will be desirable to obtain shape as well as recession information during the flight.

Comparisons of data from past flights show that nosetip material characteristics significantly impact the shaping performance of the nosetip. Four shape regimes are known to exist:

- Laminar blunt
- Laminar cap with turbulent forecone
- Slender turbulent biconic
- Blunt turbulent biconic

The determination of when, during reentry, these various shape regimes occur is critical to the material performance evaluation. One material may, for example, undergo late boundary layer transition and hence, develop a slender, fracture prone shape; another may experience transition early and develop a blunter, more stable, biconic shape.

It is necessary, through ongoing programs, to quantify the major contributors to inaccuracy by thorough analysis of flight dynamics data. Measurements of nose bluntness, transition, and recession are needed to discriminate between the nosetip and frustum-related components of reentry dispersion.

The single mode, or recession RAM gage, has demonstrated the ability to accurately indicate the maximum heating ray recession in both graphitic and metal ablation tests. Bench tests of the dual mode or shape/recession gage verified that this type of gage can be used to determine the bluntness and length of a reentry vehicle nosetip.

The manner in which these gages function is as follows. The recession (or single mode) gage operates by setting up a single compressional standing wave in the ablating nosetip. Recession is determined from the frequency versus time information generated during reentry. The recession and bluntness (or dual mode) gage operates by setting up two compressional or flexural waves in the nosetip using the fundamental frequency and the fourth harmonic. The fundamental frequency is used for recession information, and the fourth can be used to derive the forecone angle of the nosetip versus time. From these data, bluntness during reentry can be extracted.

The recession point determined by the gage is the "midpoint" length which is measured from the backface of the nosetip to the intersection of the bisected cone angle and the forecone surface.

The single or dual standing waves are produced by exciting the back end of the nosetip with a piezoelectric crystal transmitter; single or dual piezoelectric receivers are used to detect the

motion of the backface of the nosetip. At resonance, the transmitted and received signal is 90° out of phase. This phase relationship is used to accomplish the frequency tracking during reentry for both the single and dual mode gages.

On a previous program, the single mode gage was tested in the 50 MW arc jet at Wright-Patterson Air Force Base. The objective of this program was to configure it for flight and to use flight approved hardware. The dual mode gage configuration was bench-tested and subjected to the 1 MW arc jet at Acurex.

Transmission of the flight data was relatively easy. Because the frequency of the transmitter is determined by a Voltage Controlled Oscillator (VCO), the input voltage to this oscillator is the only data that needs to be transmitted to the ground during reentry.

The electronics for the gage had also been configured so that changes in the boundary layer noise could be detected. It was expected that this would happen during boundary layer transition, hence the gage could also be used to detect transition.

The primary difficulty during the developmental tests has been testing flight hardware by using subscale tests. Subscale testing of the dual mode gage has proved particularly troublesome due to the interaction of the nosetip vibration with transducer resonance. These difficulties will be explained in more detail in Section 2 of this report.

Section 3 includes the details of the electrical and mechanical configurations. Hardware configurations at the time of the program termination and background data explaining the selection of the current configuration are included.

Design support tasks such as bench tests, 1 MW tests, and Acoustics Analysis are described in Section 4.

The appendices include details which were important to the program. Appendix A includes reduced blueprints of the mechanical components of the gage as well as test hardware and support equipment needed for bench, 1 MW, and 50 MW tests. Reduced electronic schematics and component layouts are included in Appendix B; Appendix C contains parts lists for the electronic components. Appendix D includes copies of the Nonstandard Parts Approval Requests which were submitted in order to qualify the required electronic components.

It should be noted that the Resonant Acoustic Measurement (RAM) gage is also referred to as the Acoustic Recession Gage (ARG). Both designations are used in this report.

SECTION 2

RECOMMENDATIONS FOR DESIGN AND HARDWARE CHANGES

This report describes the work done during the PANT II program to develop and build a Resonant Acoustic Measurement gage. Near the end of the program several factors important to the design of a flight gage were discovered which should change the procedure for developing further acoustic gage hardware. These factors relate to testing and test hardware.

2.1 BENCH TESTS

Many of the bench tests were performed with aluminum models rather than carbon/carbon nose-tip models since aluminum was easier to obtain and work with. The different acoustic velocities, damping coefficients and acoustic impedances at times led to erroneous test conclusions. It is therefore recommended that all tests be done with carbon/carbon materials or materials which would at least duplicate the composite nature of the carbon/carbon materials.

2.2 MODEL SIZES

Subscale nosetip models behave quite differently than full-scale models. The resonant frequency of a subscale model is much higher than that of a full-scale model. This can have serious effects on hardware which was designed for full-scale models. For example, the resonant frequency of a subscale model may be at the resonant point of the transmitter waveguide or gage housing.

Subscale models are usually acoustically stiffer than full-scale models since the length is scaled down, but the shank diameter is kept constant for proper attachment of the acoustic gage. This increased stiffness can also lead to erroneous results.

2.3 1 MW AND 50 MW TESTING

Because of model constraints in test facilities such as the 1 MW and 50 MW arcs, subscale nosetips are tested in these facilities to qualify flight hardware. This causes the type of problems described in Section 2.2. It is recommended that only full-scale tests be done in such facilities as the RPL nosetip test facility. Subscale testing is not an effective method of proving the flight worthiness of acoustic hardware designed for full-scale nosetips.

2.4 APPLICABLE CARBON/CARBON MATERIALS

Since the exact nosetip configuration is not too critical for bench tests, used nosetips from RPL tests for example, are an excellent source of test nosetips.

2.5 DESIGN CHANGES

One of the major limitations in the current design was the anticipated available electrical power on the Material Screening Vehicle* (MSV). It might be useful to consider an acoustic electronics package which has its own battery so that more power could be made available during the few seconds of reentry.

^{*}Subscale reentry vehicle used for nosetip material testing.

SECTION 3

HARDWARE CONFIGURATION

This section describes the details of the electrical and mechanical hardware and the development and engineering which preceded the current configuration. The program was halted before the final flight configuration was completed, hence some of the design details may be missing or incomplete. The configurations to be used for planned 50 MW tests are also described.

3.1 ELECTRONICS

The description of the electronics has been divided into Design Status, Flight Electronics Description, Performance, Application, Reliability, and Test Electronics. Other details related to the electronics are included in Appendices B through D.

3.1.1 Design Status

The status of the electronics design at the time of termination was as follows:

- 1. All electronic subsystems were breadboarded and tested
- 2. Drafted schematics for the single mode gage were completed but not checked and finalized
- 3. Module layouts were completed and partially checked

The major efforts remaining were to finish the transformer and housing design and select the connectors and RFI filters as required. With completion of those tasks, a flight prototype could be fabricated.

3.1.2 Flight Electronics

The selected method of detecting nosetip recession is to continually excite the nosetip at its resonant frequency. To accomplish this, a phase-lock loop was used (see Figure 1, Flight Electronics Block Diagram).

A voltage controlled oscillator (VCO) excites the nosetip at some frequency close to resonance. A phase detector senses whether the phase angle between the transmitter and receiver is greater than or less than 90°, and commands the VCO to shift frequency in the appropriate direction to achieve the 90° phase angle characteristic of resonance.

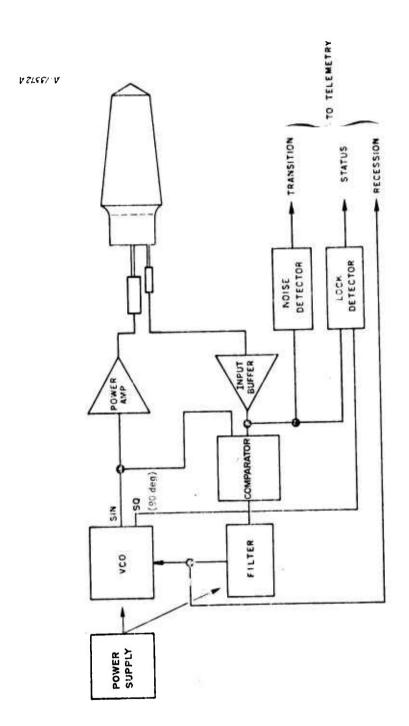


Figure 1. Flight electronics block diagram.

The VCO is designed so that the frequency is linearly proportional to input voltage, thus the VCO input may be fed directly to the telemetry system as an indication of resonant frequency.

Other functions provided in the flight electronics include a lock detector, which gives an indication as to whether the loop is locked to a good resonant peak, and a noise detector, which will hopefully provide information as to the occurrence of boundary layer transition. These two functions will be described in detail, along with the blocks in the recession gage loop, in the next section.

In addition, the flight circuitry incorporates a startup circuit which initializes the VCO to a predetermined frequency just below the anticipated nosetip resonance. The VCO then sweeps towards a higher frequency, causing the loop to sweep through the nosetip resonance, acquiring lock as it passes through resonance. Thus, it is guaranteed to lock to the appropriate nosetip resonance as it is turned on in flight.

The electronics is divided into several modules. Detailed descriptions of the modules are discussed here using simplified schematics. Detailed schematics are provided in Appendix B.

- a. <u>Package</u> The package, which will be discussed in greater detail later, consists of six microwelded, potted cordwood modules enclosed in an aluminum housing. Certain electronic parts, such as power transistors, transformers, and parts which must be selected to customize the electronics to a specific nosetip is located external to the potted modules.
- b. <u>Power Supply</u> The function of the power supply is to convert the incoming battery, with a voltage that can vary over a wide range, to a regulated DC voltage stable enough to obtain accurate system outputs. It provides two regulators of DC voltage. The first, V2 (20.5 volts) (see Figure 2, Power Supply), is the main source of power and this requires a current driving pass transistor which is located external to the module, heatsunk to the aluminum chassis. The other voltage, V1 (10.25 volts), is provided for bid levels only, and is obtained by dividing the main supply by 2 and by buffering with an operational amplifier. The regulator for the 20.5 volts is a standard integrated circuit, as shown in the simplified schematic.
- c. Input Buffer The input buffer is a simple voltage follower (see Figure 3) which picks up the high impedance crystal signal and buffers it so that it can drive the next stages. In addition, the gain can be selected so as to accommodate a range of signal levels which may result depending on waveguide and nosetip configuration. Some configurations may actually require attention, thus the buffer is designed to have a gain range 0.1 to 10. The input is protected against high voltage transients by diodes to ground and V_2 .

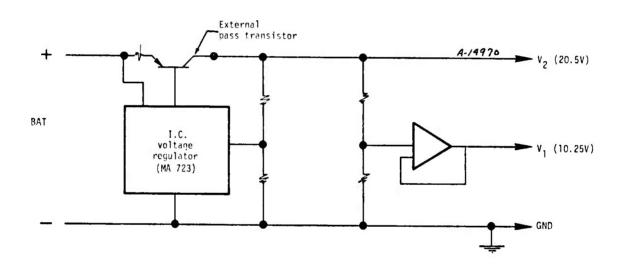


Figure 2. Power supply.

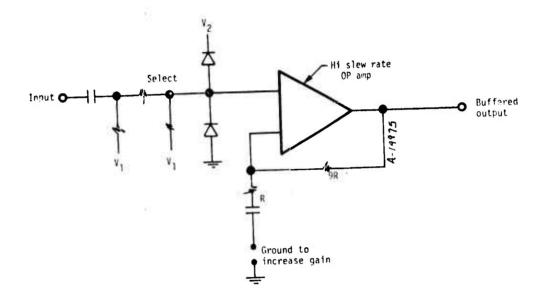


Figure 3. Input buffer.

- d. Phase Comparator The phase comparator (Figure 4) is a linear integrated circuit multiplier. Thus the output is the product of the two input signals. It can be shown that when the two input signals are of the same frequency, the output consists of a double frequency component (not of interest) and a DC voltage which is positive when the signals are in phase, negative when they are 180° out of phase, and going to zero at a 90° phase angle. Thus the output is nulled when the phase is at the desired 90° phase which occurs at nosetip resonance. A phase compensation network is provided at the input which takes in the VCO signal. This corrects for the small phase error which occurs in the power amplifier and input buffer. Resistors must be selected to trim the multiplier output to zero at the desired 90° phase angle.
 - e. Filter The filter is a simple operational amplifier integrator which functions to remove the high frequency components from the multiplier, determines the frequency response of the loop, and eliminates the extraneous acoustic noise signals. The startup sequence is located in this section also; a startup circuit, in the module containing the input buffer controls a switch which places the filter in two different modes of operation. In the startup mode (see Figure 5), the input signal is locked out, and the output of the filter is biased at a fixed 5 volts DC. This condition exists until the power supplies have stabilized. When the startup circuit commands the search and lock mode, the filter becomes an integrator and a current is fed into the integrator input through the resistor to connect to $\mathbf{V_2}$. This causes the integrator voltage to ramp negative. Since the VCO input characteristics are such that decreasing voltage yields increasing frequency, the VCO frequency increases as the filter is ramping negative. When a large nosetip resonance is experienced, the signal at the input overwhelms the ramp current, and the integrator voltage stays locked at a fixed level. This level will be set to the specific nosetip frequency at 4.5 volts. This gives the output enough range to continue to decrease when the nosetip frequency increases due to recession.
 - f. Voltage Controlled Oscillator The voltage controlled oscillator (Figure 6) is an integrated circuit function generator with a frequency linearly proportional to the input current. A resistor network is placed on the front to convert the filter voltage to a current. A capacitor of the appropriate value is selected to make the VCO frequency equal to the nosetip resonant frequency with a 4.5-volt input. Since both the resistor network and the capacitor network directly control frequency, components with low temperature coefficients are chosen. In addition, two resistors are selected to minimize

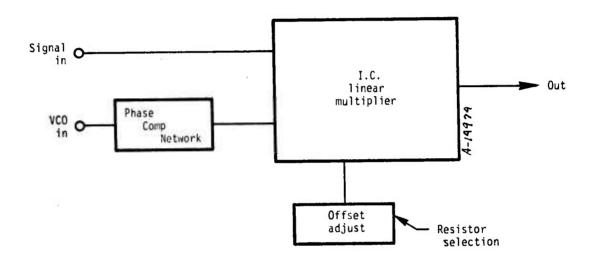


Figure 4. Phase comparator.

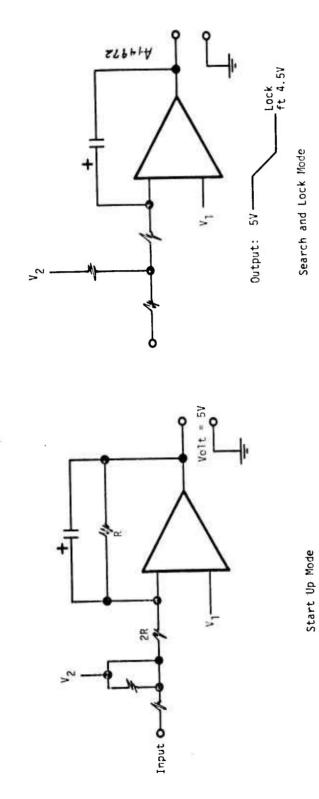


Figure 5. Filter.

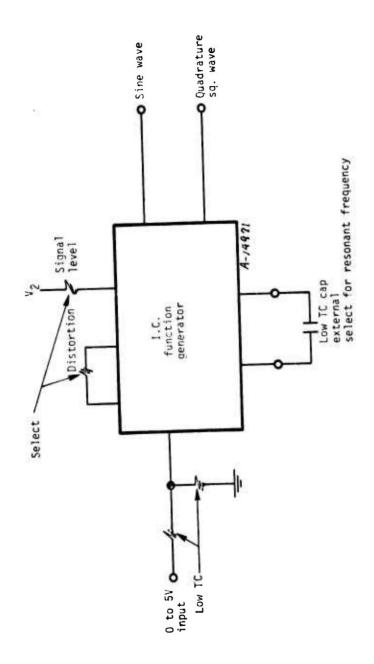


Figure 6. Voltage controlled oscillator.

sinewave distortion and to adjust the sinewave output to the appropriate amplitude. In addition to the sinewave output, the function generator has a squarewave output which is at 90° phase to the sinewave. This squarewave is used in the lock detector to be decribed later.

g. Power Amplifier — The power amplifier consists of a high slew rate amplifier coupled to a power gain stage. The power transistors are external to the potted module and are heat sunk to the aluminum chassis. Power is supplied to the output directly from the battery, since high currents required to drive the crystal would result in a large power loss if supplied through the regulated supply. The power stage is designed to operate with peak voltages as close as possible to the power supply rails to minimize power consumption. A power transformer steps up the voltage from the power stage to the crystal in order to provide as large a driving force as possible. The turns ratio is dependent upon the size of the crystal used. Since the crystal is a capacitive load, the transformer reflects a load to the power stage which has a capacitive value equal to the turns ratio of the transformer squared, times the capacitance of the crystal. This reflected capacitance results in a power dissipation in the power stage which is expressed by:

$$P = \frac{VI}{\pi}$$

where V is the battery voltage and I is the peak output current into a capacitive load. Of course, I increases with capacitance and with frequency. The power stage is designed to handle about 1 amp into the transformer input, resulting in about 8.9 watts power dissipation. If the maximum frequency is 50 kHz and the peak output voltage is 12 volts (half the minimum supply voltage) then the reflected capacitance can be calculated to be 0.26 microfarad maximum. Thus, if a transmitter crystal selected has a total capacitance of 0.0026 microfarad, the maximum turns ratio is 10 and the output voltage to the transmitter is 120 volts peak, or 85 volts rms. Although the transformer design was never finalized, it was anticipated to be wound on a ferite toroid of about 0.8-inch diameter. The power amplifier has an additional input provided so that when dual mode operation is desired the second VCO can be summed in. (Shown grounded in Figure 7.)

h. <u>Lock Detector</u> — The lock detector circuit (Figure 8) is a synchronous demodulator and filter which used the squarewave output from the VCO to demodulate the input signal. The filter thus contains a DC level which corresponds to the magnitude of the phase component

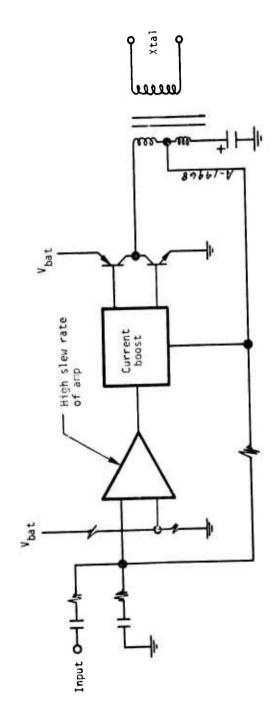


Figure 7. Power amplifier.

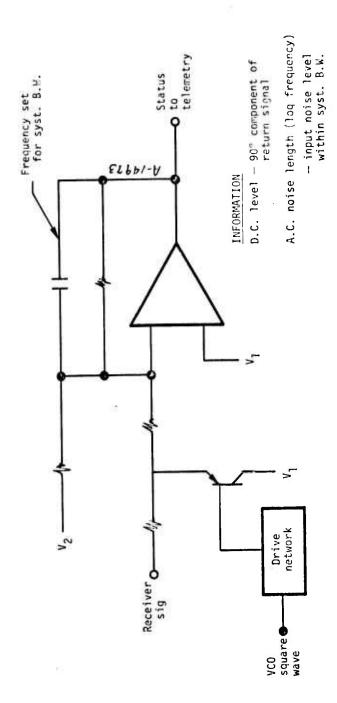


Figure 8. Lock detector.

of the received signal. Since the squarewave is in quadrature with the VCO sinewave signal, the lock detector responds to the 90° component of the input signal with respect to the crystal drive signal. Thus, a good resonance producing a strong quadrature component produces a large DC output. It is admittedly difficult to determine, considering that the strength of a resonance may vary during the conditions incurred during flight, at just what level indicated that lock is maintained. However, the lock detector can provide additional information to help interpret flight data from the recession gage. In addition, the lock detector will contain an AC noise signal which is proportional to the noise encountered within the bandwidth of the phase lock loop. Thus if the loop is overcome by acoustic noise, the lock detector will provide that information.

- i. Noise Detector The noise detector is designed to measure the high frequency noise encountered during flight. Since the input signal contains the recession gage signal as well as the noise, the recession gage signal must be removed. This is the purpose of the bandpass filter at the noise detector input (see Figure 9). The design center for this filter was selected as 300 kHz, although any appropriate frequency within the response of the receiver transducer may be selected. The output from this filter is rectified and the DC component recovered with a low pass filter. Since the noise level could have a large dynamic range which is essentially unknown before flight, it was decided that a logarithmic output response was desired. Thus the rectified output is fed through a logarithmic amplifier and a level shifter to condition the signal to telemetry levels.
- j. <u>Packaging</u> In order to meet the high shock and vibration environment, the electronics are packaged in six potted modules (welded cordwood construction) which are inserted into holes in an aluminum housing (see Figure 10). Transistors dissipating large power are attached directly to the aluminum housing. The module interconnects are soldered wires. External components which are selected to adapt to a specific nosetip are soldered to the module terminals. These interconnects and external components are potted in place before attaching the lid.

Figure 11 shows how the system is partitioned into modules and what external parts are required.

The electronics for a dual mode gage may be assembled by adding an additional phase and lock detector module and an integrator and VCO module. The interconnects between the two modules are identical, and the phase detectors share the same input. The output of the second VCO is attached to the unused input on the power amplifier.

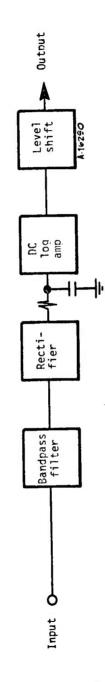


Figure 9. Noise detector.

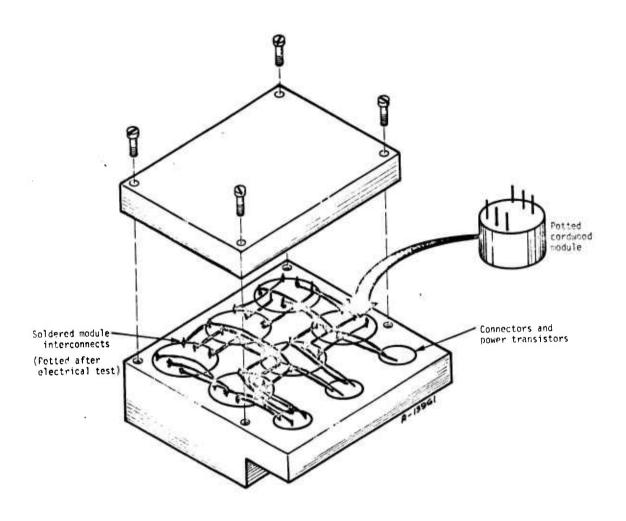


Figure 10. Package.

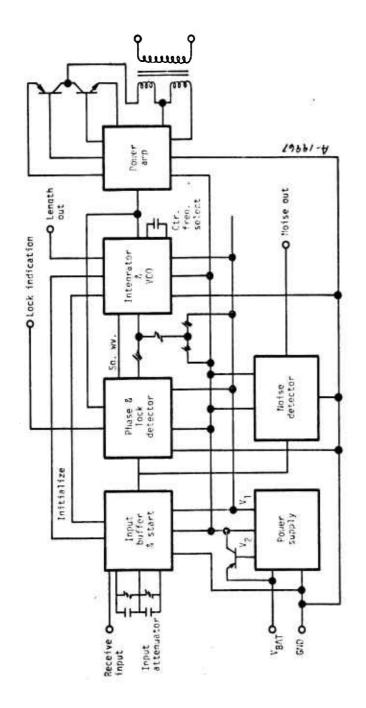


Figure 11. System interconnects.

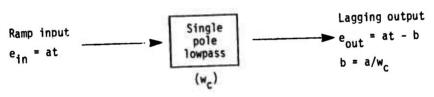
3.1.3 Performance

Accuracy — The error in the recession measurement due to the electronics is small compared to errors from various mechanical effects (such as heating). Table 1 lists the major error sources and the contribution to system error. The largest error source is the system lag, which is the amount the system falls behind a quickly recessing nosetip.

Frequency Response and Noise Rejection — The loop response for a typical loop response is shown in Figure 12. The response is a single pole roleoff beyond unity gain, thus assuring loop stability. The unity gain frequency is determined by the filter cutoff frequency in conjunction with the return signal level and phase comparator gain. Changing signal level in flight can change the loop response. The model lag, which does not affect loop response for this case, is determined by the model resonant bandwidth.

The unity gain cutoff frequency is chosen as a trade-off between noise rejection and speed of tracking. The minimum 28-Hz cutoff frequency was chosen as follows:

Required System Bandwidth



Assumptions: Starting resonant frequency 20 kHz

Ending resonant frequency 40 kHz

Time of event 4 sec

Requirement: Slew rate > 5,000 Hz/sec

Max lag > 28 Hz*

 $W_{C} = 5,000/28 = 178 \text{ rad/sec}$

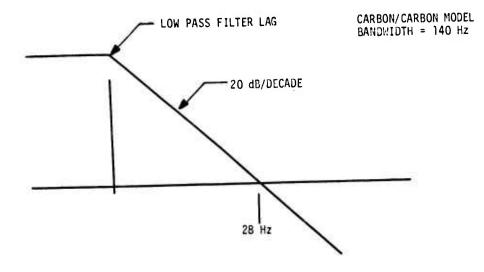
 $F_c = 28 \text{ Hz}$

Experiments have shown that the system can operate with a signal-to-noise ratio of 2.5 to 1 (noise being within the bandwidth of the system). Further experiments have indicated that the acoustic recession signal at nosetip resonance is as high as 30 g's rms. Thus the system could operate with about 12 g's rms of noise within the 28-Hz bandwidth. This represents a noise density of 2.27 g/ $\sqrt{\rm Hz}$, or a total noise of 1,200 g's in the 300-kHz bandwidth. Unfortunately, that much noise would saturate the input stage. The input amplifier is scaled to

Model bandwidth 140 kHz, follow within 0.2 bandwidth.

TABLE 1. ACCURACY

Error Source	Contribution
Phase Detector — Static Error	0.03%
System Lag	0.13%
VCO Drift	0.10%
Capacitor Drift	0.05%
Resistor Drift	0.05%
RSS Tota	0.18%
Assumptions: Model Q = 140 Temperature Drift = 20°C	



TYPICAL LOOP RESPONSE (USED AT 50 MW)

Figure 12. Loop response.

accept a total noise signal five times the basic recession gage signal, or about 150 g's rms.

3.1.4 Application

Various nosetip lengths, shapes, and materials will result in differing nosetip initial resonant frequencies, bandwidths, and receiver signal strengths. In addition, various flight profiles may result in various recession rates and noise levels. It is therefore desirable to customize each unit to optimize the above parameters for the particular flight.

Each of the potted modules may be built far in advance, along with the housing and hardware. The unit can then be customized at final assembly by selection of a few components mounted external to the modules. A summary of the steps in customizing follows below.

Final Assembly Procedure

- 1. Insert fully tested, potted modules into housing
- 2. Wire interconnects, power transistors, EMI filtering, etc.
- 3. Temporarily install "custom" components
- 4. Perform functional test
- 5. Store this assembly until nosetip is known

Adapting Electronics to Specific Nosetip

 The following nosetip/mission parameters must be known (Column 1). The electronic circuit parameter in Column 2 may then be calculated. The circuit parameter is then fixed by the selection of a passive component (resistor or capacitor).

Nosetip Parameter

Resonant frequency Receiver signal level Maximum recession rate Nosetip bandwidth

Circuit Parameter

VCO center frequency Input buffer gain Loop frequency response search speed Integrator time constant

- 2. Attach selected components
- Perform functional test
- 4. Apply potting, lip
- 5. Acceptance testing

The calculation of values, final assembly, testing, and potting would take about 3 days. The time required for acceptance testing would depend on the requirements of the procuring agency.

3.1.5 Reliability

In order to assure a high reliability, a program was in progress in accordance with a program plan previously published (Reference 1). This plan defined the standard parts to be used, how the parts are to be applied, and the procedures for approval of nonstandard parts. In addition, various parts screening was called out. Tables 2 and 3 give a summary of the standard parts used, and

TABLE 2. STANDARD PARTS USED (PASSIVE)

Mil Designator	Mil Spec	Туре	Qty
RCR07	MIL-R-39008	Resistor, Carbon	10
RNR55K	MIL-R-55182	Resistor, Metal Film	54
RNR55J	MIL-R-55182	Resistor, Metal Film (25 ppm)	4
RWR81	MIL-R-39007	Resistor, Power Wirewound	2
CKR05	MIL-C-39014	Capacitor, Ceramic	21
CSR13	MIL-C-39003	Capacitor, Solid Tantalum	8
CLR65	MIL-C-39006	Capacitor, Sintered Anode, Tant	3

TABLE 3. STANDARD PARTS USED (ACTIVE)

irt No.	Description	Quantity
N2907A	Transistor, PNP, Low Power	3
2N2920	Transistor, NPN, Dual	1
N2945A	Transistor, PNP, Chopper	4
2N3501	Transistor, NPN, Low Power	2
2N3637	Transistor, PNP, Low Power	2
2N3792	Transistor, PNP, High Power	2
1N4148	Diode, Signal	15
MA723	Voltage Regulator	1
1N4148	Diode, Signal	15

Table 4 lists the nonstandard parts. In addition, complete parts lists and nonstandard parts approval requests are included in the documentation portion of this report.

3.1.6 Test Electronics

A set of test electronics was built for use in bench experiments and ground tests. This test box was built long before the flight electronics, and since the object was to prove the theory, the electronics was optimized for convenience and not for flight. However, functionally it performs the same as the flight electronics, but has additional features. It also contains the electronics for dual mode, which was successfully demonstrated on the bench. A schematic of the test electronics is included in the documentation section. Figure 13, shows a typical test setup for a 50 MW test using flight electronics. (This was for a single mode test, although a dual mode test would be similar.)

Note, that since the nosetip is located 300 feet from the electronics, additional line drivers and receivers have been added. Also, the power amplifier must be located at the sting, since a large amount of power would be required to drive a transmission line at crystal voltage levels.

3.2 MECHANICAL HARDWARE DEVELOPMENT

For the design phase of the hardware development, design limitations were based upon the available packaging envelope for nosetip instrumentation on plug type nosetips intended for a vehicle such as an MSV. For this case, the maximum practical diameter for such instrumentation packages was 1.10 inches and approximately 3 to 4 inches long. It has been assumed that peripheral equipment such as the electronics could be located elsewhere in the vehicle body. The nosetip instrumentation consists of signal transducers, attachment components, signal cable connections and packaging; all located at the nosetip base.

The in-flight environmental conditions were subsequently defined by analyzing recent MSV flight histories. Of major concern during a flight, especially a weather flight, are nosetip base vibrations due to particle impingement. Past flights have revealed base temperatures of up to 500°F, vibration levels of 1,200 g's, shocks to 220 g's, and static accelerations to 25 g's. The nosetip instrumentation from this program is designed to withstand even greater extremes of temperature, vibration, shock and static acceleration (as outlined in the Minuteman II environmental specifications). Noting contract requirements and the above flight characterization, a system design lifetime can be defined as that associated with the following environmental exposure combinations:

- 1. Qualification tests
- 2. Acceptance tests and arc jet simulation tests
- 3. Acceptance tests and one flight (powered and reentry)

TABLE 4. NONSTANDARD PARTS USED

N +wed	Document	OVOSN	Qualification Required?	
	הפסרו ולה וסו	NOT ON	Yes No	ų ty
AD532SH	Multiplier (IC)	005	×	-
HA9-2510-8	Op Amp, High Slew	003	×	ო
LM108	Op Amp, High Impedance	004	×	2
CYR41	Capacitor, Porcelain	900	×	_
ZN5038	Transistor, NPN, High Power	900	×	_
XR2206M	Function Generator	200	×	_
None	Transformer	800	×	_
Not Identified	Logarithmic Ampl	1	×	_
Not Identified	Connector, Co-Axial	ŀ	×	2
Not Identified	Connector, System Interface	ł	×	_

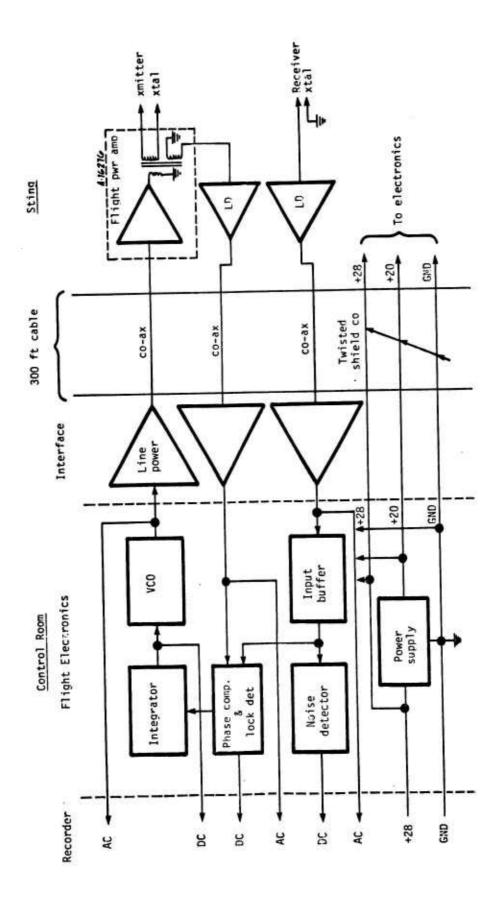


Figure 13. 50 MW single mode test using flight electronics.

The worst case loading situation is realized during acceptance tests and the arc jet simulation tests. Consequently, a design lifetime will consist of approximately 2.5 million stress reversal cycles at essentially a maximum 1,200-g rms stress level. This load characterization is a combination of axial and lateral loads experienced by the nosetip during exposure in the environment outlined above.

In the development of the acoustic gage as a measurement system, several areas of design must be addressed:

- Acoustic performance
- Structural considerations
- Thermal effects
- System packaging

Baseline acoustic performance had been demonstrated in previous work through bench and arc jet testing. The general conclusions were that more vibrations input to the nosetip are desirable to adequately track typical recession rates; the currently used receiver crystals were adequate and the general gage configuration excited the compressional mode of nosetip vibration as expected. The next step was to modify the ARG to withstand the environmental loads imposed without adversely affecting acoustic performance. This design modification also accounted for stresses induced by the thermal conditions to which the ARG system must be exposed. Ultimately, a flight qualified system package was sought to house the ARG.

Since feasibility was demonstrated using discrete vibration sensors, this general approach was again followed. Individual transmitter and receiver transducers constructed with piezoelectric crystals were employed; however, different configurations were considered. Two modes of nosetip vibration, single compressional mode and dual flexural mode were investigated. These two different modes of vibration are excited simply by locating the transmitter and receiver crystals at different orientations to the nosetip axis of symmetry. Three compressional configurations were conceptually evaluated: axial concentric transmitter and receiver, Figure 14, central transmitter with single or multiple eccentric receivers, Dwgs. #7141-080 and #7141-083, and a central receiver with single or multiple eccentric transmitters. Multiple transmitters were considered because of the need to increase vibration energy input to the nosetip; multiple receivers were considered due to the need for mass distribution radially to minimize excitation of flexural modes because of imbalance.

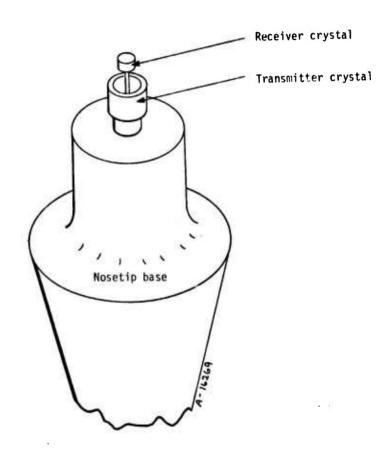


Figure 14. Concentric transmitter/receiver.

Three basic flexural configurations were also investigated: laterally opposing concentric transmitter and receiver, Dwg. #7141-064, lateral in-line transmitter and receiver, Figure 15, and axial eccentric transmitter and receivers, Dwgs. #7141-081, -082, and -099. Again these arrangements were built up of the individual sensor components, transmitters and receivers. These components are described in detail along with gage attachment and system packaging.

3.2.1 Sensor Construction

Since discrete components were to be employed, the individual sensors were analyzed in detail. The design goal was to boost transmitter output power to the nosetip and address the structural aspects of transmitter placement and support. The receiver acoustic performance, demonstrated to be sufficient in previous work, was analyzed for placement relative to the transmitter and structural support. Also, ways to miniaturize the receiver were investigated to allow more freedom in overall ARG configuration. The following basic design elements were considered:

- 1. Transducer construction optimization (transmitter, receivers)
- 2. Attachment to nosetip
- 3. System packaging

Individual components were studied to determine trade-offs between improvements in acoustic performance and structural weaknesses. A major problem faced was avoidance of resonant frequency operation at sensor assembly frequencies which lead to subsequent loss in ability to track the nose-tip frequencies. Assembly resonant frequencies were to be in excess of 50 kHz range with 25 kHz being the anticipated nosetip resonance operating range. In light of the thermal environment and space contraints at the base of the typical MSV nosetip, attachment of ARG components is difficult. Directly attaching the piezoelectric crystals to the base where temperatures may briefly exceed 500°F seemed doubtful. System packaging was addressed to provide a means of protecting the ARG during fabrication, testing and installation on the reentry vehicle (a typical system lifetime).

Initially, commercially available accelerometers were thought to be an excellent choice for this application. They are available as packaged units; are flight tested and qualified; yield a broad banded flat response; have very compact geometry; are relatively inexpensive and readily available from several manufacturers. The only disadvantage at the outset was that recommended ranges of operation did not approach the frequency range of 25 kHz, since resonant frequencies of these transducers are quite low. Several models were tested as transmitters with the general conclusion that not enough vibration energy could be delivered to the nosetip; overdriving the accelerometers with higher than rated input power resulted in permanent damage. However, these accelerometers could

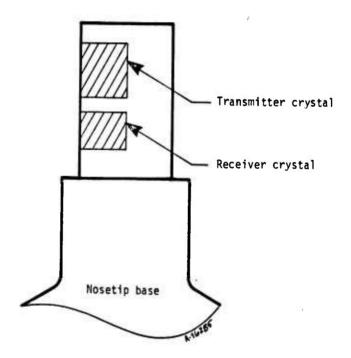


Figure 15. In-line flexural transmitter and receiver.

potentially be used as receivers if the nonlinear response near resonance could be cancelled out. A receiver crystal was fabricated (Dwg. #7141-079) and used for baseline comparison with the commercial accelerometers. Development of this particular design yielded significantly higher sensitivity and greater output signal; however, with a much lower resonant frequency. The natural frequency of this assembly was lower than 8 kHz, but no harmonics could be detected at higher frequencies which might degrade receiver performance. This receiver design was chosen because of the high output signal, acceptable frequency response and extremely compact size. Commercially available accelerometers tested were compared with the model and yielded reduced signal response with a given nosetip vibration input. Since improved receiver performance was obtainable, commercial accelerometers were eliminated entirely from the ARG system.

A prototype acoustic gage system in which a transmitter and receiver crystal were mounted within a single housing was fabricated for use in this program, Figure 16. Acoustic performance was poor with no significant difference in receiver crystal output signal whether attached or not to a bench test model nosetip. It was concluded that the receiver crystal was directly coupled acoustically to the transmitter crystal with no response to the nosetip.

Subsequently, the ARG components were examined and an optimization process begun with material selection and basic geometry definitions.

3.2.2 Crystal Study

Since previous work at Acurex dictated the use of piezoelectric transducers, only this type of crystal material was considered.

Table 5 lists some common piezoelectric materials with electrical and mechanical properties important for vibration transducer design. Initially, PZT-5 crystal material was chosen, primarily because of superior performance due to high values of electromechanical coupling coefficient, h_{33} , the dielectric constant and piezoelectric modulus, d_{33} ; and also a low value of the piezoelectric pressure constant, g_{33} , is desirable. This combination of parameters allows for large electrical energy storage in the crystal with subsequently high conversion to mechanical vibration, thus affecting maximum vibration energy input to the nosetip. Practical transducer design principles favored use of PZT-4 material because of greater material strength. Testing revealed no significant acoustic performance gain with PZT-5, as material properties would indicate, but revealed the loss in material strength. It was decided that the strength advantage of PZT-4 outweighed any acoustic performance differences. Both types of crystals have continuous operating temperature limits of at least the temperatures experienced at the nosetip backface during flight (Figure 17). Since exposure to this temperature range is extremely brief, crystal performance reduction would not be expected.

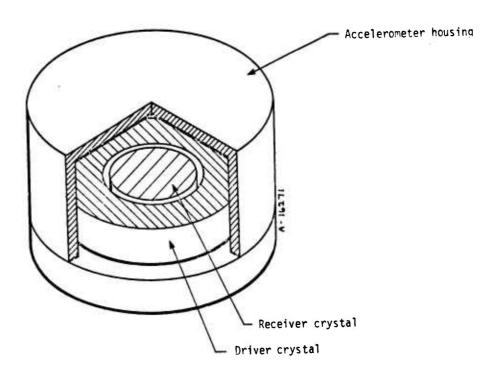


Figure 16. Prototype accelerometer.

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Lead Methaiobate 0.209 5-1Zd 1,750 4,000 0.274 290 0.71 380 25 000.9 PZT-4 0.270 1,300 11.8 50.5 0.68 250 280 25 TABLE 5. PHYSICAL PROPERTIES OF PIEZOELECTRIC MATERIALS Barium Titanate 0.199 1,250 3,000 0.46 17.1 110 145 13.1 Lithium Sulfate 0.074 10.3 175 0.4 75 91 1 Ouartz 0.096 11.6 550 4.5 0.1 28 Piezoelectric Pressure Constant, 9_{33} [10 $^{-3}$ (V/m)/(N/m 2)] Electromechanical Coupling Coefficient, \mathbf{k}_{33} Bulk Acoustic Impedance (10^5 lbm/ft 2 sec) Piezoelectric Modulus, \mathbf{d}_{33} (10^{-12} m/v) Maximum Operating Temperature (°C) Dynamic Tensile Strength (psi) Tensile Modulus (106 psi) Dielectric Constant Density (1bm/in³)

0.42

85

250 225 42.5 4.2 26.5

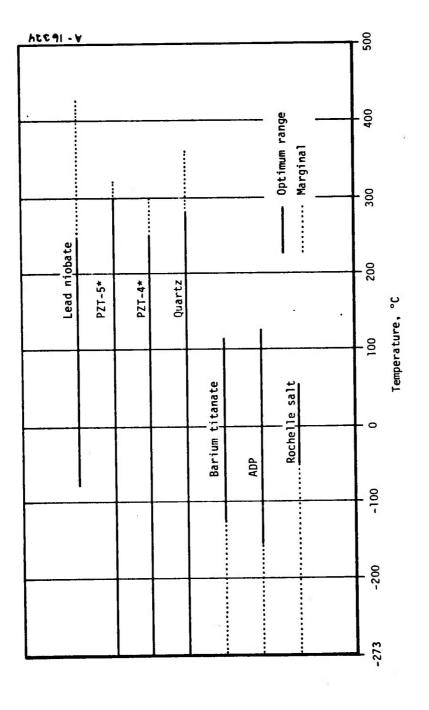


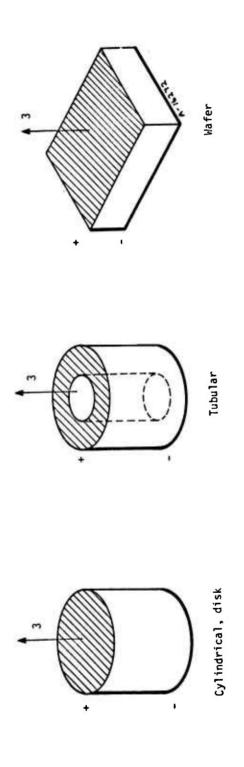
Figure 17. Useful temperature range of various piezoelectric materials.

One design goal throughout was to avoid component and system resonance of the ARG to provide flat response through the frequency range of operation. Both PZT-4 and PZT-5 work quite well in this respect because crystal dimensions were likely to be much less than 1 inch in thickness in the direction of vibration and resonant frequencies of such crystals would exceed several hundred kHz. Crystal orientation was well demonstrated in previous work at Acurex on the ARG and evolved with a "33" arrangement, namely, that crystal polarization and deflection are in the same direction. Such configurations are shown in Figure 18 for cylindrical, tubular, and wafer crystals. Initially it was felt that less complicated designs could result with use of such parallel, longitudinal crystals rather than shear types. The dish and tubular types were selected first to determine which shape and what general size crystal was required to generate enough vibrational excitation of the nostips. Bench tests were initiated to cover the spectrum of sizes selected for starting.

The following table covers the range of dimensions:

Diameter		Thickr	ness	
Diameter	0.100"	1/8"	1/4"	5/8"
1/8" disk		X	X	
1/4" disk	x		X	X
3/8" disk	x			
1/2" disk, tube	x		X	
5/8" tube			X (1,	/8" wa11)
3/4" tube			x (1,	/8" wall)

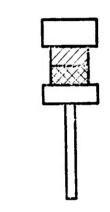
A small test rig was fabricated to house these crystals by mechanically clamping each between electrodes and mounting them to an aluminum nosetip simulating a MSV type nosetip. Figure 19. Previous work established good correlation between nosetip shape/length and resonant frequency; to facilitate bench testing turnaround time, test models were fabricated of 2024 T3 aluminum rather than carbon/carbon composite materials. Also, the bulk acoustic impedance of aluminum alloys is quite close to that of 2,2,3 carbon/carbon, thus aluminum is a reasonable simulation of an acoustic load to test acoustic drivers. Results of this work are discussed in Section 4.1. In short, acoustic performance seemed to track well with thin crystals of larger diameter; the amount of vibration energy output was proportional to crystal diameter. Consequently, disk and tubular crystals of 1/2-inch diameter and 0.100-inch thickness were tentatively chosen; these crystals also allowed a compact transducer design. Tubular crystals look attractive because the central hole allows freedom in housing and mechanical

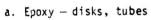


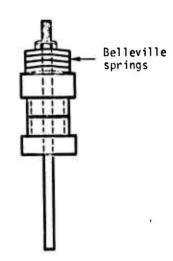
Polarization direction

Electroded surfaces

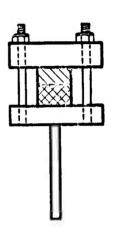
Figure 18. Desired piezoelectric crystal shapes.







b. Bolted tubes



c. Clamped disks, tubes

Figure 19. Crystal test fixtures.

attachment to a load, with a concentric bolt. The disk crystals were retained for design simplicity. Figure 20 indicates results on how the crystals should be housed with peripheral components; acoustic performance appears to be better for attachment with conductive epoxy (Ablebond 36-2 in this case) rather than mechanical clamping. Additionally, the mechanical clamping arrangements tended to degrade performance in that multiple components caused spurious vibration modes due to the complexity of the hardware; the number of interfaces increased reflections and back scattering causing a reduction in vibration energy being transmitted into the nosetip. Clearly, the design goal of reducing the number of components involved in the transducer construction is evident. Also, to get good acoustic energy transmission, the crystal must be tightly clamped to the load. During bench testing (in a setup as in Figure 20) the crystal output increased as the clamping pressure approached 3,000 psi; however, almost every crystal fractured at this clamping pressure. Crystals which were epoxy bonded gave better output performance with no clamping and exhibited no fracture failures.

3.2.3 Transmitter and Receiver Construction

The degree of nosetip excitation depends upon how the crystal output is coupled to the load, the nosetip. Both single and multiple crystals in a bimorph configuration, and epoxy bonded and mechanically clamped crystals were evaluated. Adequate nosetip vibration was achieved using a bonded, dual crystal bimorph similar to the design in Figure 19(a) and Dwg. #7141-065. Epoxy bonding allowed an acoustically clean design without bolts, springs, or awkward clamping dishes as in Figures 19(b) and 19(c). The thin (0.100-inch thickness) crystals yielded a very compact arrangement with strong acoustic output.

Conventional transducer design practice was used as a guide for the general approach of the transducer design. For this application some degree of directional acoustic transmission is desirable. To drive the nosetip, ideally the end of the transmitter must be firmly clamped to a rigid, nonabsorbing support, or one of high inertia with poor acoustic transmission. Practical design dictates that there be some physical interface between the crystals and the nosetip, with nonabsorbing and very high acoustic transmission capability.

A material search was undertaken to determine suitable candidate materials for such acoustic reflectors and transmitters; Table 6 is a listing of common materials of construction. By noting that the acoustic load in this application is the nosetip mode of carbon/carbon 2,2,3 and the crystal transmitter material selected was PZT-4, impedance matching considerations indicate clear material preferences. Spatially fixing the back side of the crystal is affected by a gross impedance

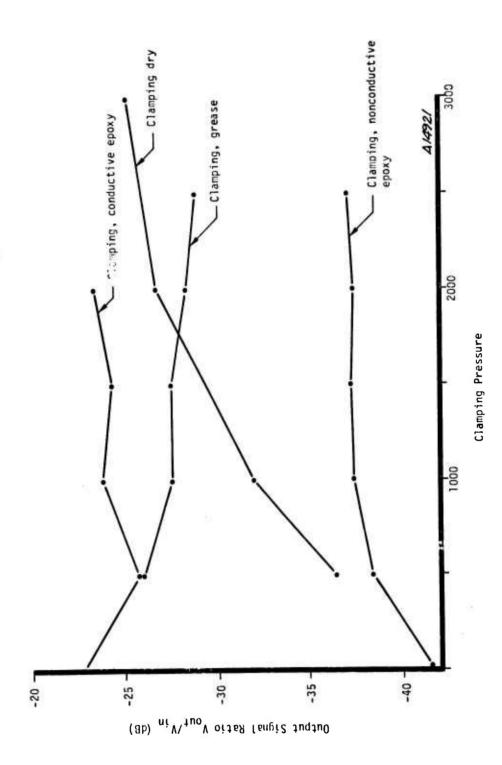


Figure 20. Crystal clamping.

TABLE 6. ACOUSTIC IMPEDANCE OF VARIOUS MATERIALS

Material	Density (1bm/in³)	Tensile Modulus (x 10° psi)	Acoustic Impedance (x 10³ lbm/in²sec)
C/C 2,2,2	0.067	13.9	19.0
PZT-4 Crystal	0.270	11.8	35.1
PZT-5 Crystal	0.274	7.8	28.8
Alumina	0.139	50	51.8
Aluminum 7075	0.101	10.4	20.1
Brass	0.304	15.0	42.0
Cast Iron (malleable)	0.266	26.5	52.2
Copper	0.323	17.0	46.1
Lead	0.410	2.0	17.8
Magnesium	0.064	6.5	12.7
Molybdenum	0.370	47.0	82.0
Nickel	0.321	30.0	61.0
Steel, Mild Carbon	0.283	30.0	57.3
Steel, Stainless	0.290	28.0	56.0
Titanium Alloy	0.160	16.5	31.9
Tungsten, Alloy	0.650	45.0	106.2

mismatch with a material such as tungsten. Good acoustic transmission into the nosetip is favored by connecting with a material with an impedance midway between that of the crystal material and the nosetip, namely aluminum or titanium. In light of material availability and fabricability, aluminum was chosen (Figure 21). A range of aluminum alloys was considered with the primary emphasis on fatigue strength and acoustic impedance, Table 7. Aluminum alloy 7075-T6 was chosen for highly stressed members and 2024-T3 for other components.

In general, the component geometry is a major factor in transmission; optimum transmission occurs in an intermediate medium of a thickness equal to one-quarter wavelength. In this application the frequency range of operation was anticipated to be on the order of 25 kHz; one-quarter wavelength in aluminum is approximately 2.0 inches, 1.8 inches in tungsten. However, bending stresses in a cantilevered beam due to lateral body vibration are proportional to the square of beam length. Therefore, waveguide length was varied during bench testing to determine a performancestructural trade-off. Also, the waveguide (crystal-nosetip interface medium) cross sectional profile was thought to affect acoustic performance. Figure 22 illustrates some of the waveguide shapes investigated. Since all were of the same length only the shape was varied with the performance differences resulting shown in Figure 23. The waveguide with highest acoustic performance also compared favorably from a structural standpoint. A large cross sectional area at the waveguide base, the location of the greatest bending moments of a cantilevered beam, would reduce bending stresses. The same criteria were used to size the tungsten backmass. This is important because of the high density and large moment area of this component. Bench testing revealed that a backmass of thickness comparable to that of the piezoelectric crystals was suitable. Dwg. #7141-065 illustrates the transmitter design resulting from the above considerations. The waveguide was sized primarily for a permissible stress level to provide a fatigue life of approximately 2.5 million bending stress reversal cycles. The results of the crystal study comparison suggested use of the PZT-4 crystal of 0.500-inch diameter and 0.100-inch thickness. The tungsten backmass is also 0.500-inch diameter and 0.100-inch thickness. The entire assembly is bonded together with a silver-filled, electrically conductive epoxy. The crystals are arranged in a bimorph (and thus expand outward in unison) configuration requiring a copper foil electrode on which to solder one of the input signal leads; the other signal lead is attached to the tungsten backmass and the aluminum waveguide. The entire assembly is then enclosed with heat skirt tubing to contain the delicate wiring.

As mentioned above, the design objective of receiver crystal modifications was to maintain vibration signal sensitivity while striving for miniaturization. Clearly for the compressional mode ARG with single transmitter and dual receivers, Dwg. #7141-065, savings in receiver diameter

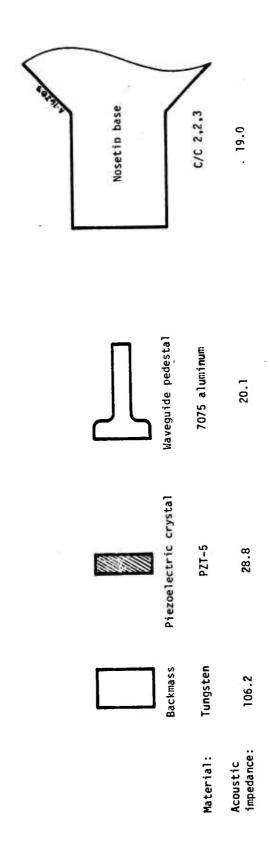


Figure 21. Transmitter construction.

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TABLE 7. MATERIAL PROPERTIES

Acoustic Impedance (1bm/in²sec) 19.8 9.61 19.5 19.5 20.5 19.4 19.4 20.1 (lbm/in³) Density 0.095 0.095 0.096 0.100 0.098 0.099 0.102 0.097 0.101 Tensile Modulus 10.6 × 106 10.6 x 106 10.3 x 106 10.3 x 106 10.2 x 106 10.0 x 106 10.4 × 106 10.3 x 106 10.2 × 106 10.2 x 106 (psi) **Endurance Limit** 21,000 20,000 20,000 22,000 22,000 14,000 23,000 23,000 23,000 (psi) 20,000 Shear Str 32,000 40,000 28,000 30,000 48,000 45,000 38,000 24,000 (psi) Tensile Str 62,000 70,000 42,000 000,09 000,69 43,000 45,000 83,000 (psi) Machinability 0 0 В ပ ⋖ 5056 (H38) 5090 (H38) 5154 (H38) 5052 (H38) 7049 (173) Aluminum Alloy # (91) (1909 7075 (16) (91) 6/0/ 2024 (T3) 2014 (T4)

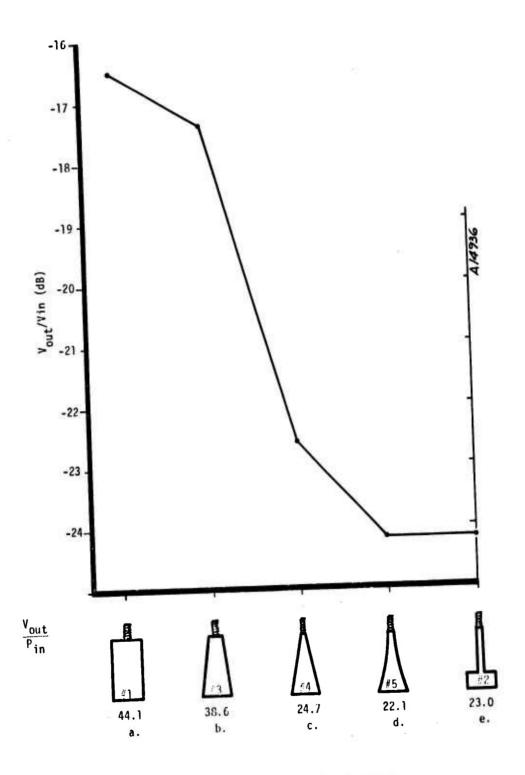


Figure 22. Waveguide performance.

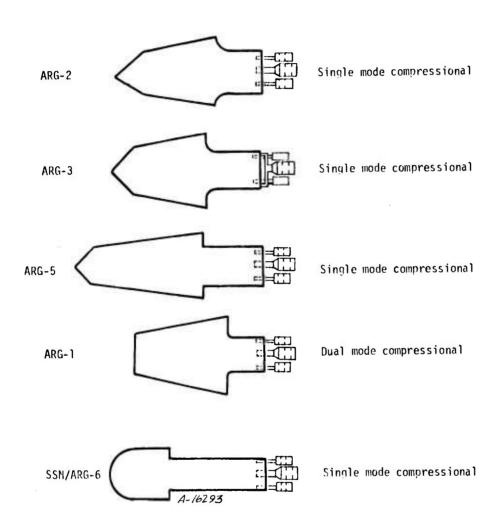


Figure 23. 50 MW test models.

or height reflect on length and diameter of the waveguide and hence, the load carrying capacity. Especially critical in this particular design, is the dimension tolerancing which is close in order to provide a minimum radius fillet at the waveguide base to reduce the local stress concentration. Details of the receiver assembly are shown in Dwg. #7141-079.

3.2.4 Gage Attachment

Several methods of attaching the ARG components to the nosetip base were investigated: screw threads, epoxy bonding and press fits. Press fits of an aluminum shaft (waveguide or receiver base) into carbon/carbon materials resulted in worsening the already high stress field due to relative thermal expansion during heatup. Epoxy bonding these components (with flat bottom surfaces) to a base plate (Dwgs. #7141-065 and #7141-063) which in turn was bonded to the nosetip base resulted in a packaged unit. However, several shortcomings were identified: acoustic performance with the added base plate deteriorated significantly and in spite of the high strength bonding provided by the epoxy (FM 400 as supported epoxy made by American Cyanamid), the 2,2,3 carbon/carbon material experienced a delamination of the first X-Y weave layer at relatively low amplitude lateral vibration levels. Subsequently, threaded fasteners were explored because transmitter and receiver loads could be distributed to many X-Y weave layers axially into the nosetip base. A coarse thread series is desirable to achieve full thread engagement with the unit cell of the carbon/carbon matrix. A relatively uniform stress distribution is favored with a very loose thread fit between aluminum and carbon composite materials if an unsupported epoxy is added to supply adhesion and fill the voids at the thread roots. A range of applicable epoxies appears in Table 8. Currently Hysol EA 934, an unsupported epoxy, is used to secure transmitter and receiver assemblies, Dwgs. #7141-080, -083, -081. This particular epoxy also has a relatively low cure temperature with good high temperature strength; cure temperatures are important during fabrication because of potential softening of the solder used to connect the cable assembly to the crystal electrode and backmass, also some weakening of the conductive epoxy used to assemble the crystals may occur.

3.2.5 System Packaging

The issue of encapsulating the ARG within a structural package is important for the following:

- Structural integrity
- Corrosion resistance of fragile components
- Hermetic sealing to prevent moisture condensation
- Handling protection during storage and installation

TABLE 8. ADHESIVE PROPERTIES

Epoxy	Max Temp	Core Temp	Tensile Str	Shear Str	is	Fatique Str
	(42)	(¿F)	(psi)	(a 77°F (psi)	(Мах Тетр	(osi)
Ablebond S17a	300	250 (1 hr)	5,000	2,500	800	:
Ablebond S50	260	300 (2 hrs)	:	6,000	1,000	;
Ablebond 293-14(EC)	1	260 (1 hr)	;	2,200	:	;
Scotch Weld 2214	350	225 (2 hrs)	:	2,000	006	:
FM 96	300	350 (2 hrs)	;	3,647	2,508	;
FM 460	420	350 (2 hrs)	1	4,010	1,850	600 psi @ 107 cycles No failures
FM 1000	180	340 (2 hrs)	1	7,200	3,500	:
Hysol 956	300	200 (1 hr)	;	2,500	1,000	;
Hysol EA 934	300	200 (1 hr)	1	3,100	1,000	;
Loctite 306	300	200 (1 hr)	1	1,800	1,400	:
			,			

RFI shielding of components

The significance of good shielding was demonstrated in previous work; in arc simulation testing the plasma gas stream generates significant RFI noise which is easily received by unshielded signal cables. Dwg. #7141-065 illustrates shielding techniques employed; both receivers are completely sealed within an aluminum case bonded with an electrically conductive epoxy (Ablebond 36-2). This should prevent electrical cross-talk between the transmitter and receivers. To prevent outside noise interference with the transmitter signal, the entire ARG can be housed within an aluminum case again sealed with an electrically conductive epoxy. With this type of packaging the ARG system can be stored safely and applied to a nosetip with a single bonding operation.

3.3 50 MW TEST MODEL DESIGN

Although the 50 MW tests were never performed due to facility difficulties this section describes the hardware which was fabricated for those tests.

3.3.1 Nosetip Configuration

The nosetip material for the four ARG models was 1,1,3 carbon/carbon (c/c) (Billet No. 113-2, Preform No. 1005). The SSN/ARG-6 model was a 2,2,3 c/c with a 3/8-inch diameter TaC integral weave core. All models were subscale, but were designed to provide the maximum size and shape permissible for the stream conditions and testing mode. The four ARG models were flat face or biconic 15° half-angle cone frustums.

All ARG models were exposed to the steady-state, peaked enthalpy profile, high stagnation pressure condition for maximum recession rate. The biconic models were single mode compressional models designed to provide the maximum length change at these conditions for measurement of recession rate only. The flat face nosetip was designed to produce the maximum amount of shape change. This model was operated in the dual compressional mode for both recession rate and shape change information.

A 1.1-inch cylindrical shank was provided at the base of the conic nosetip to simulate expected flight vehicle nosetip shapes. The shank/cone interface provided a contoured attachment shoulder similar to that expected on flight nosetips. By operating the acoustic sensor at the nosetip first compressional mode of vibration, this attachment technique was optimized by placing the nosetip/holder attachment location near a vibration node resulting in minimum signal attenuation.

Two of the three ARG biconic nosetips were identical with the exception of the sensor configuration. The third model was 0.5 inch longer. The intent of the longer nosetip design was to investigate the gage performance through a flexural compressional mode crossover not expected during the length change of the two shorter models.

The SSN/ARG nosetip tested in this series was included to demonstrate the feasibility of the ARG in composite c/c material. The radically different shape, compared with the ARG models, was a result of the large core diameter (3/8 inch) and the preference for both an optimum overall diameter to core diameter ratio and an acoustically "clean" geometry (cylindrical). As in the case of the ARG models, the attachment shoulder was located near the first compressional node.

Due to the size of the model, the ramp mode of testing was employed. The hemispherical tip was utilized to detect transition and to monitor the core/parent material interface during recession.

A summary of the nosetip shapes is given in Figure 23. Detailed drawings of the nosetip are included in Appendix A.

3.3.2 Support Hardware

Each of the five nosetips was preassembled in carbon-phenolic (c-p) model holders which included a heat-treated stainless steel threaded adaptor to mate to the facility strut. Although the impedance mismatch of a copper holder would have been desirable acoustically, the long dwell time required for the desired 3/4 inch of recession warranted the use of a higher temperature c-p material.

To compensate for potential attenuation and frequency shifts resulting from a holder material similar in mechanical properties to that of the nosetip, the nosetip/holder interface was not bonded. The model was held in place by loose fitting c-p tangential pins.

This acoustically optimized design had the potential for high pressure, high enthalpy gas leakage to the strut interior in the event of model failure or improper injection. To protect against possible damage to facility equipment a silicone 0-ring was installed at the nosetip shank/model holder interface and the aft portion of the stainless steel threaded adaptor was filled with an epoxy or RTV potting. This potting also served as a strain relief for the instrumentation leads.

3.3.3 Model Instrumentation Support Hardware

Each test model was a completely preassembled unit ready to thread to the facility strut.

All instrumentation leads terminated in plugs. The leads were supported throughout the interior

of the strut by a 1/4-inch diameter split stainless steel tube and concentric split aluminum washers (Appendix A, Dwg. #7141-069). The leads were mated to extension cables and/or a line driver box located in an aft section of the sting. The 8-foot extension cable from the sting connected to facility terminal strips mounted on the carriage in the case of thermocouples (T/C) or to a power amplifier box in the case of acoustic gage signals. From the carriage location all leads were routed to the control room and data acquisition equipment via the normal facility conduit system.

SECTION 4

DESIGN SUPPORT

The design support tasks consisted of bench tests, I MW arc jet tests and computer analysis of the acoustical behavior of the gage and nosetip. The analysis was especially important in order to interpret the data correctly.

4.1 BENCH TESTS

During the development of both the flexural and the compressional sensor systems, several bench test series were conducted. These tests were designed to investigate the relative merits of different sizes and shapes of crystals, their orientation and attachment configurations, and the optimum packaging configuration for the chosen sensor system. In addition, tests were required on the ground test materials of interest. The nosetip vibrational response was characterized, the vibration modes to be "tracked" were identified and quantified, and the nosetip geometry effects were investigated. This section describes the hardware, test objectives, and test results of the developmental bench test program.

4.1.1 Bench Test Hardware

4.1.1.1 Crystal Test Fixture

A small crystal test fixture was constructed to investigate the various crystal sizes, shapes, stack configurations, attachment techniques, and polarity orientation. The fixture was large enough to accept the largest crystal configuration tested so that no mass change, other than that of the crystals, was experienced during the investigation. The entire fixture could be mounted to the test model. The transmission efficiency of the test configuration could be measured by mounting a standard receiver crystal on the opposite end of the test model. Effort was made to make the experiment as repeatable as possible by measuring the clamping torque at each assembly. A sketch of the crystal test fixture is shown in Figure 24.

4.1.1.2 Aluminum Nosetips

Aluminum nosetips were fabricated for the developmental portion of the bench test program.

The basic nosetip shape chosen was that of a full scale MSV nosetip. The MSV was the expected gage

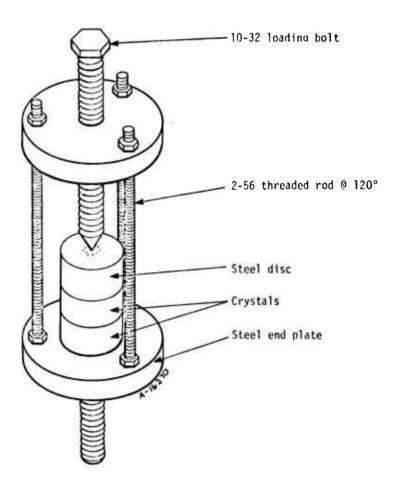


Figure 24. Bimorph test configuration.

test flight vehicle. Several shank geometries were investigated to determine the effect of increased diameter and shank extension. The intent was to achieve an optimum nosetip shape as large in diameter as the vehicle constraints would permit and as long as possible to reduce backface temperatures during reentry and to lower the resonant frequencies. Trade-offs were required between long shank extensions and "clean" vibration response.

The nosetip shape for most of the developmental tests was a flat face configuration. This shape provided a "clean" control case for the crystal studies and sensor configuration experiments. The flat face also provided a common location for a standard receiver throughout the testing of various transmitter configurations.

One of the aluminum nosetips was reserved for flexural excitation systems. Various schemes for attaching transmitter and receiver crystals to the base of the shank were investigated; such as brackets and cavities in the base of the model. These configurations were designed to hold the transmitter crystals in an orientation that would excite flexural vibrations while minimizing compressional vibrations.

Several models were designed to accept bonded sensor assemblies and sensor housings (canistors). Others were designed with threaded holes for direct attachment and bonding of transmitter systems.

4.1.1.3 Sensor Configurations

A prototype assembly of each sensor configuration was fabricated for testing and comparison on the aluminum nosetips. For those assemblies requiring bonding, several epoxies and adhesives were tried. A fast curing adhesive such as Eastman-910 or Micro-Measurements M-Bond 200 methyl-2-cyanoacrylate was used for the majority of bench testing because of its ease of application and short cure time. High temperature specs were not required for the bench testing development program.

After a sensor configuration was determined, several high temperature, high stress epoxies, both conductive and nonconductive, and both supported and nonsupported, were investigated for a nosetip bonding agent. Conductive and nonconductive epoxies were also compared in the crystal study portion of the program to determine the optimum methods of bonding crystals to each other as well as to waveguides and backmasses.

A detailed description of the sensor configurations investigated is given in Section 3.2.

4.1.1.4 Data Acquisition

The bench test data acquisition hardware included a dual trace oscilloscope, frequency counter, spectrum analyzer, and scope camera. In addition, the main instrument for determining the actual nosetip vibration and confirming the desired resonant mode was a "node probe."

The probe consisted of a small piezoelectric crystal and steel backmass with a directional probe (nail, small diameter drill bit, etc.) bonded to the end with conductive epoxy. The receiver crystal was encased in a hand held aluminum housing with connecting co-ax cable and BNC connector.

With the sensor and electronics operating at any selected resonant frequency, the entire model surface could be probed. In this manner resonances could be identified as being either flexural or compressional. Furthermore, by probing the side of the model for nodes (vibration nulls) the desired compressional or flexural frequency could be determined.

The majority of the bench test data were polaroid records of the nosetip response spectrum over a 0 to 100 kHz or 0 to 50 kHz bandwidth. All system resonances within these bandwidths were displayed in this manner. From these traces individual "peaks" could be isolated and probed for analysis and characterization.

4.1.2 Bench Test Objectives and Procedures

The developmental bench test program was conducted essentially in two parts. The first portion was structured to gather basic comparison data on the sensor configurations and individual components leading ultimately to an optimum sensor prototype. The second portion of the bench test program was devoted to fully characterizing the ground test model materials and determining the sensor response on these materials. One MW and fifty MW test nosetips were fabricated and characterized prior to testing.

In summary, the major bench test objectives were to determine the following:

- 1. Crystal material
- 2. Crystal size and shape
- 3. Number of crystals and polarization orientation
- 4. Crystal attachment configuration
- 5. Waveguide material and shape
- 6. Crystal backmass material and size
- 7. Optimum sensor packaging configuration (flexural and compressional)

- 8. Nosetip material characterization
- 9. Ground test model characterization and checkout

This section discusses briefly each of the above objectives.

<u>Crystal Material</u> — Two lead-zirconate-titanate (PZT) piezoelectric crystal materials were compared under identical conditions (PZT-4 and PZT-5).

<u>Crystal Size and Shape</u> — Disk crystals of various diameters and thicknesses were commared with each other and with tube crystals. Shear crystals were also included in the matrix, but were not tested in this program (see Reference 11 for detailed test matrix).

Number of Crystals and Polarization Orientation — All of the above sizes and shapes were tested in several combinations of multiple crystal and crystal polarization orientations. The standard bimorph configuration is defined as two identical crystals mated with a common pole at the interface [i.e., (-+)(+-)]. The center of gravity shift (e.g., shift) configuration is the reverse of the above, opposite poles at the common face [i.e., (-+)(-+)]. Various combinations of the two configurations were investigated with the intent of determining the optimum configuration; one that will result in a maximum receiver output voltage to power input ratio.

Crystal Attachment Configuration — Mechanical means of attaching the crystals to the model were investigated. For structural design considerations a mechanical clamping or threaded arrangement appear superior. Tube crystals with an internal central bolt and belleville springs were compared with an external compressive harness. Both systems were then compared with the more acoustically "clean" but structurally inferior epoxy techniques.

Waveguide Material and Shape — Steel and aluminum waveguides were compared to confirm the prediction of the superior transmission properties of the lower impedance aluminum. Various lengths and shapes of waveguides were tested from large diameter cylinders to tapered (similar to exponential horn theory) small diameter systems. Although the "point source" 2-56 threaded rod used in previous ARG ground tests (Reference 9) was desirable acoustically, larger systems were required to satisfy the structural integrity problems at high reentry vibration levels.

<u>Crystal Backmass Material and Size</u> — Aluminum, steel and tungsten backmasses were added to several of the crystal combinations to determine the effect of impedance mismatch and increased signal transmission efficiency. Various sizes of each material were tested to

determine the optimum mass for each material while trying to minimize the potential structural problems of a heavy backmass attached to the rear of the crystals.

Optimum Sensor Packaging — The preliminary bench testing and screening mentioned above resulted in defining optimum sensor components. Several flexural and compressional excitation systems were tested with these components. Offset transmitters with receivers both parallel and perpendicular to the transmitter, single and dual receivers, systems with and without hermetically sealed enclosures, and transmitter/receiver assemblies with and without an integral aluminum base were all investigated. Based upon design trade-offs between maximum returned signal for a given input power and structural considerations, the sensor configurations were narrowed down to two. Several epoxies were tried as the sensor bonding agent. Both ground tests, 1 MW and 50 MW employed these designs.

Nosetip Material Characterization — The materials chosen for ground tests were analyzed with the chosen sensor configuration from above. Sweeps from 0 to 200 kHz were analyzed for nosetip and sensor vibrational response.

Ground Test Model Characterization and Checkout — Each 1 MW and 50 MW nosetip was instrumented and characterized. The flexural and compressional modes of interest were identified. Quantitative informations of return signal amplitude, frequency, and phase relationship were recorded for all phases of model build-up from nosetip alone to completely assembled and potted models.

4.1.3 Bench Test Results

The problems encountered in the developmental testing program are discussed in this section along with the results of the major phases of the bench test program.

4.1.3.1 Data Interpretation Problems

Several recurring problems with the bench test screening tests involving data repeatability and data acquisition are described below:

Crystal Study Test Fixture — The test fixture used for screening the various crystal and waveguide configurations, described in Section 4.1.1.1, was subject to data nonrepeatability problems. The test fixture itself was a significant part of the nosetips/sensor mass system. It had multiple resonances in the nosetip bandwidth of interest. Although the concentric single loading bolt and load distribution slug were constant throughout the testing, it is doubtful that the torque on the loading bolt could be repeated within 10 percent. Even

assuming repeatable torque settings uneven nonparallel crystal faces resulted in nonuniform, nonrepeatable stress distribution during loading. Thus uneven stress loading resulted in crystal fracture in some cases at moderate torque/compressive stress loadings.

Epoxy — To insure repeatable test conditions to the maximum extent possible, the fabrication of those test configurations involving crystal component or sensor assembly bonding should employ proper bonding techniques. Surface preparation, mixing, application and curing should all be performed to the specification of the adhesive manufacturer. This was not possible in the multiconfiguration, multitest point matrix of the crystal component screening tests. Consequently, a fast curing cyanoacrylate was used for most of the testing without the full complement of surface preparation procedures. While this was better than no adhesive, it was subsequently discovered that the bond strength was not always repeatable.

<u>Model Size</u> — The entire ARG program to date has involved carbon/carbon materials on a subscale basis only. The material has been analyzed and nosetip resonances characterized for specimens on the order of 3 to 3.5 inches in length. These short lengths result in relatively high first compressional modes of vibration. The spectrum is extremely "noisy" through 150 kHz and the fourth compressional mode. It would be desirable to develop the sensor on a full scale vehicle where the frequencies of interest would be lowered and distributed in a "cleaner" fashion throughout the spectrum.

Node Probe — The node probe was the only instrument available to determine the vibrational pattern of the nosetip. Although it was adequate for some cases, the data for most of the carbon/carbon nosetips were ambiguous. At times it was simply impossible to define the vibration as flexural or compressional, let alone which harmonic. The probe was not directional enough. The orientation with respect to the specimen was critical; slight shifts in the angle could produce opposite results.

In general, probing perpendicular to the model axis was easier than parallel, since lateral vibrations were transmitted when attempting to probe parallel to the axis. This made it difficult to determine the number of compressional nodes; and without an indication of where to search, it was at times, impossible. The computer estimation of response was an invaluable aid in this respect.

It would be desirable to perfect the probe technique in future work. Perhaps the orthogonal dual probe technique proposal initially merits further investigation. Plotting one output vs. the other and studying the resulting Lissajous figures would yield node locations by

displaying phase shifts. In the event the node probe cannot be improved, perhaps an optical technique of some kind can be developed to display nodal patterns. A stress-coat painting technique has also been suggested. In any event a better method of establishing the identity of the resonant peak is of paramount importance since it is critical to the overall theory and tracking success.

4.1.3.2 Crystal Configuration Selection

The transmitter crystal configuration chosen as a result of the bench test program and structural design trade-offs was the bimorph configuration with a high acoustic impedance tungsten backmass. A 0.5-inch long, 1/4-inch diameter, aluminum waveguide was used. The crystals were PZT-4, 0.5-inch diameter x 0.1-inch thick. Ablebond 36-2 conductive epoxy was used to mate the crystals and electrode interfaces. See Dwg. #7141-065.

The receiver crystal was a single PZT-4, 0.25-inch diameter x 0.1-inch thick crystal with a tungsten backmass. The entire receiver assembly was enclosed in a hermetically sealed thin walled aluminum can with attached coax cable (Dwg. #7141-079).

The choice of PZT-4 over PZT-5 was a design trade-off between the structural superiority of PZT-4 and the relatively minor increased efficiency of PZT-5. Bench test results showed the merits of PZT-5 to be within the data repeatability error band. Indeed the prediction of increased response of PZT-5 published by the manufacturer show only slight advantages for this material.

The choice of 0.1-inch thickness for the crystals was based upon bench test data which demonstrated that the thinner crystals had a higher output voltage/power input (V_{out}/P_{in}) ratio. The choice of the 0.5-inch diameter over other sizes, however, was not as direct. In some cases the smaller diameter crystal yielded a better (V_{out}/P_{in}) ratio than the 0.5-inch diameter case. The data were close to the error band. The larger size was chosen because it permitted a larger bonding surface for the multicrystal/mass assembly. The larger size also simplified handling during assembly and would adapt better to a 1/4-inch diameter waveguide.

4.1.3.3 Sensor Package Configuration Selection

Initially the objective of the sensor packaging was to have a single self-contained transmitter/receiver unit. The assembly would be hermetically sealed and ready for bonding to the nosetip surface (Dwg. #7141-065). Subsequent bench testing showed, however, that the single encapsulated unit generated numerous inherent sensor resonances and was subject to severe crosstalk problems. This phenomenon was apparent in both the proposed flexural and compressional systems.

Subsequent experimentation led to individually mounted transmitters and receivers and to the transmitter/aluminum base unit with separate receivers (Dwgs. #7141-080 to -083). These designs had only a few sensor resonances in the bandwidth of interest and these were sufficiently displaced from tracked frequencies that they did not interface.

Due to the relatively large contact area of the transmitter waveguide and receiver there still appeared to be minor crosstalk problems. Early ARG designs utilizing more directional waveguides on both transmitter and receiver (Reference 8) were not as severely affected by crosstalk.

4.1.3.4 50 MW Model Characterization

After the sensor had been bonded to the nosetip several spectrum analyzer sweeps were taken to display the nosetip vibrational response spectrum over the bandwidth of interest. Computer analysis results and the node probe, defined in Section 4.1.1.4, were used to identify the first compressional mode of vibration for the single mode models. The first and second compressional modes of vibration were identified for the one dual mode model. The frequencies tracked for each of the five models described in Section 3.3.1 are listed in Table 9. Figure 25 is a 0 to 100 kHz sweep for each of the five nosetips.

4.2 1 MW TESTS

4.2.1 Test Objectives

The main objective of the 1 MW ARG tests was to demonstrate the operation of the dual mode flexural sensor configurations for carbon/carbon material in a hyperthermal environment. The test was not considered a proof test of the dual mode flexural system, but a developmental test prior to 50 MW proof testing. The dual mode electronics and oscillograph data acquisition technique were also checked out in this test program.

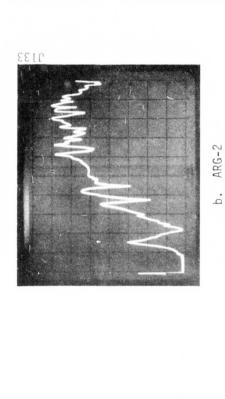
4.2.2 Test Conditions — Test Matrix

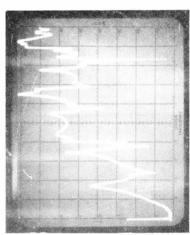
The Acurex/Aerotherm 1 MW Arc Plasma Generator (APG) provides a high enthalpy, low pressure, continuous flow test environment. Because of the low stagnation pressure, the heat transfer rate is less severe than that experienced at the 50 MW facility.

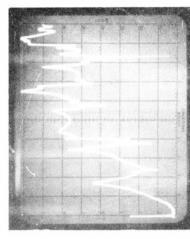
The effect upon the acoustic signal, however, should be more severe because of the increased test time and resulting temperature profile within the material. The temperature induced acoustic velocity changes, and hence the resulting frequency shifts, affect a greater portion of the nosetip for a longer period of time than that experienced in the 50 MW environment. The 1 MW environment, therefore, is a good checkout of the changes in material properties and their effect upon the transmitted acoustic signal. The test matrix for the two ARG tests is presented in Table 10.

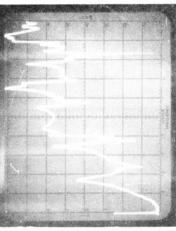
TABLE 9. 50 MW MODEL FREQUENCIES

Model No.	fl _c (kHz)	f ₂ c (kHz)	Figure 23 Identification
ARG-1	59.3	93.6	a
ARG-2	61.4		b
ARG-3	61.6		С
ARG-5			đ
SSN/ARG-6	48.0		e

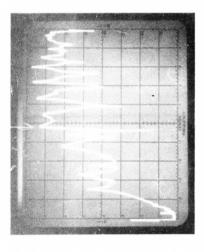








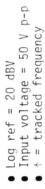




c. ARG-3

SSN/ARG-6







ARG-1

а.

TABLE 10. 1 MW TEST MATRIX

APG Test No.	Model No.	C/C Material	q flat face [Btu/(ft²sec)]	Pt ₂ (atm)	Approximate Time on G (sec)
2883	1 MW-1	Mod III _B	1,345	0.02	45
2884	1 MW-2	Mod III _B	1,388		34

4.2.3 Model Description

Both models were identical Mod ${\rm III_B}$ c/c nosetips. Approximately 1 inch in diameter, cylindrical, 3.25-inch long slugs tapered to a 0.5-inch diameter flat face were used (Dwg. #7141-073). The models were held in a loose fitting stainless steel adaptor with a loose fitting set screw. The adaptor was mated to a stainless steel tube to protect the sensor and instrumentation cables. This entire holder was encased in a circumferentially wrapped silica phenolic heatshield with a tapered graphite cap (Dwg. #7141-076).

The sensor configurations used were the offset transmitter and receiver configurations (Dwgs. #7141-081 and -082). For Model #1 MW-2 the sensor was threaded and bonded directly in the c/c nosetip base. The sensor for Model #1 MW-1 was a split aluminum base plate. The two semicircular sections contained the single transmitter and single receiver. The split base was bonded to the nosetip with supported epoxy.

The first and fourth flexural modes of vibration were tracked for this test. Table 11 lists the resonant frequencies for each model prior to the test.

TABLE 11. 1 MW MODEL FREQUENCIES

Sensor Base Configuration	f ₁ kHz	f ₄ kHz
Split Aluminum	15.1	68.9
Direct	16.1	69.9
	Configuration Split Aluminum	Configuration KHz Split Aluminum 15.1

Model #1 MW-2 was instrumented with two type K base thermocouples (T/C). T/C #1 was located on Q in the c/c 1/4 inch in depth. T/C #2 was bonded directly to the nosetip base.

4.2.4 Test Procedure

An optical pyrometer was aligned 0.1 inch back from the stagnation point to monitor surface temperature and to determine when 0.1 inch of recession occurred during the test. A flat face calorimeter and a pitot probe were injected for stream calibration prior to model exposure. All stream conditions and model T/C data were recorded by a high-speed magnetic tape data acquisition system. All sensor instrumentation signals were recorded on the oscillograph. For each model and for each of the two oscillator loops of the dual mode electronics, the following signals were recorded:

Loop #1 (f_4) and Loop #2 (f_1): • Output of VCO — dc signal proportional to frequency

Phase lock detector output — dc signal monitoring status
 of loop lock

The tests were run to destruction. Shortly after the receiver signal was lost due to epoxy failure the test was terminated.

4.2.5 Test Results

Lock was lost within the first 1 to 3 seconds on one of the two resonances in both tests. It was not the same peak in each case. Overall recession was less than 0.1 inch indicating thermal effects resulted in loss of lock.

Figures 26 and 27 are the phase lock detector output signal histories for Tests #1 and #2, respectively. For Test #1 Figure 26 shows that a significant deviation from preset zero voltage occurred on Lock #1 loop (fourth flexural) around 20 seconds. This deviation indicates loss of lock and tracking capability. Lock #2 loop (first flexural) lost lock immediately, but recovered after the insertion vibration damped out. The reverse was true of Test #2.

Figures 28 and 29 are the frequency shift histories for both resonances of Models #1 and #2, respectively. The oscillograph sensitivity was adjusted for approximately 2 percent frequency shift based on previous 1 MW c/c data (Reference 8). The "end of data" or "no data" points indicate the frequency shift exceeded this value and the VCO/oscillograph amplifier saturated.

Figures 30 and 31 present the optical pyrometer output for Models 1 MW-1 and 1 MW-2, respectively. Note that the pyrometer was aligned 0.1 inch aft of the stagnation point. Figure 32 is the base temperature history for Model 1 MW-2. The plot indicates that the epoxy failure temperature was reached at approximately 20 seconds. The figure further indicates that the base was heated by conduction and not high temperature gas leakage through the loose fitting adaptor and heatshield. This was suspected initially because of rapid base temperature response during the test.

4.3 ANALYSIS

Theoretical analyses of the resonant acoustic response of nosetip/waveguide systems are needed to:

- Generate resonant frequency versus length and shape mass for data reduction purposes
- Correlate and extrapolate bench and arc test experimental results
- Establish the sensitivity of nosetip/waveguide system resonant frequencies to forecone shape and nosetip temperature distributions

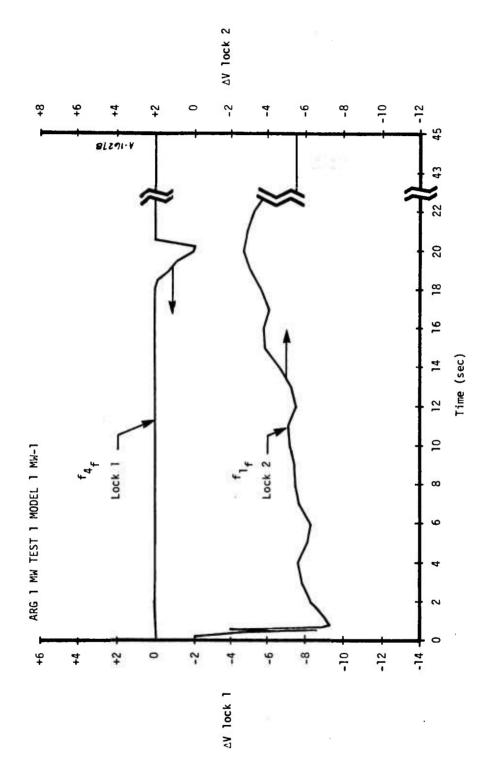


Figure 26. 1 MW Test 1 lock detection signal history.

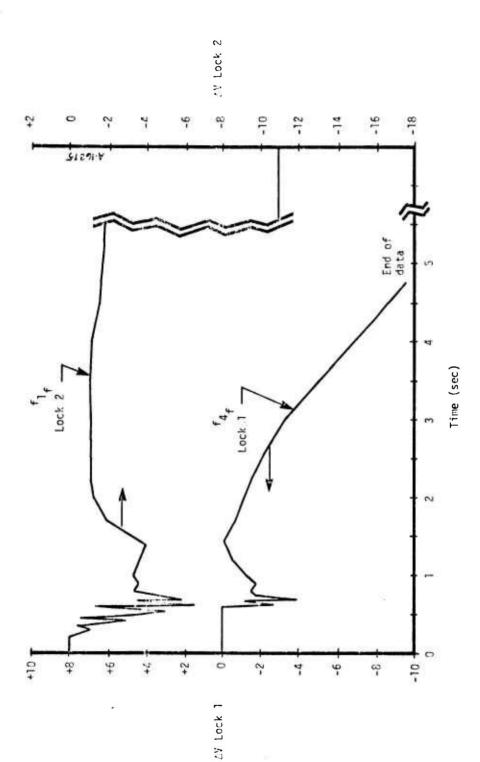


Figure 27. 1 MW Test 2 lock detection signal history.

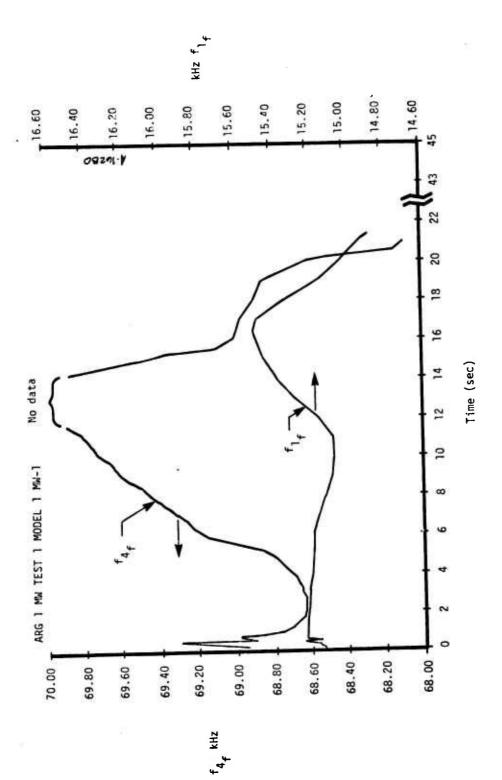


Figure 28. 1 MW Test 1 tracked frequency vs. time.

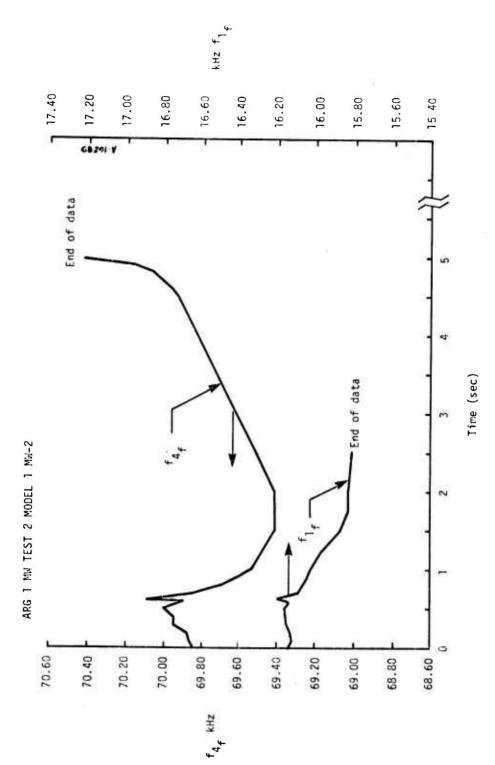


Figure 29. 1 MW Test 2 tracked frequency vs. time.

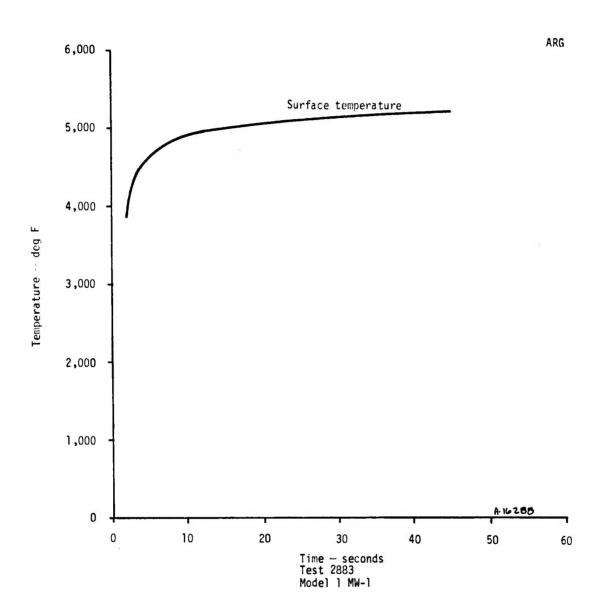


Figure 30. Nosetip surface temperature.

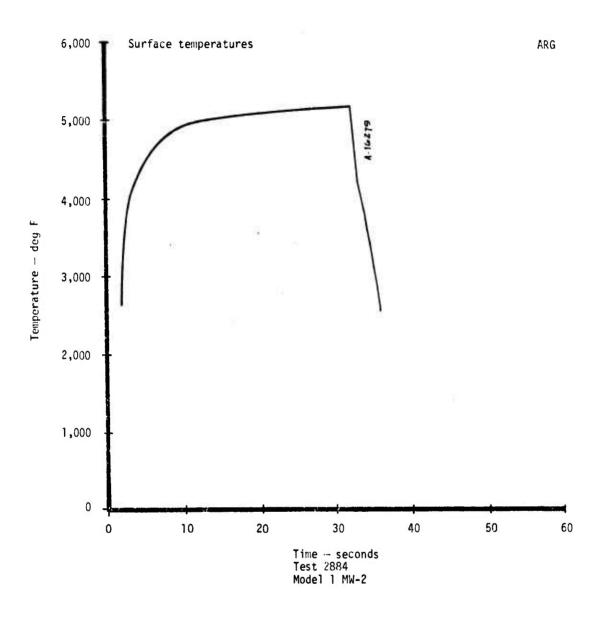


Figure 31. Nosetip surface temperature.

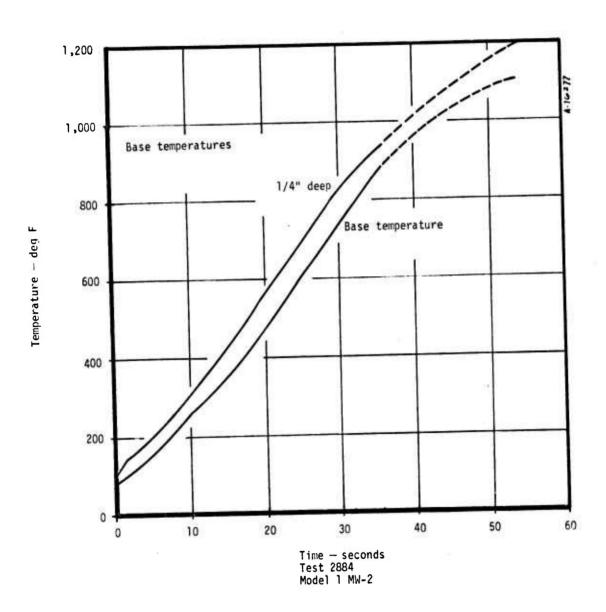


Figure 32. Base temperature.

 Assist designers in the optimization of the acoustic response of nosetip/waveguide systems

The following paragraphs discuss the theoretical methodology utilized in this study and some applications of the methodology to nosetip/waveguide systems.

4.3.1 Methodology

Since a large number of calculations were expected to be made during this program, a method was sought which would give adequate accuracy at minimal cost. Previous studies had indicated that simple analytical techniques could not provide the needed accuracy for the complex nosetip shapes and temperature distributions of interest. Consultations with an expert* indicated that a numerical finite element technique which is capable of predicting resonant frequencies (modal analysis) would be most suitable for application in this program. The finite element code selected for use in this study is the Structures Analysis Program (SAP IV) developed at the University of California at ' Berkeley (Reference 2). This code is widely available through various computer services and is typically well supported by their personnel. It is completely general allowing treatment of one-, two-, or three-dimensional configurations with the choice of eight different finite element types. Static, steady-state dynamic (i.e., modal analysis) as well as transient response predictions of arbitrary shaped bodies can be made with either isotropic on nonisotropic material properties. In summary, predictions of the full spectrum of nosetip/waveguide shapes and temperatures can be treated with this single code. However, the addition of succeedingly more complex elements or material properties (e.g., nonisotropic, elastic modulus) increases the computational time and thereby the computational costs. Also, for the more complex elements (i.e., three-dimensional brick elements), problem setup time is greatly increased. Recognizing the cost impact of the more complex elements, the simple beam element analysis is applied to predict the first compressional resonant response of nosetip/waveguide systems. Accurate predictions of higher order resonant mode frequencies require a more sophisticated and costly approach.

4.3.1.1 Single Mode Gage

In the application of the beam element modal analysis to nosetip/waveguide systems, the nosetip and waveguide are broken into discs as illustrated in Figure 33. These discs are assumed to have stiffness properties characteristic of beams made of the same material with the same cross sectional shape. Since each beam element requires input of material properties, temperature effects

^{*}Professor Hugh D. McNiven, U.C. at Berkeley.

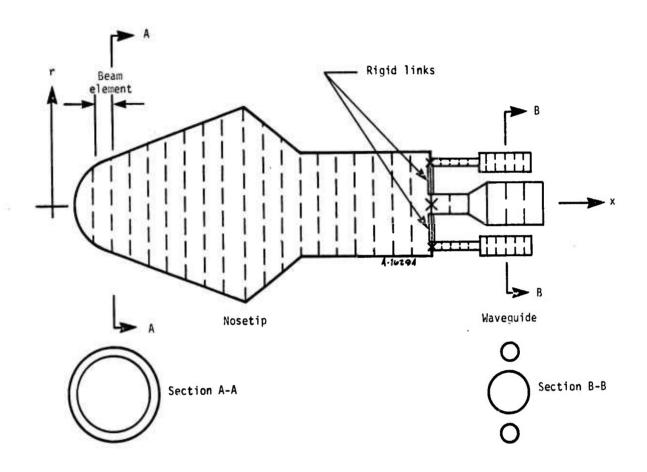


Figure 33. Schematic of SAP IV beam element applications to nosetip/waveguide system.

as a function of distance along the axis can be easily included in the analysis. With the use of a combination of rigid links* and beam elements, fully three-dimensional waveguide systems can be modeled with the beam analysis approach. Figure 33 illustrates a typical application of rigid links.

To reduce SAP IV beam element problem setup time, two auxiliary programs have been constructed by Aerotherm to generate beam element geometric input data from overall nosetic geometry. The first program, SAPINB, requires as input the nosetip overall length, plug dimensions, forecone and aftcone half angles and element lengths. The program generates nosetip element geometric data on punched cards which can be directly input into the SAP IV code. Waveguide geometric element data must be generated by hand and appended to the above data set to predict nosetip/wavequide system response. The second program, SAPINA, is constructed to interface with the Sandia Nosetip Analysis Procedure (SNAP) code (Reference 3). The SNAP code is a computational tool used to determine the shape and internal temperature distribution histories of nosetips during reentry into the atmosphere. At selected trajectory times during the calculations, shape and temperature distributions are automatically stored on magnetic tape to be retrieved at a later time. The SAPINA program accesses this data type and generates beam element geometric data from the predicted nosetip shape for direct input into the SAP IV code. This approach reduces the time consuming and error prone process of generating geometric data by hand. This approach is particularly useful for assessing the variation of resonant frequency under actual flight conditions over a complete reentry trajectory.

Given element geometric and material properties, the SAP IV code determines the nosetip/ waveguide system resonant response by:

- Constructing mass and stiffness properties of all elements
- Linking elements together and forming a set of simultaneous equations
- Solving the simultaneous equation set for its eigenvalues (resonant mode frequencies)
 and eigenvectors (relative displacements along and perpendicular to the axis)

If desired, the results of the above modal analysis can be utilized as code input for a dynamic response analysis of the nosetip/wavequide system. Given a forcing function, the SAP IV dynamic response option determines, as a function of time, the absolute displacements and forces at the endpoints of all of the elements. The dynamic response option is useful in establishing forces within the nosetip/waveguide system as a result of nonacoustic gage generated vibrations and

An element which connects other elements but which doesn't permit relative displacements between its endpoints.

phase relationships between the gage driver frequencies and receiver frequencies. It should be noted that the forcing function input for the dynamic response option must be defined in a discreet manner as a function of time. This input can become quite bulky for several periods of the driver oscillation. Also, the computer run time is increased over the modal analysis, and the output generated is bulky and not well suited for steady-state forced vibration problems. These negative aspects limit the extensive use of the dynamic analysis approach in this study.

The SAP IV beam element modal analysis has been validated via comparison with bench and arc test first compressional mode frequency data. In Figure 34, SAP IV beam element predictions of resonant frequencies are compared to values measured for several lengths of tungsten bar. Since the bars, especially of longer lengths, are beam-like, then good agreement is expected between predictions and measurements. In Figure 34 this is found to be the case for the first compressional mode, even for the shorter bar lengths. For the longer lengths, agreement is also found between the beam analysis and simple bar theory* for both compressional and flexural resonant modes.

It should be noted that the simple analytical bar theory for flexural vibrations differs from the beam analysis results and data at the shorter lengths. Since the shorter bar lengths have length-to-diameter ratios typical of nosetips, the above deviation illustrates the limitations inherent in applying simple bar theory analytical approaches to nosetip type shapes.

The good agreement between the first compressional mode, beam analysis predictions and measurement, for various bar lengths, prompted the use of the code in checking the "effective" elastic modulii of some materials used during the program. For these cases the material elastic modulii are established by adjusting the code input for these quantities until the predicted bar frequencies are equal to the measured values. The values found are typically close to published results but differ slightly by some nominal amount. The approach for checking elastic modulii is a valuable aid in

$$f_{compressional} = \frac{C_n}{L} \sqrt{\frac{E}{\rho}} \qquad \qquad \frac{n \quad 1 \quad 2 \quad 3}{C_n \quad 1 \quad 2 \quad 3}$$

$$f_{flexural} = \frac{F_n}{L^2} \sqrt{\frac{EI}{w}} \qquad \qquad \frac{n \quad 1 \quad 2 \quad 3}{F_n \quad 3.56 \quad 9.82 \quad 19.24 \quad 31.31}$$

where L = length, E = elastic modulus, ρ = density, w = mass per length, I = sectional moment of inertia, all in units of lbf-in-sec.

^{*}For long bars of uniform length cross sectional shape it is found that

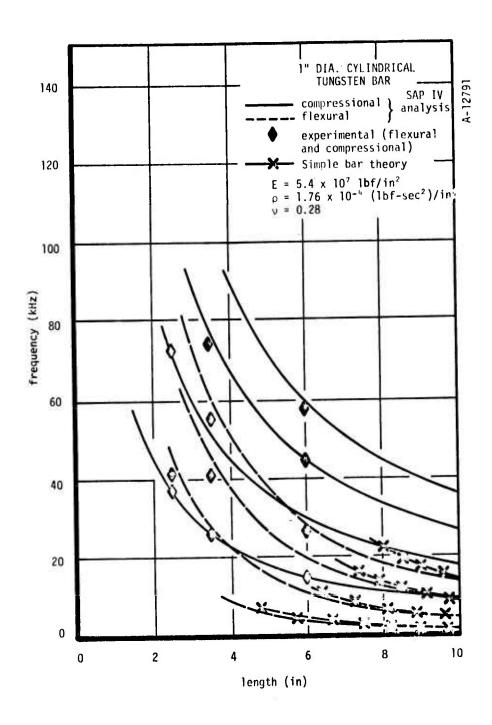


Figure 34. SAP IV beam analysis predictions of tungsten bar resonant frequencies.

developing code input data for nonisotropic carbon/carbon type materials. As previously indicated the beam analysis approach is essentially one-dimensional in nature and detailed nonisotropic material properties cannot be included in this option. However, if an "effective" elastic modulii is defined for the material based on a certain geometry then adequate predictions of frequencies can be made over a range of shapes and lengths which include this geometry. In essence, the beam analysis elastic modulii data is calibrated for beam analysis applications to nosetips which have nonisotropic material properties. The validity of this approach is demonstrated by arc test results which are discussed below.

In Table 12 SAP IV beam analysis predictions of 1 MW tungsten and carbon/carbon nosetin/
waveguide system resonant frequencies are compared with measurements. The carbon/carbon "effective"
elastic modulus input into the code was established from experiments on bar shaped samples of the
material. The shapes of the nosetips deviate somewhat from the bar examples discussed previously.

A major change from the bar examples is the inclusion of the asymmetric waveguide and crystal configurations in the analysis. The waveguides and crystals are constructed of materials different
from the nosetip. For these cases, the presence of the waveguide system alters nosetip resonant frequencies. Also, several additional resonant frequencies appear which are associated primarily with
the waveguides. In summary, the resonant response of the nosetip is altered and complicated by the
presence of the waveguides. Since it is experimentally difficult to sort out the waveguide and body
frequencies, several beam analysis predictions were made to try to evaluate the resonant response
of some nosetip/waveguide systems used during this program.

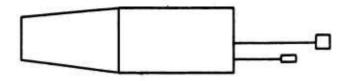
The comparison made in Table 12 indicates that resonant mode frequencies primarily associated with the body are predicted well for both tungsten and carbon/carbon nosetips. Though somewhat incomplete and not totally conclusive, the results presented in Table 12 indicate that the code can predict with reasonable accuracy responses associated primarily with the waveguides.

It should be noted that experimentally a resonant mode frequency was observed for both tungsten and carbon/carbon models which could not be associated with any beam analysis prediction of frequency. These responses might have arisen from either crystal resonances or nonbeam type (i.e., non-one-dimensional) responses of the nosetip. In a later discussion it will be demonstrated that nonbeam type responses can develop for nosetip type shapes. It is conjectured that the responses not predicted by the beam analysis approach shown in Table 12 are of this nature.

Besides the thin waveguides illustrated in Figure 33, the beam analysis approach, utilizing the same material properties has been applied to several aluminum nosetip shapes with massive waveguides. These waveguides are more typical of flight hardware than the thin waveguide cases

TABLE 12. COMPARISON OF SAP IV BEAM ANALYSIS AND MEASURED NOSETIP/WAVEGUIDE RESONANT FREQUENCIES

a. 1 MW ARC TUNGSTEN MODEL



E = 5.4 x 10^7 lbf/in² ρ = 1.758 x 10^{-3} (lbf-sec²)/in⁴ ν = 0.28

TUNGSTEN

Resonant Mode Type	Frequency Predicted	
W, TX, f ^a l body flexural W, RC, L	12.49 14.53 17.18	12.0
W, TX, f W, RC, f 2 body flexural	25.69 26.09 29.53	28.8
<pre>l body compressional W, TX, f 3 body flexural 2 body compressional</pre>	30.21 43.02 46.59 53.94	31.4 40.0 42.0 56.3
W, TX, L W, TX, f 4 body flexural	58.69 63.64 64.33	60.0

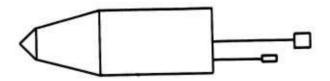
^aW = waveguide TX = transmitter

RC = receiver

f = flexural
L = compressional

TABLE 12. Concluded

b. 1 MW ARC CARBON/CARBON MODEL



E = $3.65 \times 10^6 \text{ lbf/in}^2$ $\rho = 1.49 \times 10^{-4} \text{ (lbf-sec}^2)/in}^4$ $\nu = 0.097$

CARBON/CARBON

Resonant Mode Type	Frequency Predicted	(kHz) Measured
l body flexural W, RCTX, f W, RC, f l body compressional 2 body flexural W, TX, f 2 body compressional 3 body flexural W, TX, 1 X, TX, f	18.54 25.73 26.28 31.41 36.69 43.19 55.81 56.70 61.32 63.99	19.0 25.0 28.0 31.4 34.8 43.0 52.0 55.0 59.0 65.0

illustrated in Table 12. The results presented in Table 13 demonstrate the agreement that can be achieved between predictions and measurement. As can be seen in Table 13, the beam analysis is adequate to predict second* compressional resonant response of a nosetip/waveguide system. Predictions of higher compressional resonant frequencies have larger deviations from measured values than the second compressional resonant response.

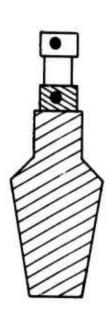
Having established the validity of the beam analysis approach for nosetip/waveguide systems, a series of calculations were made to demonstrate the accuracy of the method for a variety of nosetip forecone angles that represent nosetip shapes which are typical of flight shapes. Table 14 demonstrates the accuracy of the code in predicting first compressional resonant frequencies of a fixed length nosetip for forecone angles of 30°, 45°, 60°, and 90°. It should be noted that the deviation from experiment is always positive with the largest difference between deviations being 1.6 percent. These results indicate that the deviations could be reduced further by calibration of the elastic modulii to bring, for example, the 45° forecone angle case into direct agreement with the data.

To this point in the discussion, all examples presented have been for nosetip/waveguide systems at room temperature. When the nosetip is heated in an arc test or in flight the stiffness or elastic modulus of the material is altered. For very high temperatures typical of arc tests or flight, the elastic modulus of some materials can become a small fraction of the code value. Since resonant frequency is a function of the material stiffness (i.e., typically scales with the square root of the material stiffness) then resonant frequency can be strongly affected by temperature. Further, for some materials (e.g., tungsten) as the temperature rises, the material damping coefficient increases substantially. This alters both resonant frequency and the amplitude of the resonant response signal. Several beam analysis predictions of nosetip/waveguide systems under heating conditions were made during this study to demonstrate the validity of the beam modal analysis under actual flight type conditions.

Existing 1 MW tungsten arc test resonant frequency results are compared with first compressional beam analysis predictions in Figure 35. Agreement is seen to be good over the 20 second operating time period of the arc. The tungsten nosetip and waveguide configuration is similar to that given in Table 12. Elastic modulii properties were obtained from several sources and are summarized in Figure 36. The temperatures utilized to determine local elastic modulii along the length

^{*}The second compressional nosetip/waveguide response for this system is equivalent in terms of body displacements to the first compressional response of the nosetip shown in Table 1. This is a result of the massive waveguide acting like an extension of the body. This is the frequency that would be tracked in flight.

TABLE 13. MSV NOSETIP WITH SINGLE CRYSTAL WAVEGUIDE



 $E = 9.704 \times 10^6 \text{ lbf/in}^2$ $\rho = 2.596 \times 10^{-4} \text{ (lbf-sec}^2)/\text{in}^4$ v = 0.332

			Resonant Frequency (kHz)	requency	(kHz)		
	Co I	Compressional II	la1 III	I	Fley	Flexural	IV
SAP IV Beam	18.52	18.52 30.03 49.50 4.39 19.96	49.50	4.39	19.96	22.83	32.77
Experimental	17.42	17.42 29.93 44.60 4.08	44.60	4.08			
Percent Difference	5.9	1.7	9.6	7.1			

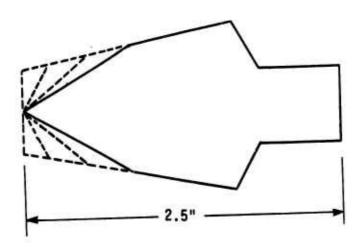
TABLE 14. ALUMINUM NOSETIP FIRST COMPRESSIONAL RESONANT MODE FREQUENCIES

 $\rho = 2.596 \times 10^{-4} (1bf-sec^2)/in^4$

 $E = 9.704 \times 10^6 \text{ lbf/in}^2$

v = 0.332

	Frequency (kHz)			
Forecone Angle	SAP IV	Measured	Percent Change	
30	53.85	51.19	5.2	
45	50.08	48.34	3.6	
60	48.75	46.95	3.8	
90	47.36	45.55	4.0	



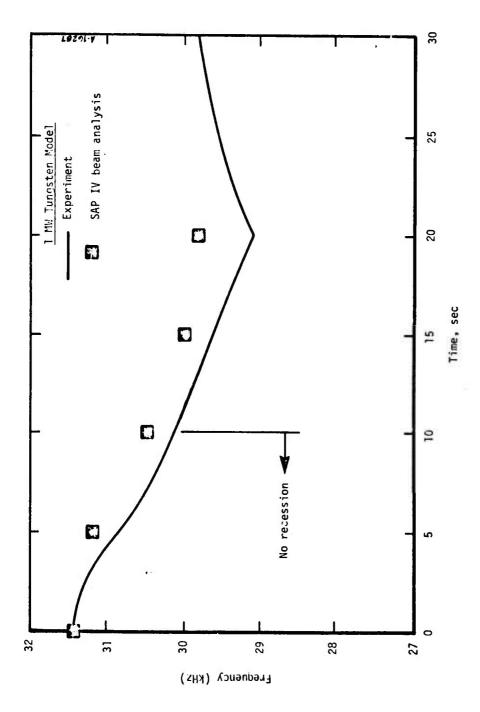


Figure 35. Comparison of 1 MM arc SAP IV beam analysis predictions and measurements for tungsten nosetip.

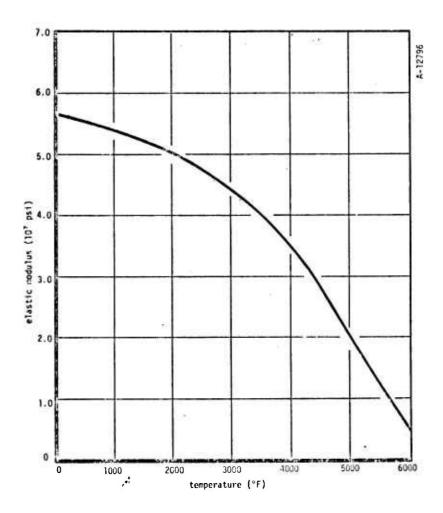


Figure 36. Tungsten elastic modulus as a function of temperature.

of the nosetip were generated using a one-dimensional heat conduction code and the measured nose and backface temperature during the arc test. Due to the one-dimensionality of the predictions, the accuracy of the temperature distributions shown in Figure 37 are not very good, and yet, predicted frequencies are close to measured values as is shown in Figure 35. This indicates that resonant frequencies are not very sensitive to temperature effects.

Under actual flight conditions the heating rate is much greater and the heating time at this rate much less than that in the 1 MW arc jet test facility. The amount of material at high temperature under these conditions is limited to a narrow region close to the surface. Therefore, the effect of temperature on resonant frequency for the flight case should be less than that experienced in the 1 MW arc jet. This is confirmed by the high heating rate 50 MW tungsten arc test results shown in Figure 38. The predicted frequencies are in good agreement with measured values even though "cold" elastic modulii values were utilized as input into the SAP IV beam analysis. It can then be concluded that for the high heating rates and short heating times encountered during flight, temperature effects for tungsten can be adequately handled by the beam analysis approach.

Unlike tungsten, there is evidence that carbonaceous materials increase in stiffness as temperature increases. This is illustrated in Figure 39 for a number of graphitic materials. However, at extremely high temperatures the stiffness of the material will eventually decrease as is indicated in Figure 39. Carbon/carbon fiber type materials, though significantly stronger than graphite itself, exhibit similar elastic modulii trends with temperature (Reference 5). Since temperatures within nosetips under flight conditions vary from relatively cold in-depth to extremely hot near the surface then it is expected that portions of the nosetip will have increased stiffness, whereas other sections will have reduced stiffness. On the whole, it is expected that local temperature effects will tend to cancel each other leaving the first compressional resonant frequency relatively unchanged from its cold value. This assumption is substantiated in Figure 40 by the plot of measured first compressional frequency versus time for the carbon/carbon nosetip in the 1 MW arc. The nosetip and waveguide system for this case is similar to that presented in Table 12. During the test the carbon/carbon material at the surface was heated to very high temperatures. Negligible recession occurred during the test period and, therefore, most of the frequency change is a result of temperature effects. Neglecting the initial abrupt drop in frequency shown in Figure 40, it can be seen that as the model is heated the frequency first rises as stiffness increases then falls as the surface temperature rises to very high values. Finally, as the steady state is approached the entire nosetip becomes hot, driving up the frequency. The variation in frequency reaches a maximum of

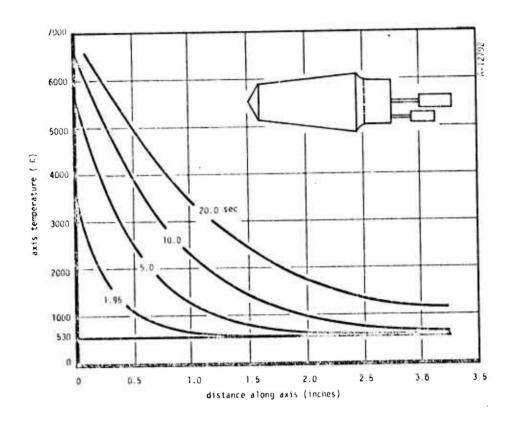


Figure 37. Predicted 1 MW arc tungsten temperature distributions as a function of time.

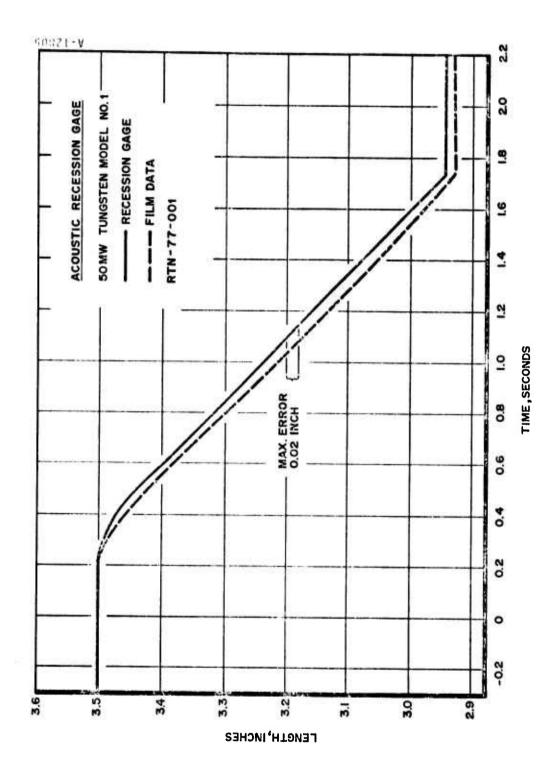


Figure 38. Comparison of 50 MM arc SAP IV beam analysis predictions and measurements for a tungsten nosetip.

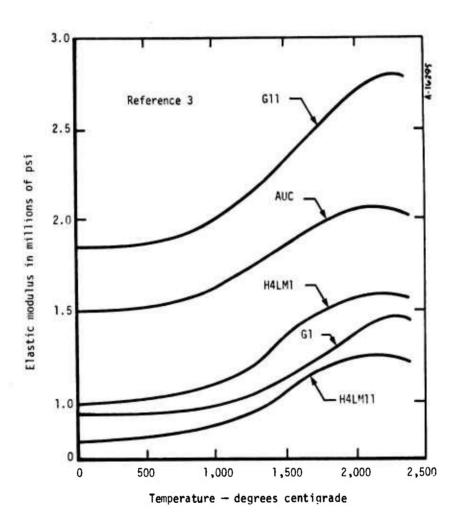


Figure 39. Elastic modulus versus temperature for representative commercial graphites.

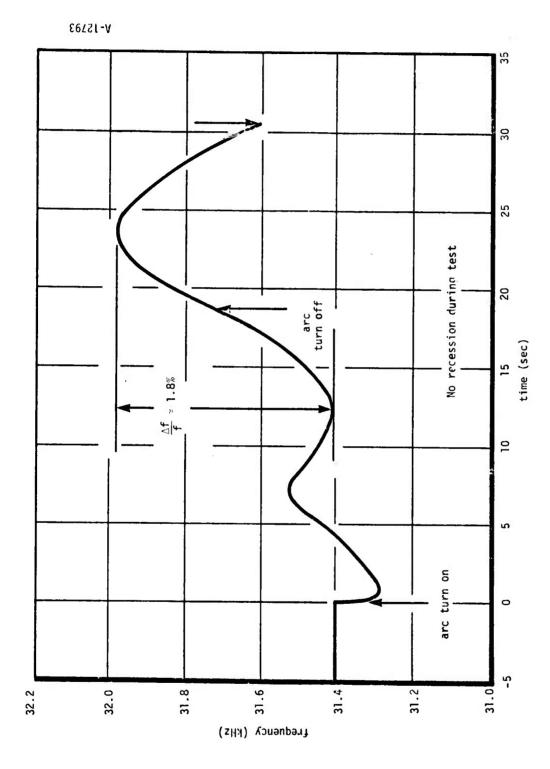


Figure 40. One MM arc test results for a carbon/carbon nosetip.

1.8 percent during the heating event. In terms of uncertainty in length measurement,* this frequency change is negligible.

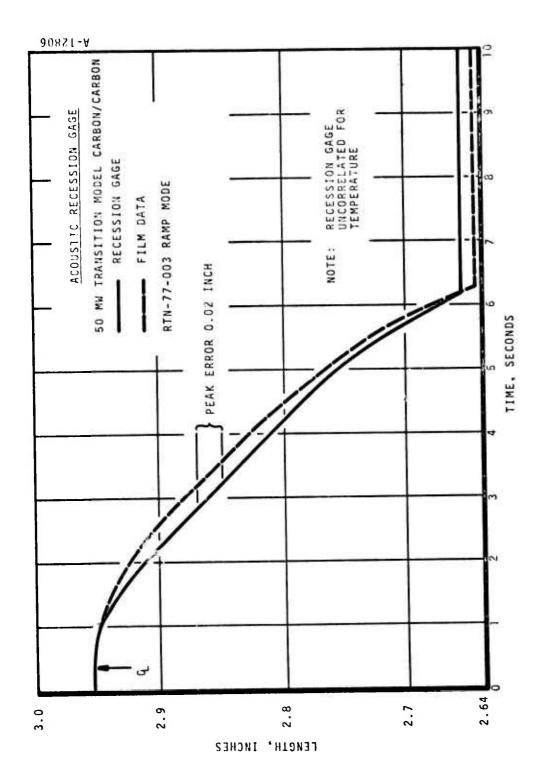
These results indicate that carbon/carbon nosetip resonant frequency is not a sensitive function of temperature. For high heating rate cases typical of flight, this conclusion should be even more applicable. This is illustrated by the high heating rate 50 MW arc test results, which show good correlation with data in Figure 41, even without any correction for temperature.

4.3.1.2 Dual Mode Gauge

In the previous section, the relationship between a single resonant mode frequency and overall nosetip length was discussed. Predictions and measurements of first compressional resonant mode frequencies as a function of length indicate that there is sufficient sensitivity to accurately infer length from measured frequency. Given two resonant mode frequencies, simultaneous shape and nosetip overall length can be established. As in the overall nosetip length measurement approach, the first flexural or compressional resonant mode is selected as one of the frequencies to be measured. Previous studies have shown that the fourth flexural resonant mode frequency in combination with the first flexural will provide the most sensitivity for determining both shape and length. However, the sensitivity for measuring shape is not as great as that for measuring length. Therefore, the analysis approach must be reexamined to determine if accuracy is sufficient to accurately infer shape from frequency measurements. Figure 42 gives the beam analysis predictions of the first and fourth flexural resonant frequencies of an aluminum nosetip as a function of midpoint length. Midpoint length is defined as the measured length from the plug end of the nosetip to the intersection of the major cone angle bisector with the nosetip forecone face (see schematic in Figure 42). From Figure 42 it can be seen that the first flexural resonant frequencies fall on a single line for all nosetip forecone angles, whereas the fourth flexural frequencies are spread out over a frequency band which is a function of a nosetip forecone angle and midpoint length. The frequency band is not very wide, particularly for the blunter forecone angles. Utilizing the results of Figure 42, Figure 43 illustrates the shape uncertainty produced as a result of a small 1-percent frequency uncertainty. These results indicate that accurate shape inference for blunt nosetips require accurate predictions of both first and fourth flexural frequencies.

Predictions made for the single mode acoustic gauge have demonstrated the validity of using the SAP IV beam analysis approach to determine first flexural resonant mode frequencies. However,

Length uncertainty is directly proportional to frequency uncertainty for simple bars (i.e., $\Delta L/L \propto -\Delta f/f$).



Comparison of 50 MW arc SAP IV beam analysis predictions and measurements for a carbon/carbon nosetip. Figure 41.

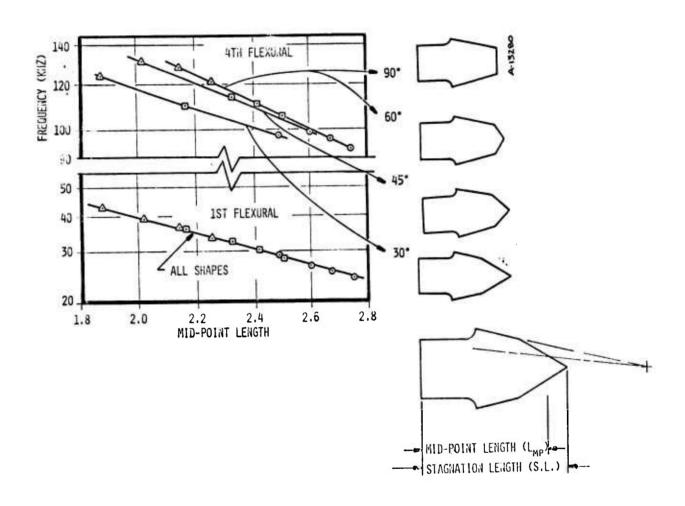


Figure 42. First and fourth flexural resonant frequencies versus midpoint length.

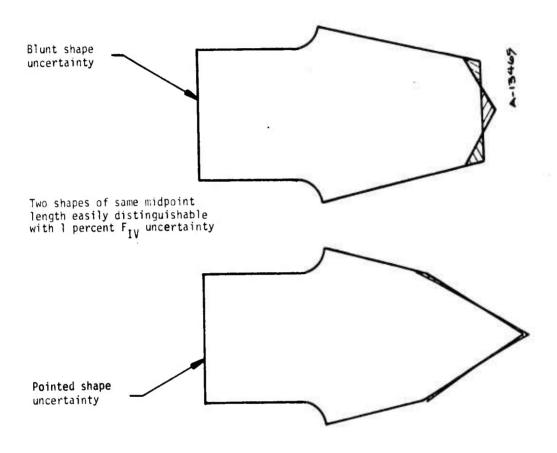


Figure 43. Shape uncertainty as a result of predicted frequency uncertainty.

SAP IV beam element predictions of higher order flexural or compressional mode frequencies are consistently higher than measured data. This is illustrated in Table 15, where beam analysis predictions and measurements of several flexural and compressional resonant mode frequencies for an aluminum nosetip of 30°, 45°, 60°, and 90° forecone angles are compared. These results demonstrate the increased deviation between predicted and measured frequencies for the higher order modes. A probable cause for this deviation is that the beam elements do not allow sufficient distortions to adequately model the three-dimensional solid body displacements produced at the higher frequency modes. Because of this restriction of the degrees of freedom, this causes the body to be artificially "stiff", increasing the predicted resonant frequency above the measured values.

To test the artificial stiffness hypothesis, a two-dimensional analysis of a nosetip-type shape was carried out, utilizing both SAP IV beam elements and the more sophisticated SAP IV quadrilateral brick elements. The brick elements model the detailed displacement in two-dimensions, whereas the beam elements only give displacements along the axis of the body. As shown in Table 16, the frequencies predicted using quadrilateral brick elements were lower than those using the beam elements. Also, the detailed brick element analysis gave additional resonant modes which were not predicted by the beam analysis. These are nonclassical beam type vibrations which, like the results shown in Figure 44, exhibit considerable distortion of initially flat planes. These vibrations may account for several resonant mode peaks found experimentally that cannot be identified with classical beam type vibrations as discussed previously.

Even though the SAP IV quadrilateral brick element planar calculation demonstrated the value of applying a more sophisticated element approach to calculate higher order modes for shape determination, the large increases in problem setup and computer time for the two-dimensional case precluded the use of SAP IV on a large matrix of three-dimensional cases. A search was then made to find a finite element code which, for a reasonable cost, could perform a detailed and accurate analysis of higher order axisymmetric nosetip resonant modes. A limited search uncovered the DIAL (Reference 6) and Shell Shock (Reference 7) codes, which nominally fit the analysis and cost objectives. Both utilize a Fourier decomposition of the flexural modes of axisymmetric bodies. This approach reduces the three-dimensional acoustic response problem (which SAP IV solves directly) to a much simpler two-dimensional problem. The corresponding problem setup and computer costs are thereby reduced significantly.

To check the relative accuracy of the SAP IV beam, DIAL and Shell Shock analyses, resonant mode calculations for a truncated aluminum cone were carried out and the predicted resonant frequencies compared. As indicated in Table 17, DIAL and Shell Shock resonant frequency predictions are

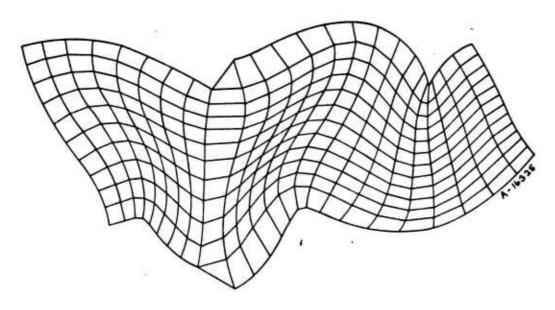
TABLE 15. COMPARISON OF SAP IV BEAM ANALYSIS RESONANT MODE FREQUENCY PREDICTIONS AND DATA FOR VARIOUS NOSE SHAPES

E = 9.704 x 10^6 $1bf/in^2$ ρ = 2.596 x 10^{-4} (1bf-sec²)/ in^4 v = 0.332

		Resonant	t Mode Fr	equencies Model	of 2.5-In (kHz)	Resonant Mode Frequencies of 2.5-Inch Long Aluminum Model (kHz)	ไนฑา๋กนฑ
	Forecone Angle	Compressional I II	sional II	F	Flex	Flexural III	IV
Test Results	90 60 45 30	45.55 46.95 48.34 51.19	75.88 78.69 81.30 84.70	25.66 27.60 29.32 31.96	47.23 50.30 53.00 54.95	67.46 69.43 70.76 70.40	92.8X 95.1X 95.8X 93.9X
Analysis	90 60 45 30	47.36 48.75 50.08 53.85	79.46 82.53 85.49 86.39	28.51 30.43 32.13 35.99	54.86 58.39 61.23 63.56	81.36 85.27 87.95 93.22	105.7X 111.0X 114.0X 110.2X
Percent Difference	90 60 45 30	3.8 3.6 5.2	4.7 4.6 5.2 2.0	11.1 10.3 9.5 12.6	16.2 16.1 15.5 15.7	20.6 22.8 24.3 32.4	13.9 16.7 19.0 17.3

TABLE 16. COMPARISON OF SAP IV BEAM AND QUADRILATERAL BRICK ELEMENT PREDICTIONS

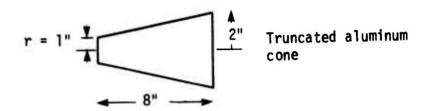
	Resonant	Mode Freq	uencies of (kh	a 2.5-Inc iz)	Resonant Mode Frequencies of a 2.5-Inch Aluminum Nosetip (kHz)	Nosetip
Approach	Compressional I II	sional II	1	Flexural II	ural III	IV
Beam	41.974	76.575	28.655	54.471	716.67	104.12
2-D Plane	40.591	72.129	25.560	44.563	61.743 65.602	86.276
Percent Difference	0.034	0.062	0.121	0.222	0.294	0.207



Modal frequency, 86.276 kHz

Figure 44. SAP IV quadrilateral brick element analysis.

TABLE 17. COMPARISON OF RESONANT MODE PREDICTIONS UTILIZING SAP IV, DIAL AND SHELL SHOCK



- a	Fred	quency (k	Hz)
Typea	SAP IV Beamb	DIAL	Shell Shock
t1 11 t2 12 13 14 15 15 16 17 18	13.77 26.62 39.58 52.47 7.89 16.97 26.40 35.48 44.27 52.74	9.24 13.57 16.88 24.71 25.39 27.88 32.51 34.29 40.19 40.21	9.41 13.56 17.16 25.04 25.31 28.39 32.77 33.74 6.85 14.10 21.30 25.60 29.70 31.50 33.40 36.80

 $a_t = torsion; 1 = compressional; f = flexural$

 $^{^{}b}$ May not correspond to 1_{1} , 1_{2} , ..., etc.

quite close to each other whereas SAP IV predictions are consistently higher, particularly for the higher order modes. Further, SAP IV beam and DIAL predictions of resonant frequencies for an aluminum nosetip are compared with measured values in Table 18. Deviations between SAP IV beam analysis results and data vary from -1.3 to 21 percent over the range of resonant modes predicted. The deviations of DIAL predictions from data varied from -3 to -6 percent. It should be noted that the material properties utilized in both calculations were identical. If material properties for the calculations were adjusted to give "exact" agreement for first flexural mode then, as shown in Table 18, the DIAL code would have much better agreement with data than the SAP IV analysis. Also, the DIAL code predicts two fourth flexural mode type responses consistent with measurement, whereas the SAP IV beam element only predicts one mode in that frequency range. Examining the displacement plots produced by the DIAL code shown in Figure 45, it can be seen that the two fourth flexural responses are quite similar except for some detailed displacements located near the outer edges of the nosetip and at the cone/plug juncture. The SAP IV beam analysis is not capable of defining these regions and, therefore, only a single resonant mode is found.

These comparisons clearly demonstrate the superiority of the DIAL and Shell Shock codes over the SAP IV beam analysis method for predicting shape.

Besides demonstrating the accuracy of the various methods, the truncated cone calculations also provide some information on the relative costs of the different methods. Table 19 summarizes the estimated relative costs of the different methods for problem setup, run and generation of displacement plots for the truncated cone case. Also included in Table 19 are some general comments relating to the methods. Based on a SAP IV two-dimensional brick element calculation, a rough order of magnitude cost estimate for a fully three-dimensional SAP IV calculation is included in Table 19. Except for a few baseline predictions, the cost penalty of the SAP IV three-dimensional method is prohibitive for a large number of cases.

Because of the easy problem setup and moderate cost, the DIAL code is applied to all dual mode gauge calculations requiring accurate higher frequency mode and detailed displacement predictions. The SAP IV beam analysis procedure is emphasized for all other calculations where shape predictions are not required.

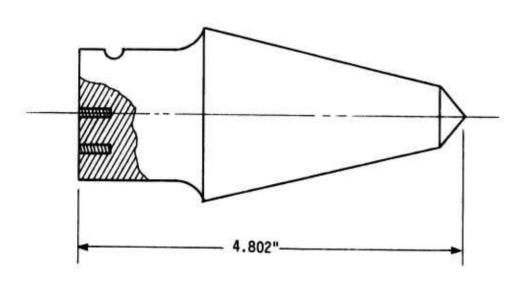
4.3.2 Applications

During this study a large number of resonant acoustic response calculations were made. This section focuses on the results of calculations which demonstrate the sensitivity of dual mode gage frequencies to temperature and nosetip length and shape.

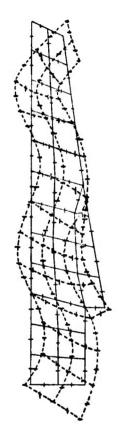
TABLE 18. COMPARISON OF SAP IV BEAM AND DIAL PREDICTIONS AND MEASUREMENTS

		Compre	essional	Frequencies	(kHz)		
Mode	Measured	Beam	%	Adjusted %	DIAL	%	Adjusted %
1 2 3 4	25.51 42.97 59.55	25.19 44.22 61.73 82.07	- 1.3 + 2.9 + 3.7	- 5.9 - 1.7 - 0.9	23.90 41.30 57.20 68.50	-6.0 -4.0 -4.0	XXXX XXXX XXXX

		Fle	xural Fre	quencies (kH	lz)		
Mode	Measured	Beam	%	Adjusted %	DIAL	%	Adjusted %
1 2 3 }4	11.66 23.00 34.63 45.62 47.78	12.20 24.77 37.97 55.22 55.22	+ 4.6 + 7.7 + 9.6 +21.6 +15.6	0.0 3.1 5.0 16.4 11.0	10.94 22.19 33.39 44.32 46.36	-6.0 -4.0 -4.0 -3.0	XXXX XXXX XXXX XXXX



Frequency: 44.3 kHz



Frequency: 46.4 kHz

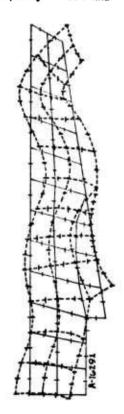


Figure 45. Fourth flexural beam type responses (DIAL code).

TABLE 19. RELATIVE COSTS OF PREDICTIONS UTILIZING SAP IV, DIAL, AND SHELL SHOCK CODES

	Relative Cost	Comments
SAP IV Beam	1.0ª	Easy problem setup, cheap, adequate for low frequency modes, can mode 3-D waveguides, isotropic material properties
SAP IV Three-Dimensional	~30	Difficult problem setup, expensive, accurate for all modes, can model 3-D waveguides, orthotropic material properties
DIAL	2.5	Easy problem setup, moderate cost, accurate for all modes, axisymmetric waveguide only, orthotropic material properties
Shell Shock	4.0	Moderate problem setup, moderate cost, accurate for all modes, axisymmetric waveguides only, orthotropic material properties

^aBaseline

4.3.2.1 Sensitivity of Higher Order Resonant Modes to Temperature

In Section 4.3.1 the impact of temperature on the first compressional resonant mode frequency was determined for tungsten and carbon/carbon nosetips. It was found that temperature effects could be accounted for in the predictions for tungsten and that no correction was required for carbon/carbon materials. For dual mode gauge purposes the effect of temperature on the relative position of the frequency maps is needed. This is of importance because the relative position between the frequencies establishes shape, and accurate predictions of frequency position are needed to reduce shape uncertainty to reasonable levels.

To assess the impact of temperature effects on relative frequency position the SAP IV beam analysis results for the 1 MW tungsten arc test model were reexamined. Geometry of the nosetip and waveguide are given in Table 1 and elastic modulus and temperature distributions as a function of time are given in Figures 36 and 37. Table 20 gives the results of the predictions for 0- (cold) second case are -0.59 to -4.74 at 5 seconds, and -3.0 to -9.9 at 10 seconds. The variation in relative position between the first and fourth flexural resonant mode frequency is 1.2 percent at 5 seconds and -1.2 percent at 10 seconds. If no temperature correction were applied, then the uncertainty of nosetip shape would be approximately that shown in Figure 33 for 1 percent uncertainty. With some correction for temperature the shape uncertainty could be reduced ever further.

For carbon/carbon nosetips, temperature corrections are not needed for establishing nosetip length from first compressional mode frequency. However, as in the case of tungsten, dual mode gauge applications require accurate predictions to reduce nose shape uncertainty. To assess the impact of temperature on the relative spacing of first and fourth flexural resonant mode frequencies, SAP IV beam analysis predictions were carried out on nosetip type shapes utilizing cold and hot carbon/carbon material properties. Both sharp and blunt ablated nosetip shapes were calculated to ensure bounding the temperature effect. Shapes and internal temperature distributions were generated using the SNAP code. Material property variation with temperature, given in Figure 46, was a compilation of several sources of data (Reference 5). The resonant mode frequencies calculated for the blunt and sharp shapes under cold and hot conditions are given in Table 21. Results for the sharp shape indicate that the relative position of the first and fourth flexural frequencies only varies by 0.4 percent in going from hot to cold conditions. The blunt shape variations of relative position is 1.2 percent for the first and fourth flexural frequency. As in the tungsten nosetip case, the shape uncertainty created by roughly 1 percent frequency uncertainty would be similar to that given in Figure 33. With some correction for temperature the shape uncertainty could be reduced below that illustrated in Figure 33.

TABLE 20. EFFECT OF TEMPERATURE ON HIGHER ORDER MODES

	Resonant		ies of a Tun ten Arc Test	gsten Nosetip Model	on a
Modea (cold)	t = 0	t = 5 sec	% 10 sec Change	t = 10 sec	% 0-10 sec Change
f ₁	14.53	14.36	-0.59	13.94	-4.1
f ₂	30.48	29.79	-2.27	28.21	-7.5
L	31.19	30.93	-0.94	30.25	-3.0
f ₃	48.11	46.69	-4.74	43.37	-9.9
L ₂	55.64	54.46	-3.97	51.67	-7.1
f ₄	66.01	64.30	-1.90	64.11	-2.9

af = flexural
L = compressional

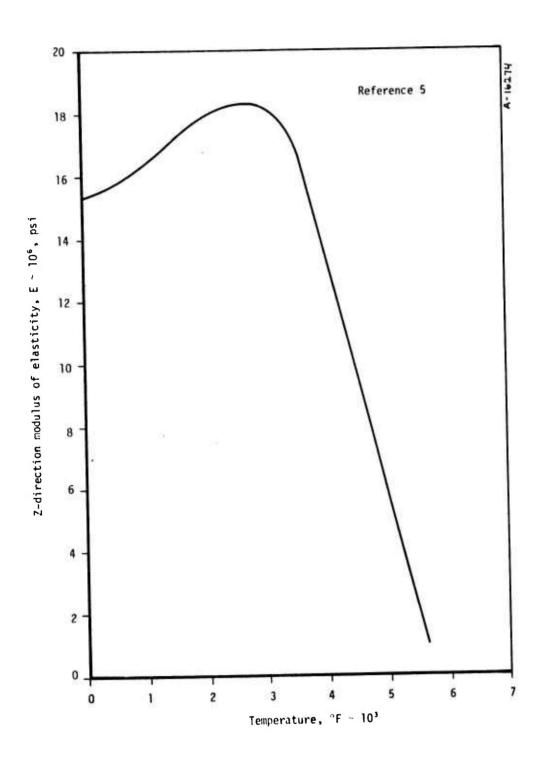


Figure 46. Elastic modulus of carbon/carbon material versus temperature.

441-1

TABLE 21. SENSITIVITY OF CARBON/CARBON FLIGHT CONFIGURATION RESONANT FREQUENCIES TO TEMPERATURE

				Resonant Moc	le Frequenci	Resonant Mode Frequencies (kHz) of Blunt Shapes	Blunt Shapes				
Analysis Type	ı	Compressional II	sional III	IV	1	11	111	Flexural IV	۸	VI	IIV
Cold	27.079	42.262	70.200	86.950	14.803	31.799	44.717	59.534	75.529	81.036	95.701
Hot	27.287	42.887	71.410	87.832	14.892	32.278	45.229	60.154	74.248	82.134	97.438
Hot/Cold	1.00768	1.01479	1.01724	1.01014	1.00601	1.01506	1.01145	1.01881	1.00978	1.01355	1.01815

				Resonant Moc	de Frequenci	Resonant Mode Frequencies (kHz) of Sharp Shapes	Sharp Shapes				
Analysis Type	I	Compressional II III	ional III	IV	-	11	111	Flexural IV	۸	ΙΛ	VII
Cold	25.131	37.953	60.952	79.600	13.097	25.827	38.482	47.457	58.867	70.331	77.269
Hot	25.253	38.223	61.693	80.300	13,145	26.094	38.847	47.880	58.696	68.990	76.156
Hot/Cold		1.00485 1.00711	1.01216	1.00000	1.00366	1.01034	1.00948	1.00891	1.99710	1.98093	1.98560

4.3.2.2 Sensitivity of Carbon/Carbon

In the operation of the acoustic gage either one or two resonant mode frequencies are tracked as a function of time. The magnitude of these frequencies alters as the nosetic shape, length and material properties change. A primary purpose of analysis is to assess the sensitivity of the resonant mode frequencies to nosetic shape and length changes. From the predictions it can be established if sufficient sensitivity is available for inferring nosetic shape and length even before the nosetic/waveguide system is manufactured. Also, the predictions indicate if any resonant frequencies will interfere or cross during nosetic shape and length change. The interference of resonant frequencies can make frequency tracking difficult during flight.

As an example of the assessment of the effects of nosetip shape and length changes on resonant mode frequencies, DIAL code predictions of carbon/carbon nosetips resonant frequencies are presented in Figures 47 and 48. Figure 49 gives the nosetip geometry and material properties input into the code for this case. The geometry is characteristic of those typically employed during subscale, subvelocity flight tests for material screening purposes. For simplicity, waveguides are not included in the predictions. Two overall lengths, 4.5 and 5.5 inches, at four forecone nose angles, 80°, 60°, 45°, and 30°, were calculated to characterize the resonant frequencies under the assumed nosetip shape and length change. Figure 47 presents the results in terms of midpoint length whereas Figure 48 gives the results in terms of the "corner" length (length from the nosetip plug end to the intersection of the nosetip major cone and forecone faces). It is apparent that results presented in terms of "corner" length give a better straight line fit of all first flexural resonant frequencies. This makes is easier to interpret the fourth flexural frequency results in terms of sensitivity to nose shape. However, it should be noted that for dual mode gage applications, there is nothing fundamental or unique about the presentation of the data in this manner. For flight data reduction purposes a much more precise map of resonant frequencies in terms of overall nosetip length is probably more appropriate than the maps presented in Figures 47 and 48.

From Figure 47 it can be seen that, at a 4.25-inch corner length, an 8.5-, 1.1-, and 1.7-kHz fourth flexural frequency change is produced by going from 30° to 45°, 45° to 60°, and 60° to 80° nosetip forecone angles, respectively. These frequency bands represent 13.7, 1.6, and 2.5 percent of the absolute frequency found at the initial forecone angle. If it is assumed that a frequency error of 1 percent can exist between modal analysis predictions and measurements in flight due to:

- Temperature effects on material properties
- Nonconical nose shapes

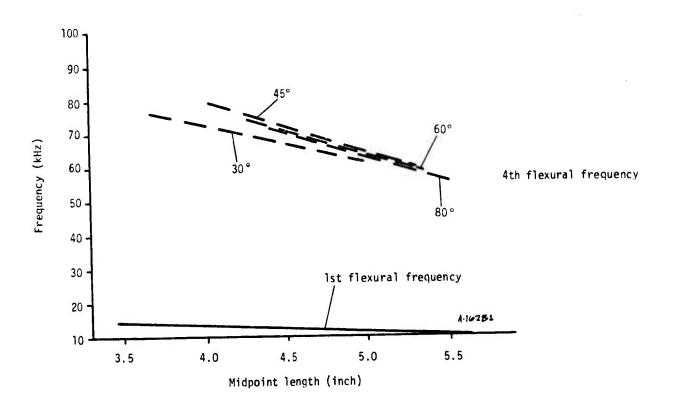


Figure 47. First and fourth flexural resonant mode frequencies vs. midpoint length.

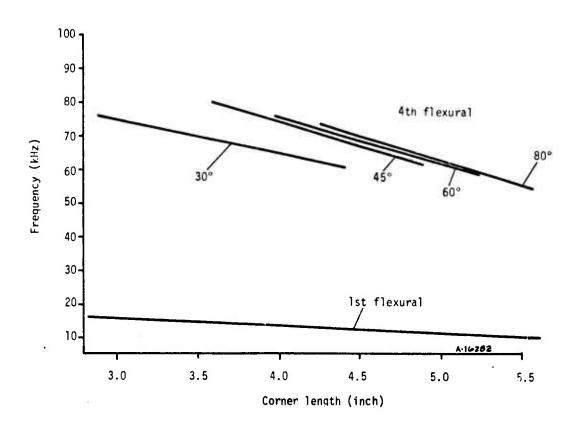


Figure 48. First and fourth flexural resonant mode vs. corner length.

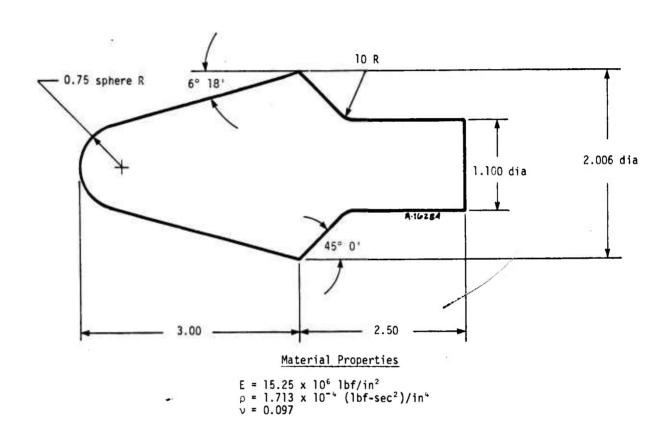


Figure 49. Carbon/carbon nosetip geometry and material properties.

- Complex waveguides
- Nonideal boundary conditions
- Forced response and damping
- Crystals and electronics

then a forecone angle uncertainty can be defined. Table 22 summarizes the angle uncertainties produced by a 1-percent fourth flexural frequency uncertainty. The angle uncertainties are only average values for the specified nose angle intervals. Predictions for several more forecone angles would yield a smoother distribution of angle uncertainty. From these results, it may be concluded that, when applied to the first and fourth flexural resonant modes of the above nosetip, the acoustic gage can determine sharp shapes with good accuracy and blunter shapes with less accuracy. The gage would certainly indicate whether the nosetip was sharp or blunt. For different selections of resonant mode frequencies or other nosetip/waveguide geometries and materials the above conclusion might be altered.

TABLE 22. NOSE ANGLE UNCERTAINTY DUE TO FREQUENCY UNCERTAINTY

Nose Angle Band	Angle Uncertainty
30° - 45°	±1°
45° - 60°	±9°
60° - 80°	±8°

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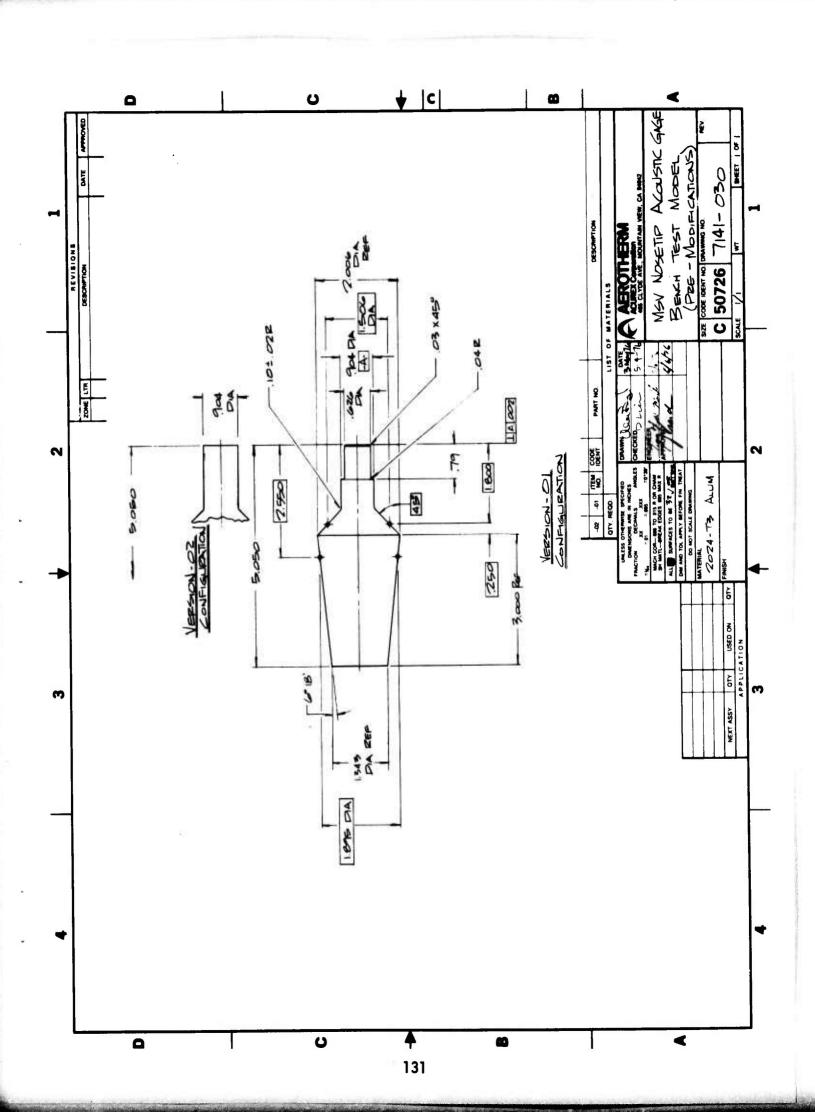
APPENDIX A DETAIL HARDWARE DRAWINGS

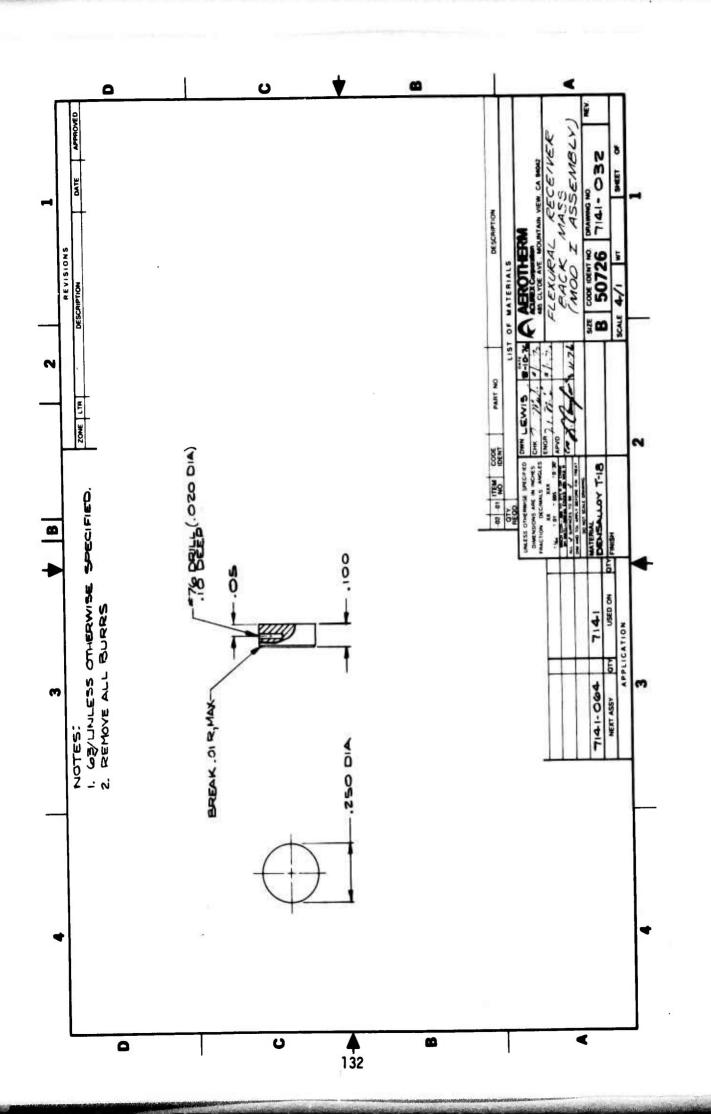
TABLE OF CONTENTS FOR APPENDIX A

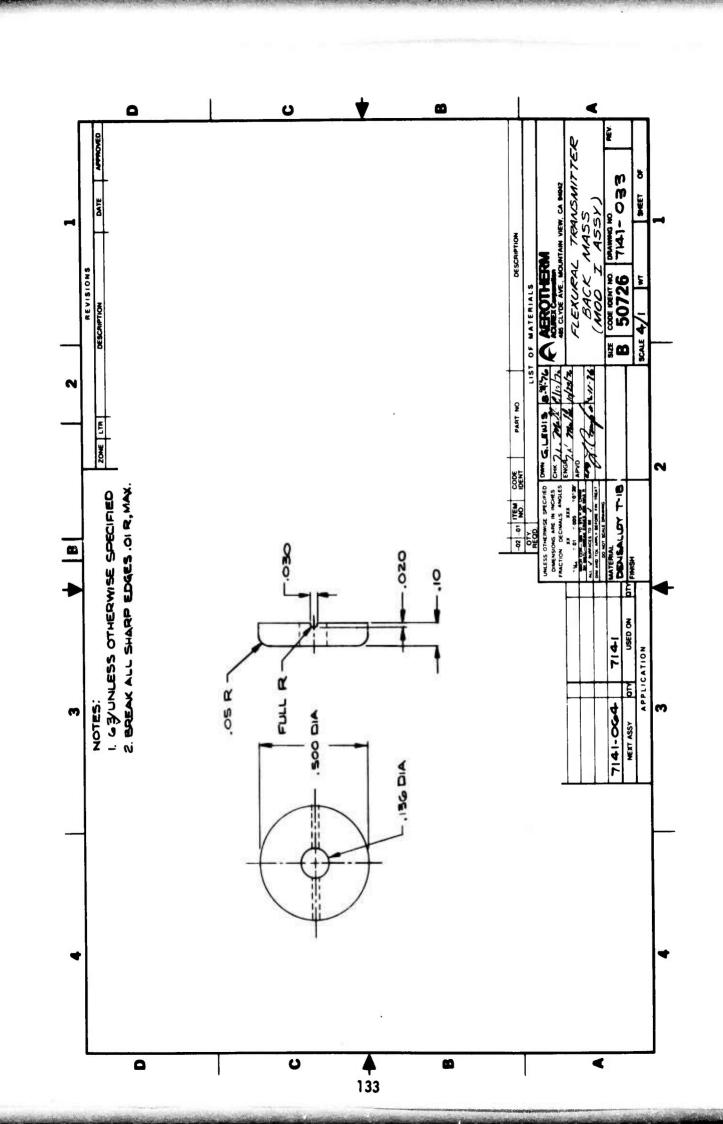
Description	Drawing No.	Page
MSV Nosetip Acoustic Gage Bench Test Model (Pre-Modifications)	7141-030	131
Flexural Receiver Back Mass (Mod I Assembly)	7141-032	132
Flexural Transmitter Back Mass (Mod I Assy)	7141-033	133
Test Dowel	7141-034	134
Concentric Flexural Waveguide (Mod I Assembly)	7 41-035	135
Cover, Concentric Flexural Housing (Mod I Assembly)	7141-036	136
Concentric Flexural Housing (Mod I Assy)	7141-037	137
Ablative Washer — ARG 50 MW Arc-Jet Test Unit	7141-041	138
Acoustic Recession Gage, 50 MW Carbon/Carbon Tip — Nosetip	7141-042	139
Adapter — ARG 50 MW Test III	7141-043	140
Model Holder	7141-044	141
Acoustic Recession Gage, 50 MW Model Assembly	7141-045	142
Heat Shield 1 MW	7141-046	143
Model Holding Fixture, Shake Test	7141-056	144
Receiver Back Mass — Mod I	7141-058	145
Transmitter Back Mass — Mod I	7141-059	146
Receiver Base — Mod I	7141-060	147
Gage Outer Case — Mod I	7141-061	148
Receiver Case — Mod I	7141-062	149
Transmitter Base and Pedestal — (Mod I Compressional)	7141-063	150
Flexural Acoustic Gage Assembly (Dual Mode Sensor) Mod I	7141-064	161
Compressional Acoustic Gage Assembly (Single Mode Sensor) Mod I	7141-065	152
Transmitter Electrode	7141-066	153
50 MW Nose Tip Test Assembly (Dual Mode Sensor)	7141-067	154
50 MW Nose Tip Test Assembly (Single Mode Sensor)	7141-068	155
Cable Support Tube	7141-069	156
Acoustic Recession Gage — 50 MW	7141-070	157
Holder — 1 MW	7141-072	158
Test Model — 1 MW	7141-073	159
Model Holder — 1 MW	7141-074	160
Mounting Flange — 1 MW	7141-075	161

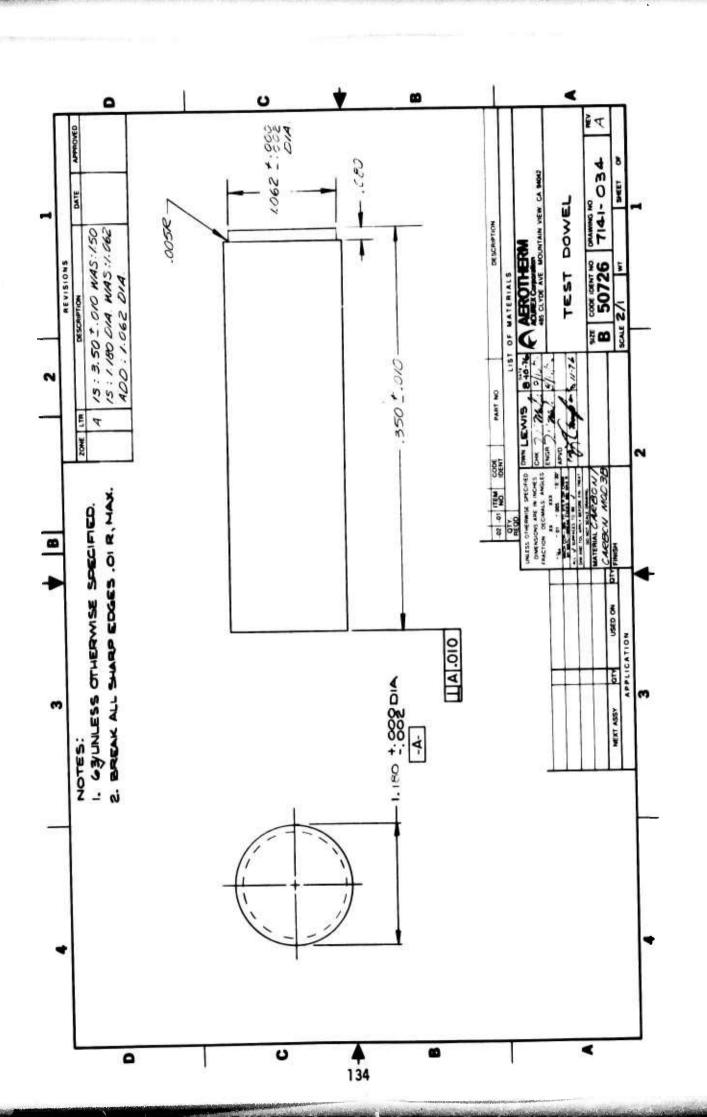
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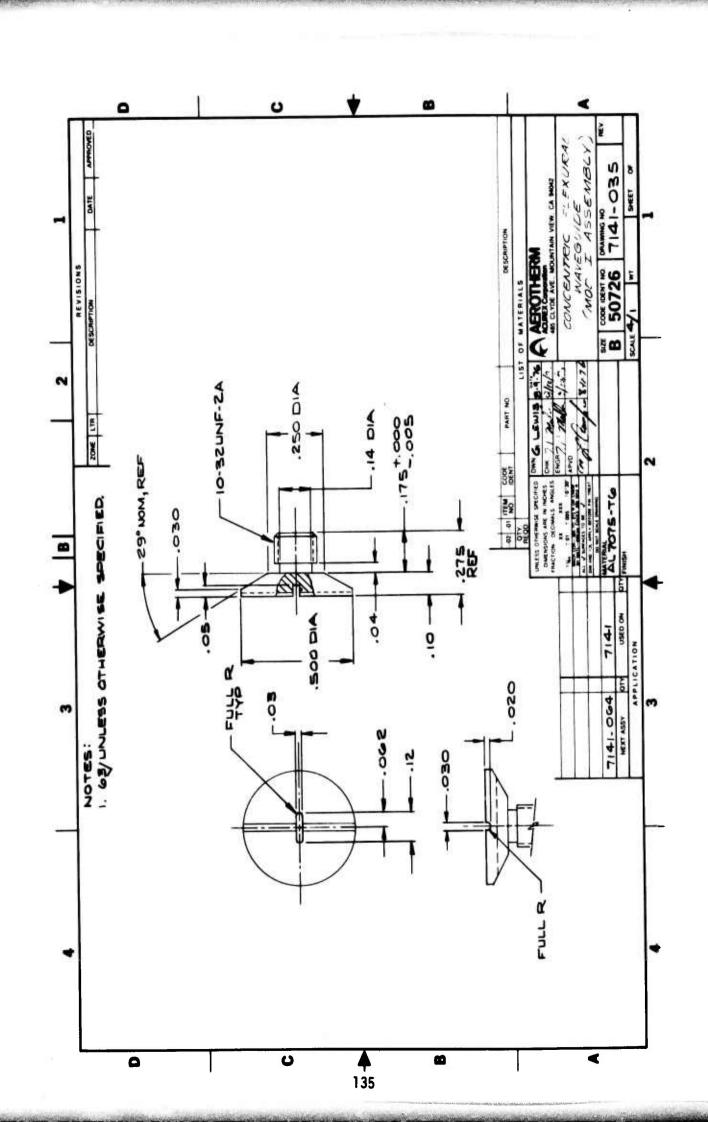
Description	Drawing No.	Page
l MW Test Assembly — with Flexural Acoustic Gage (Dual Mode Sensor) Mod I	7141-076	162
Housing, Flexural Acoustic Gage — Mod II	7141-077	163
Housing, Flexural Acoustic Gage — Mod III	7141-078	164
Receiver Assembly Compressional Acoustic Gage (Single Mode Sensor) Mod I	7141-079	165
50 MW-III Acoustic Gage Assembly (Single Mode Compressional Sensor) Mod II	7141-080	166
Flexural Acoustic Gage Assembly (Dual Mode Sensor) Mod IV	7141-081	167
Flexural Acoustic Gage Assembly (Dual Mode Sensor) Mod V	7141-082	168
50 MW-III Acoustic Gage Assembly (Dual-Single Mode Compressional Sensor) Mod III	7141-083	169
Flexural Acoustic Gage Assembly (Dual Mode Sensor) Mod III	7141-083	170
50 MW SSN/ARG Model 6 Assy	7141-085	171
50 MW SSN/ARG-6 Model Holder	7141-086	172
50 MW SSN/ARG-6 Nosetip	7141-987	173
Threaded Receiver Base Mod II Assembly	7141-088	174
Threaded Transmitter Waveguide	7141-089	175
50 MW-III Nose Tip Assembly (Single Mode Compressional Sensor)	7141-090	176
50 MW-III Nose Tip Assembly (Dual Mode Compressional Sensor)	7141-092	177
Acoustic Recession Gage Carbon/Carbon Nosetip	7141-093	178
Acoustic Recession Gage 50 MW-III Model Assembly	7141-094	179
50 MW-III ARG Model Holder	7141-095	180
Acoustic Recession Gage — 50 MW Test Assy	7141-096	181
Modified Transmitter Base and Pedestal — (Mod II Assembly)	7141-097	182
Flexural Acoustic Gage Base (Mod II Assembly)	7141-098	183
Flexural Acoustic Gage Assembly (Dual Mode Sensor) Mod II	7141-099	184

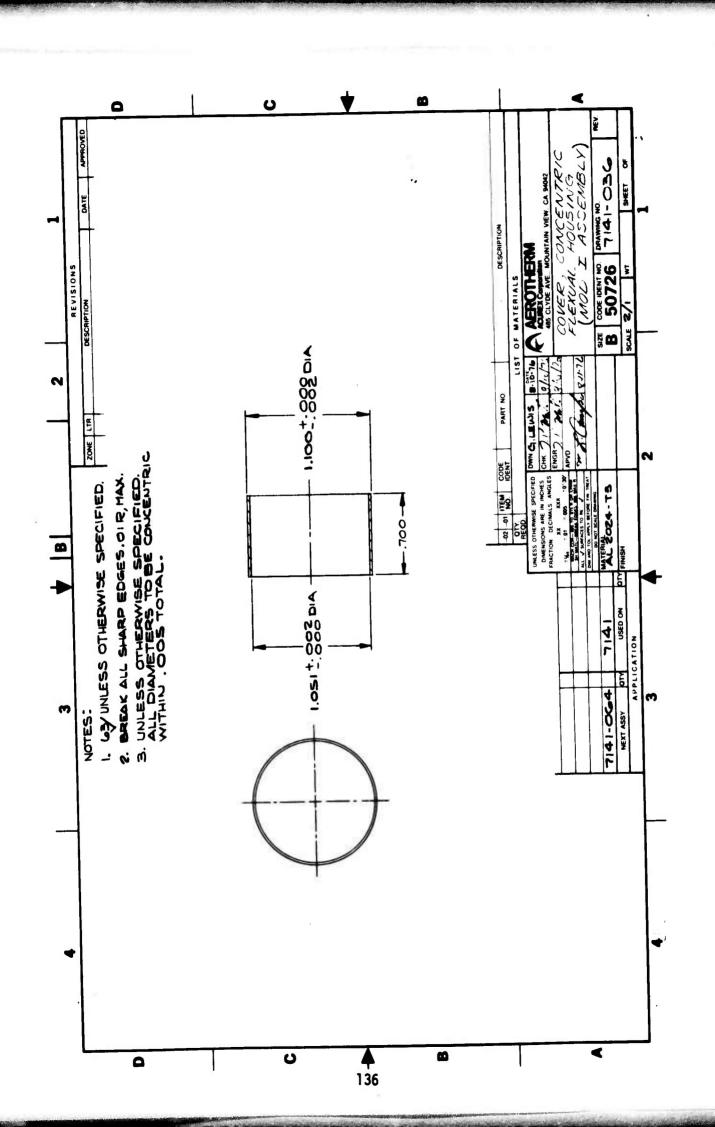


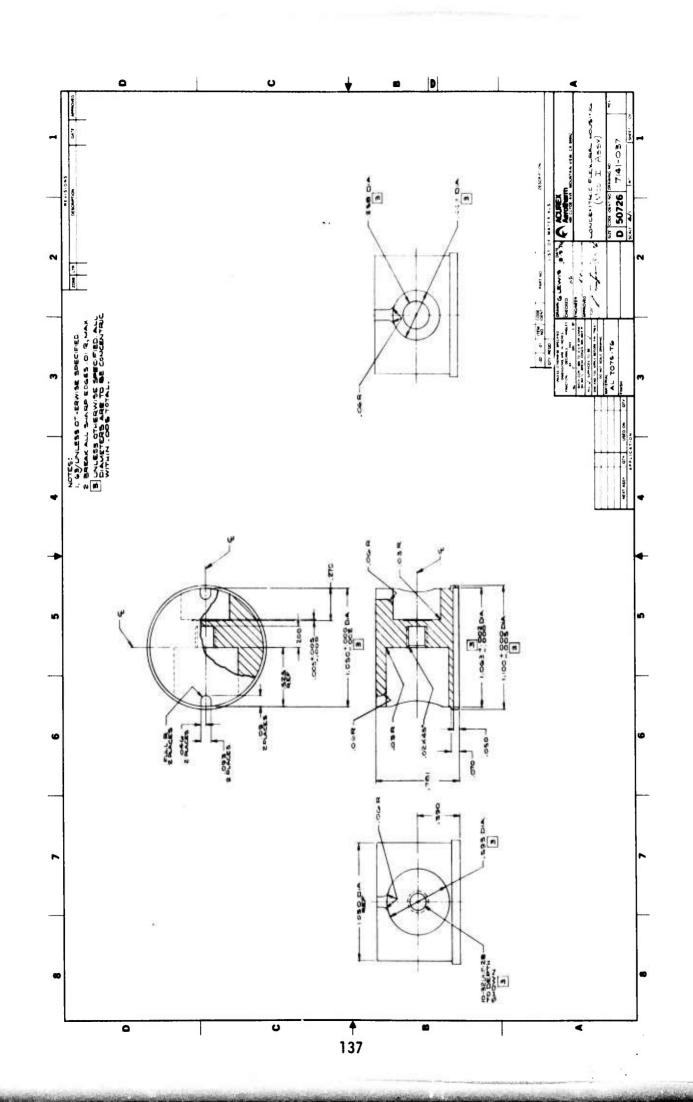


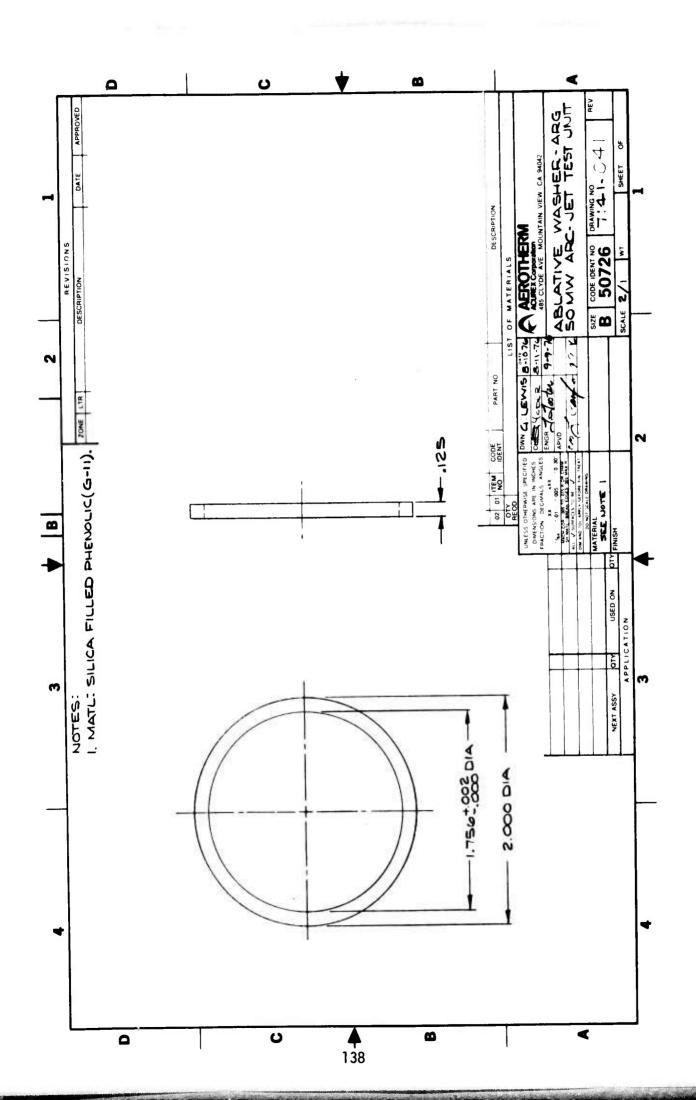


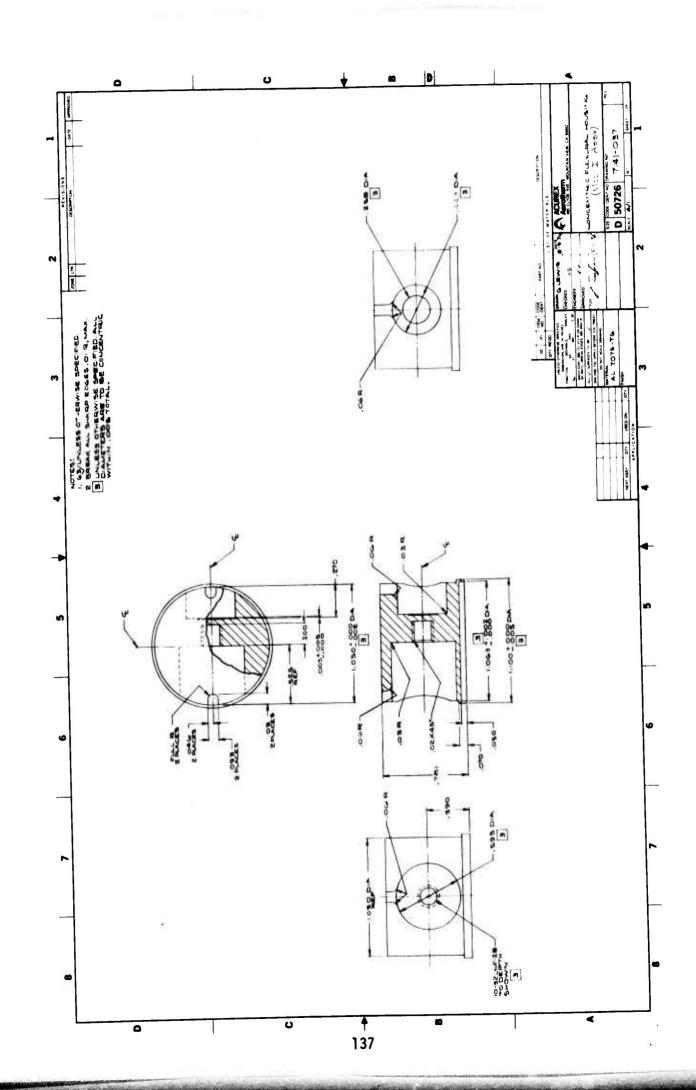


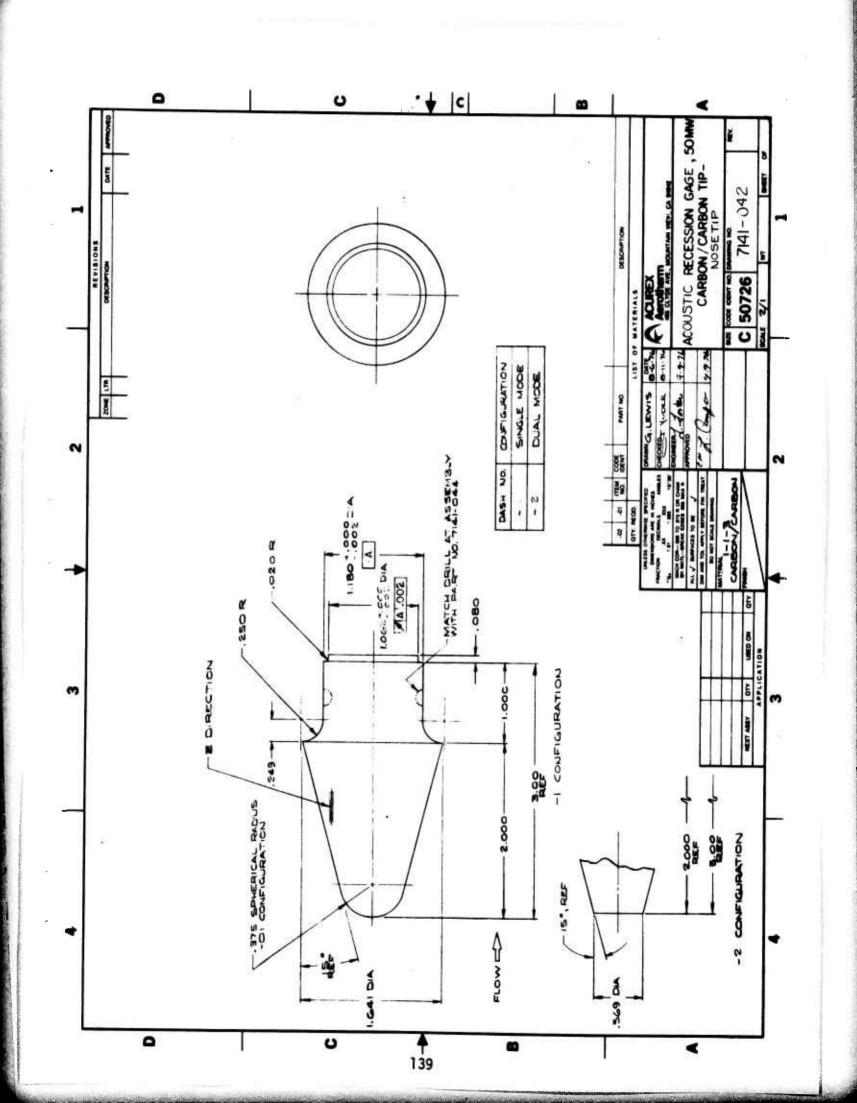


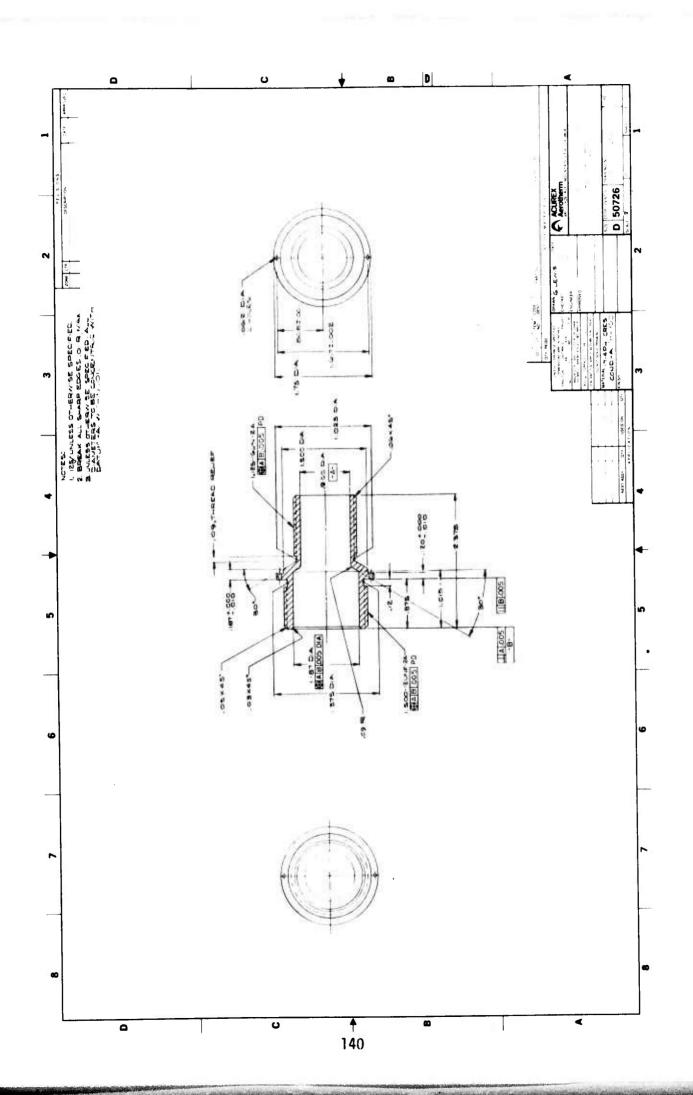


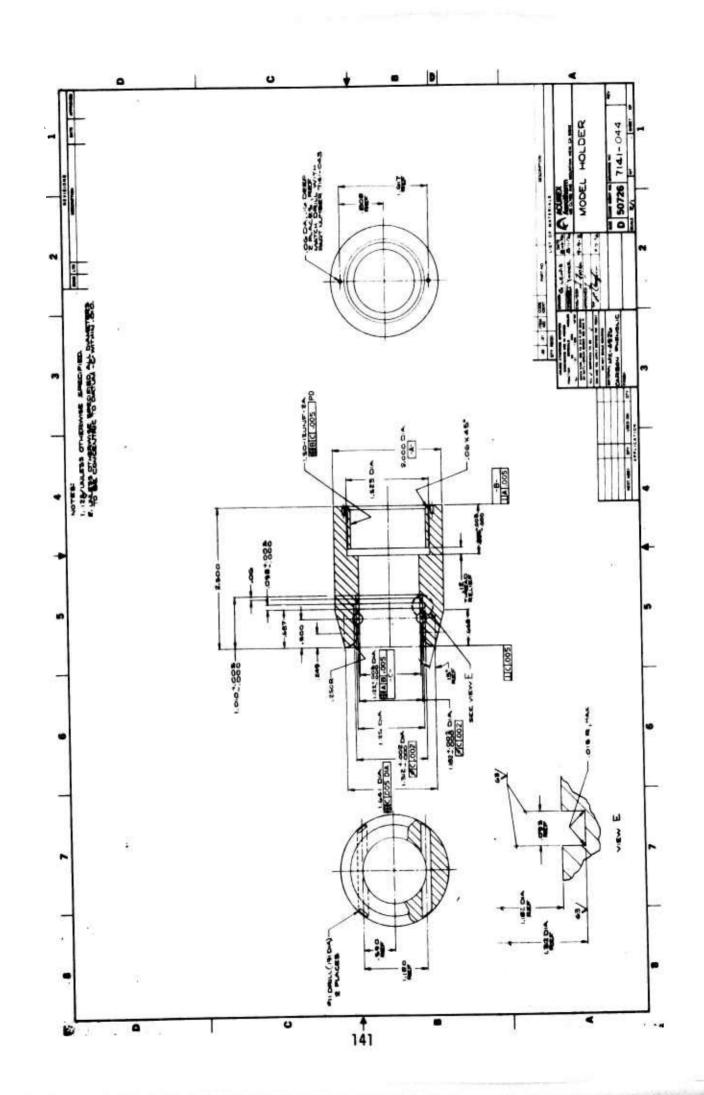


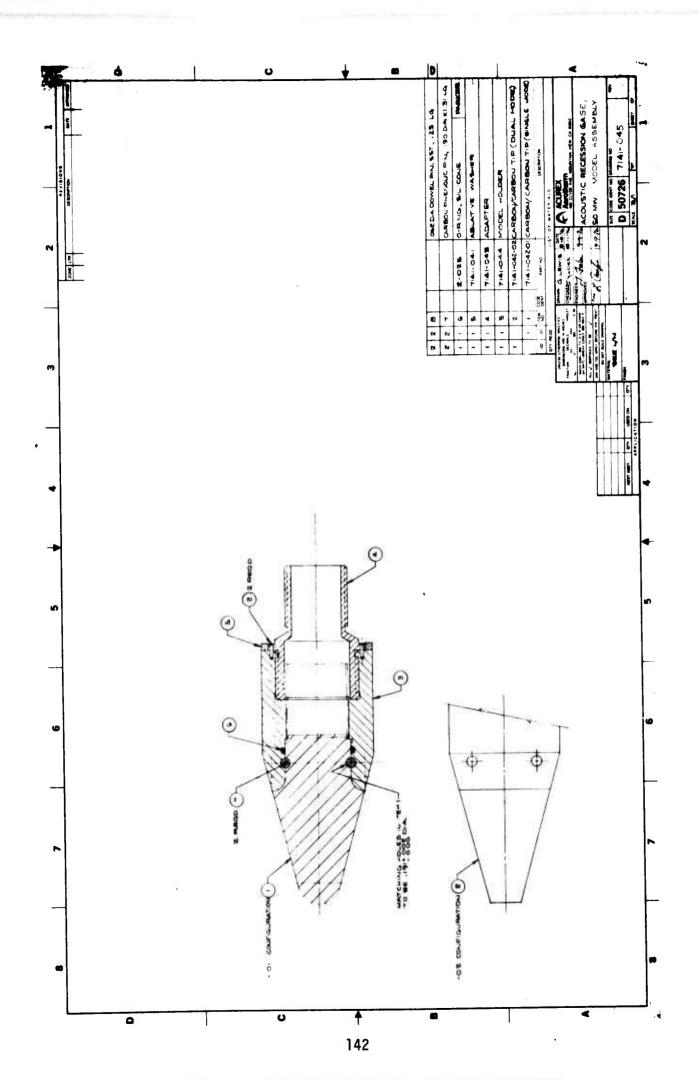


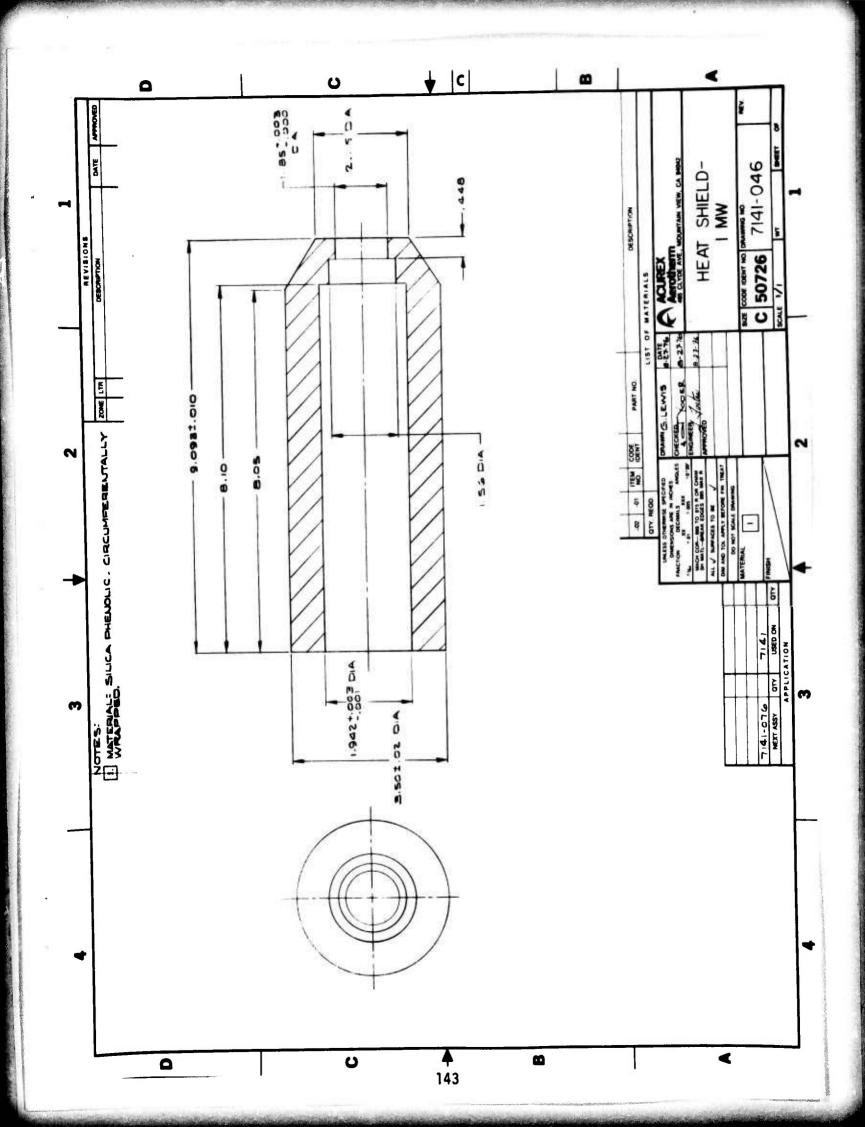


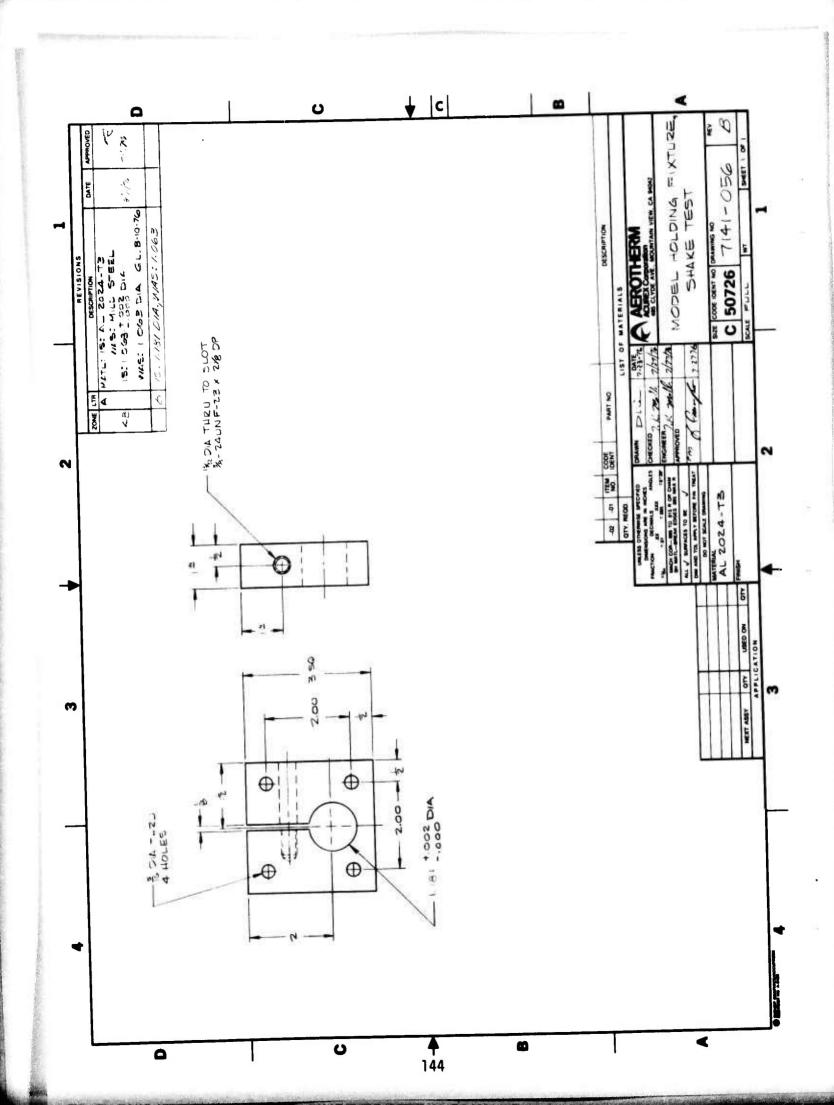


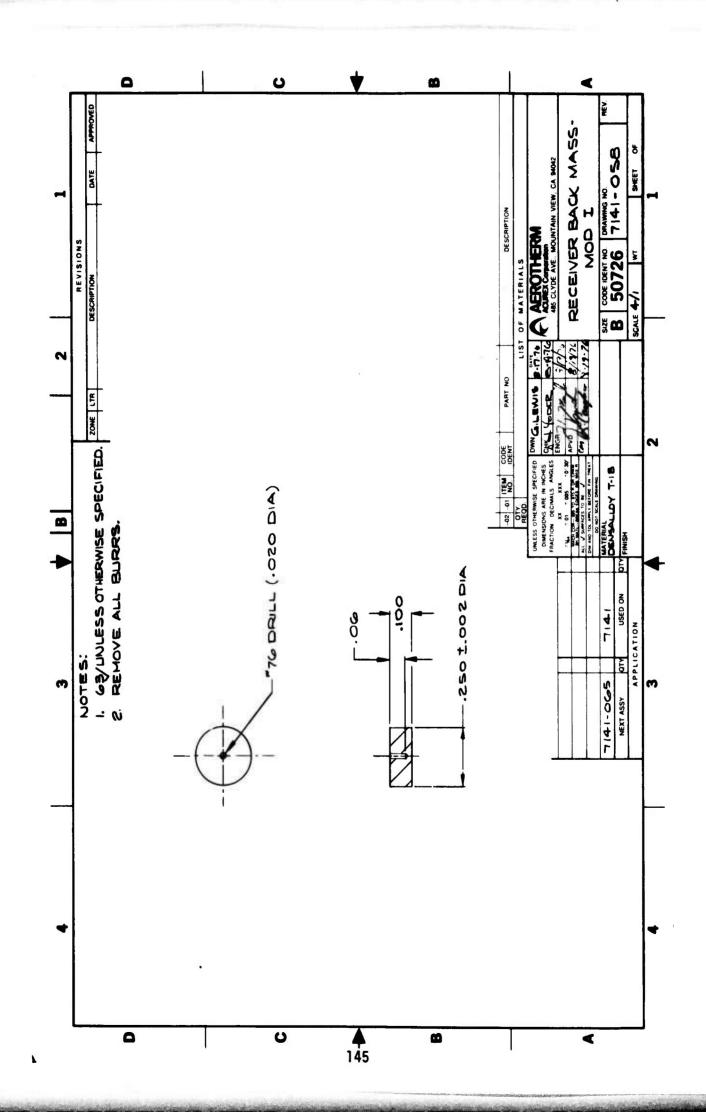


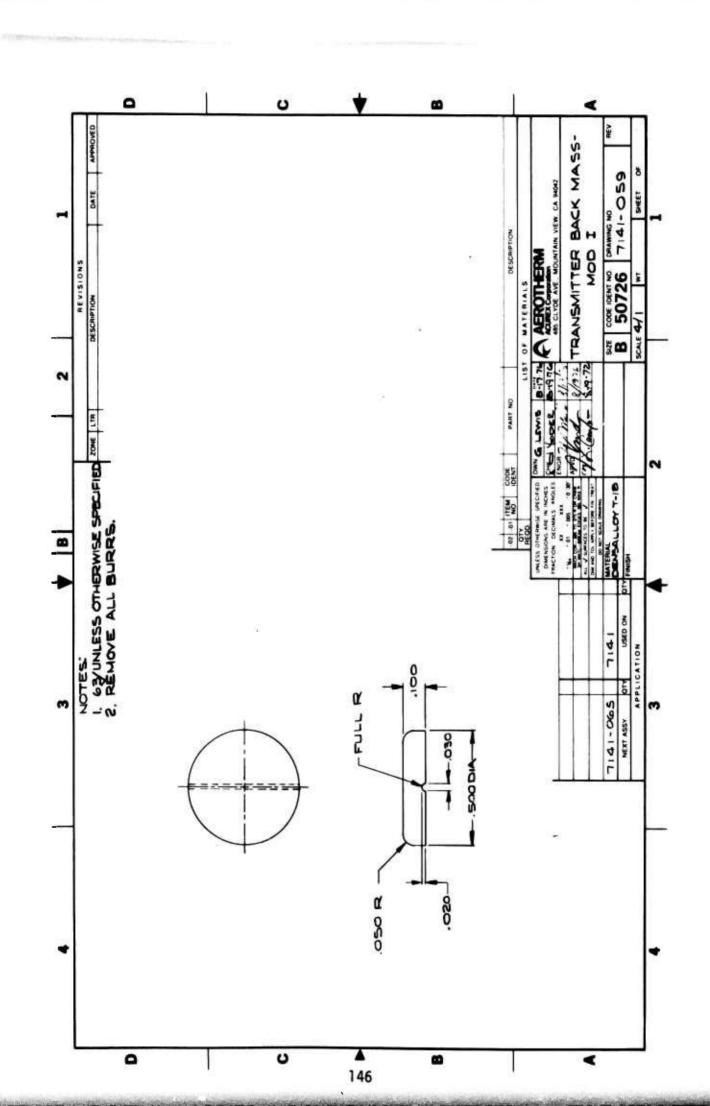


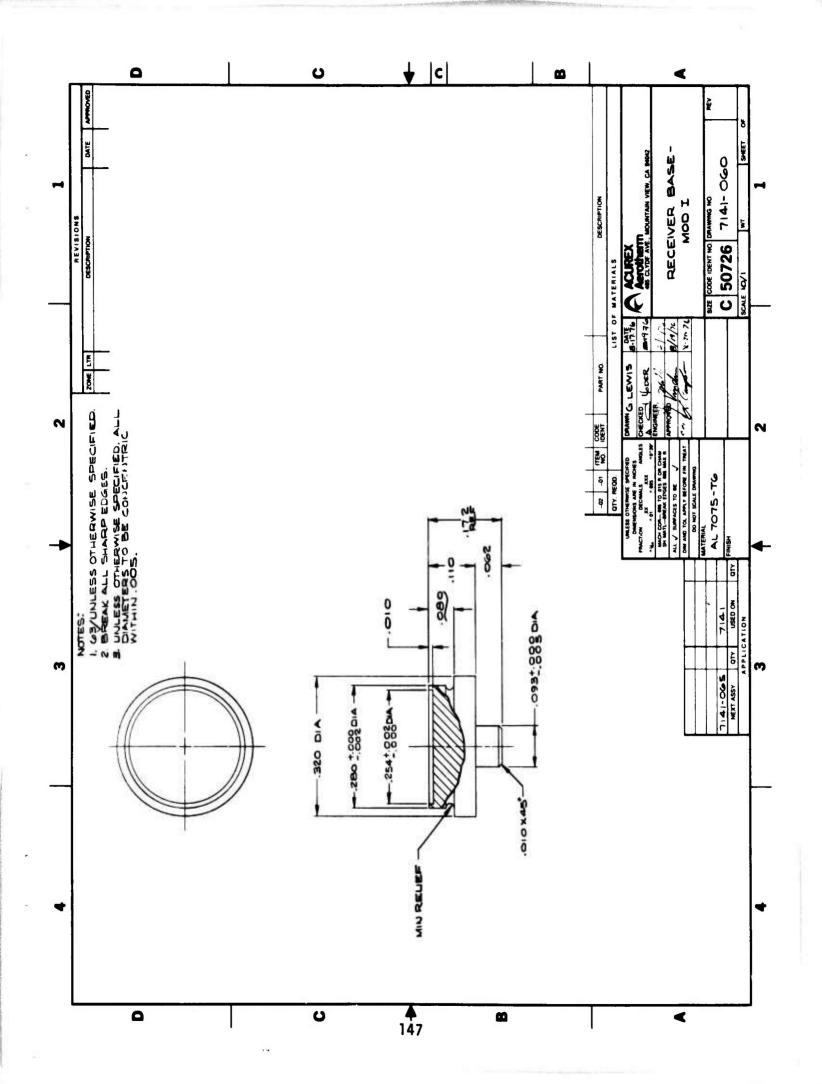


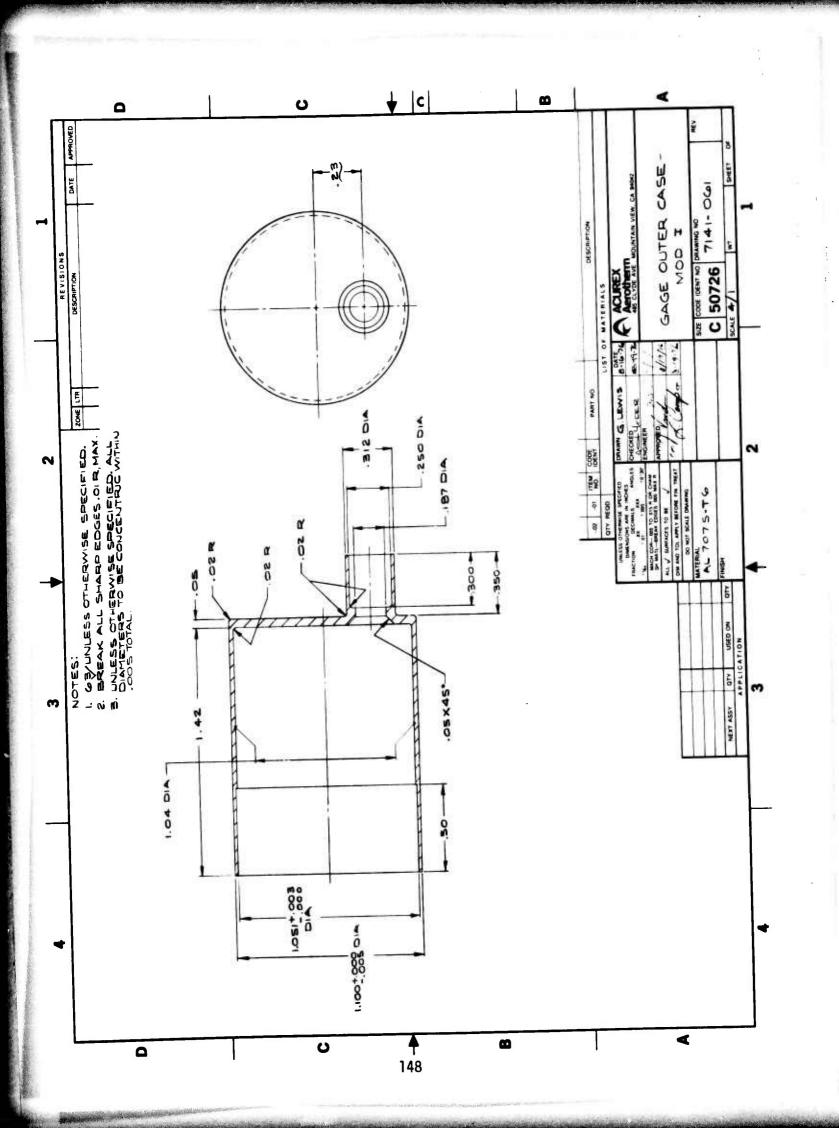


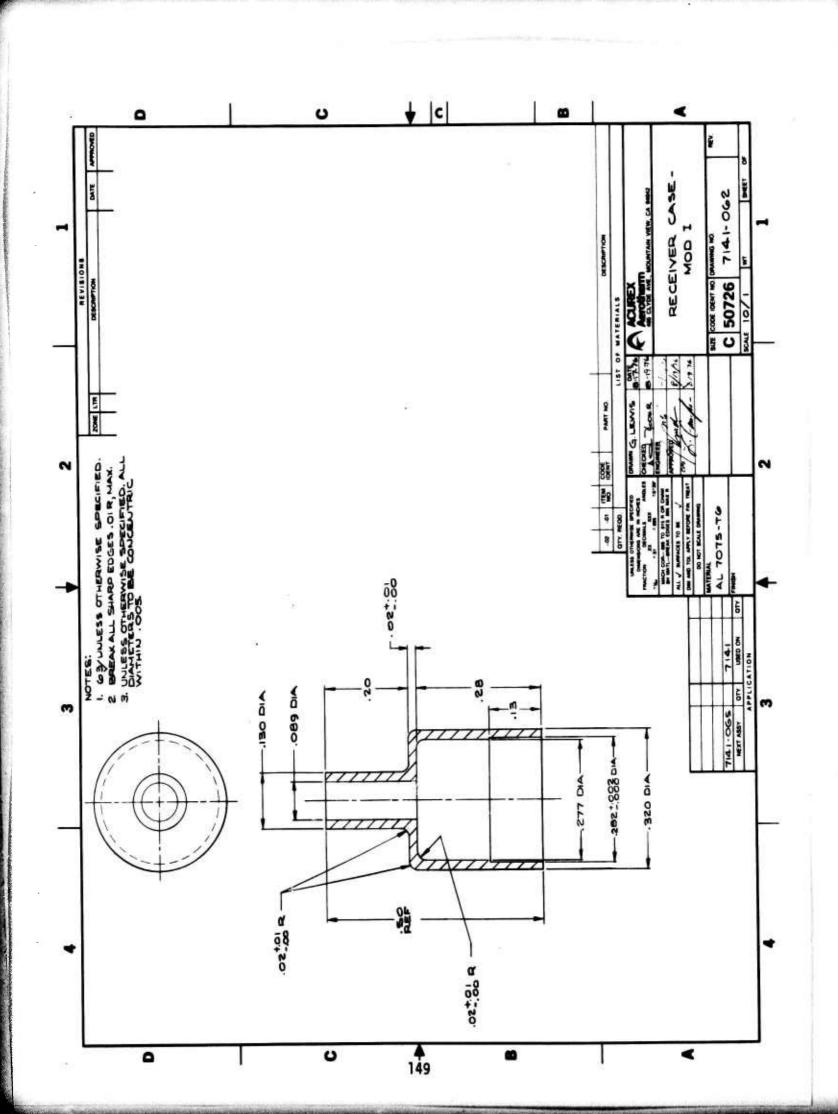


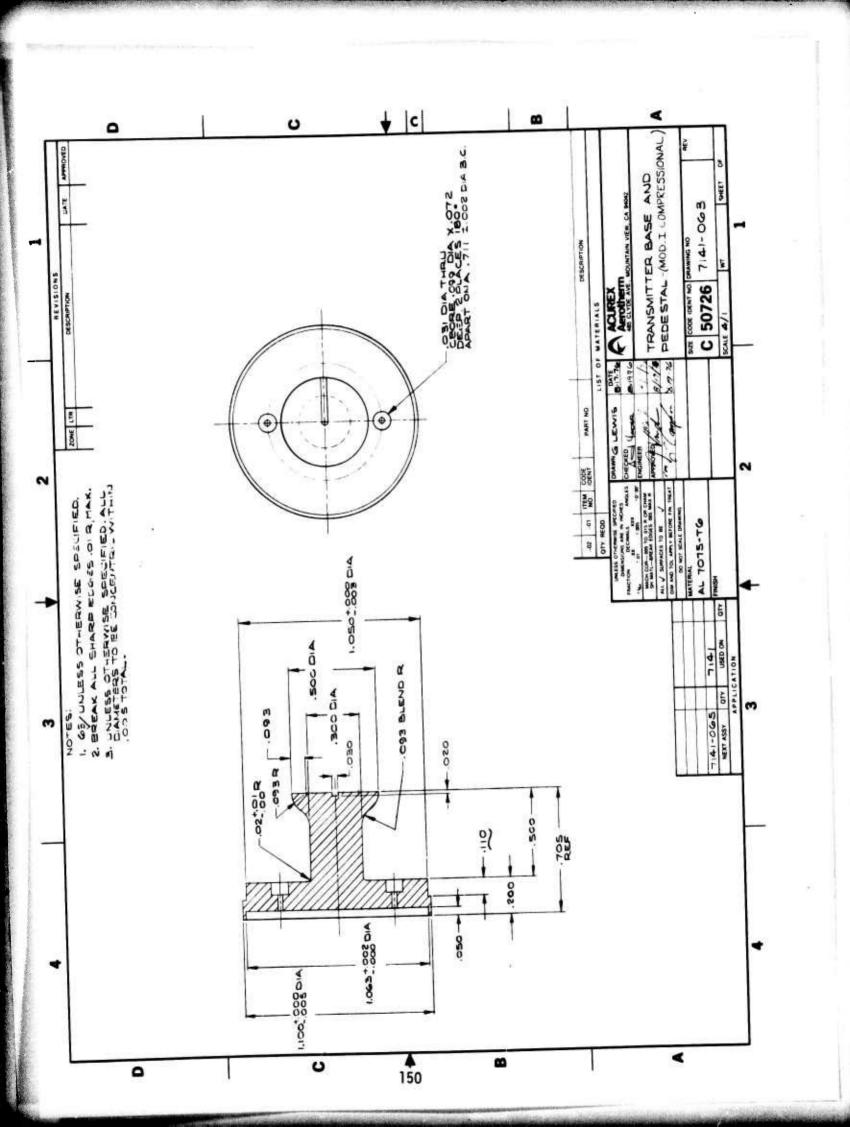


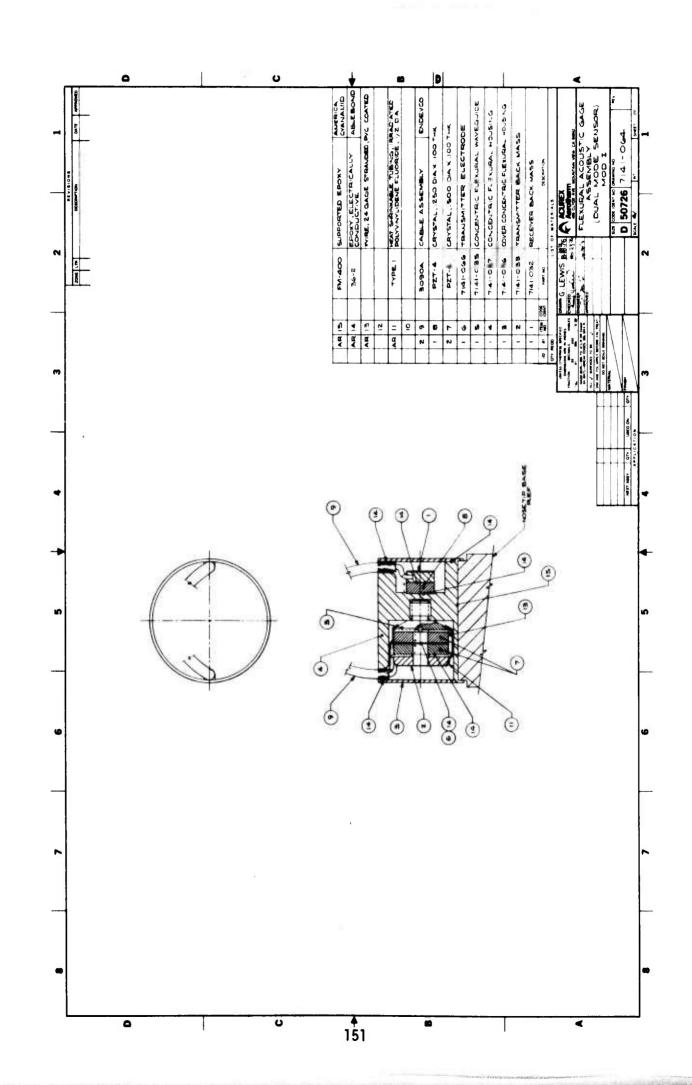


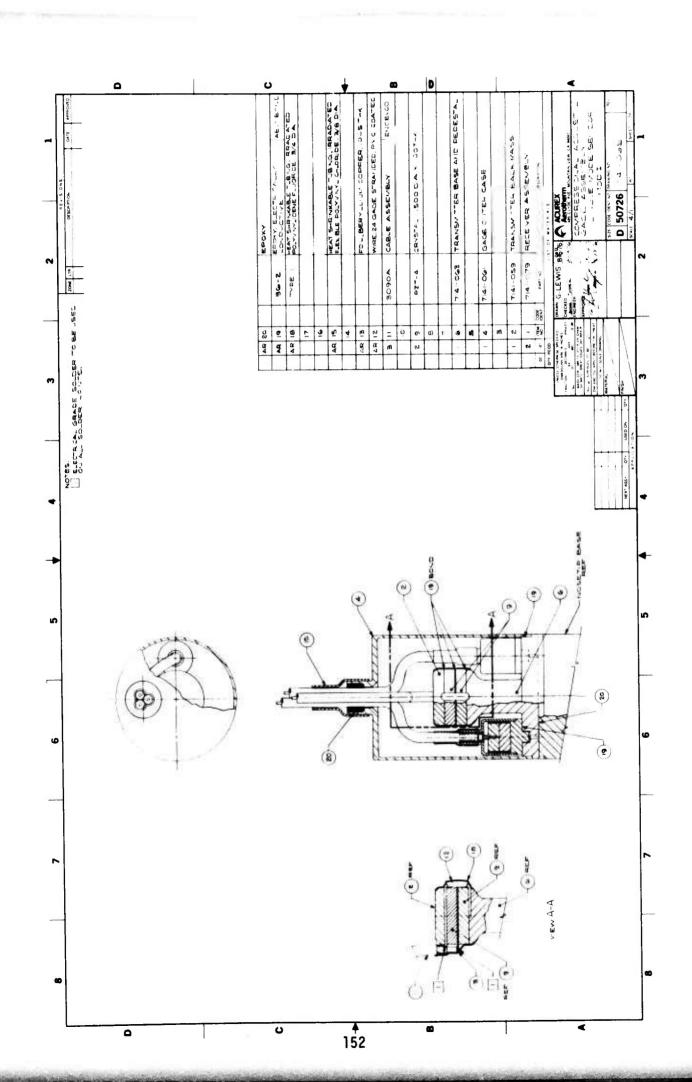


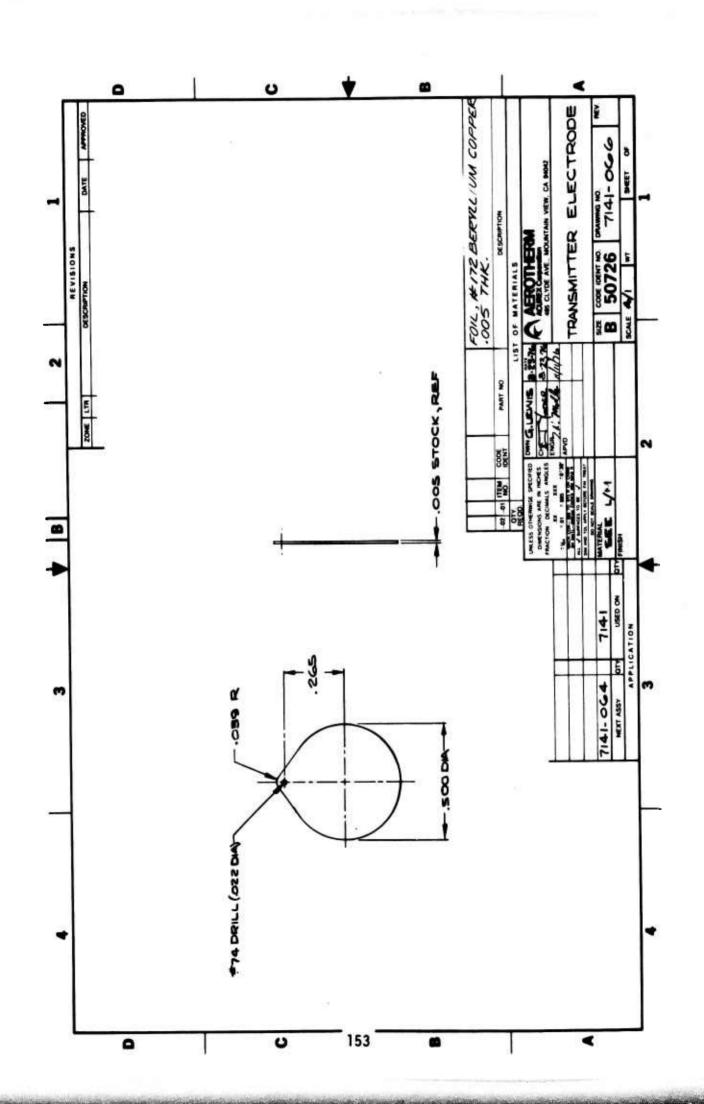


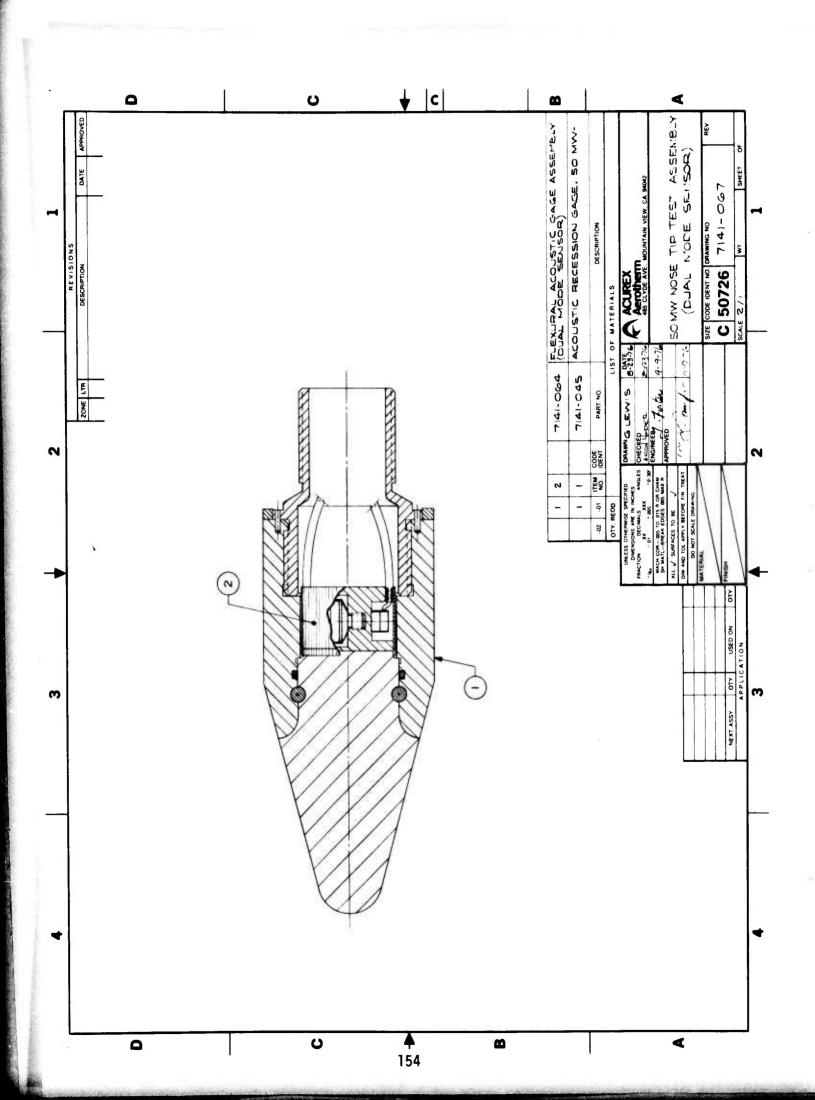


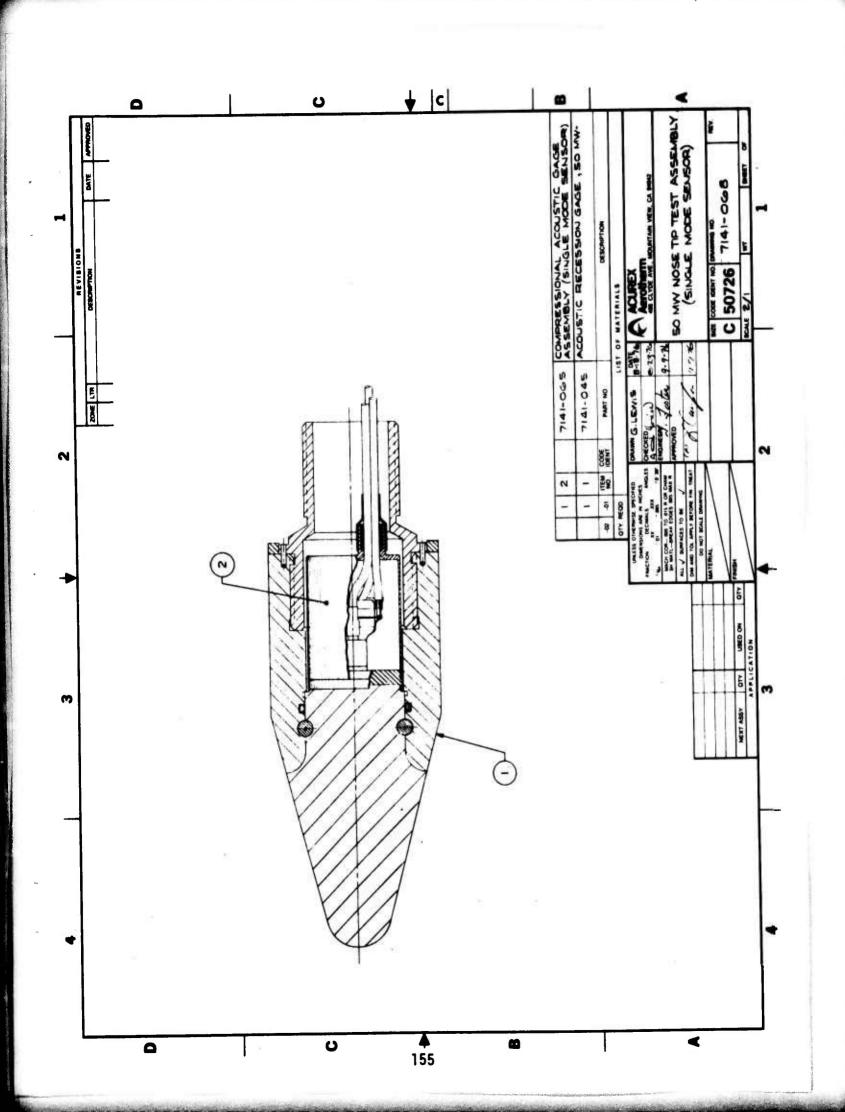


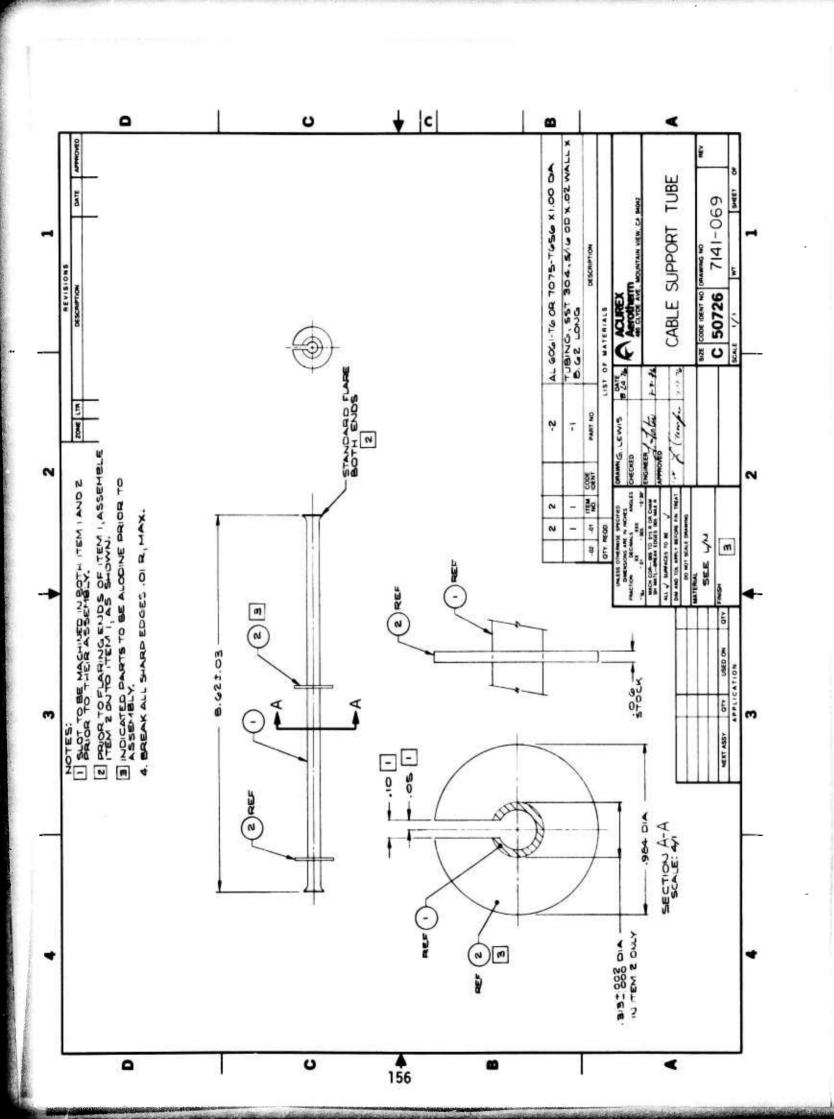


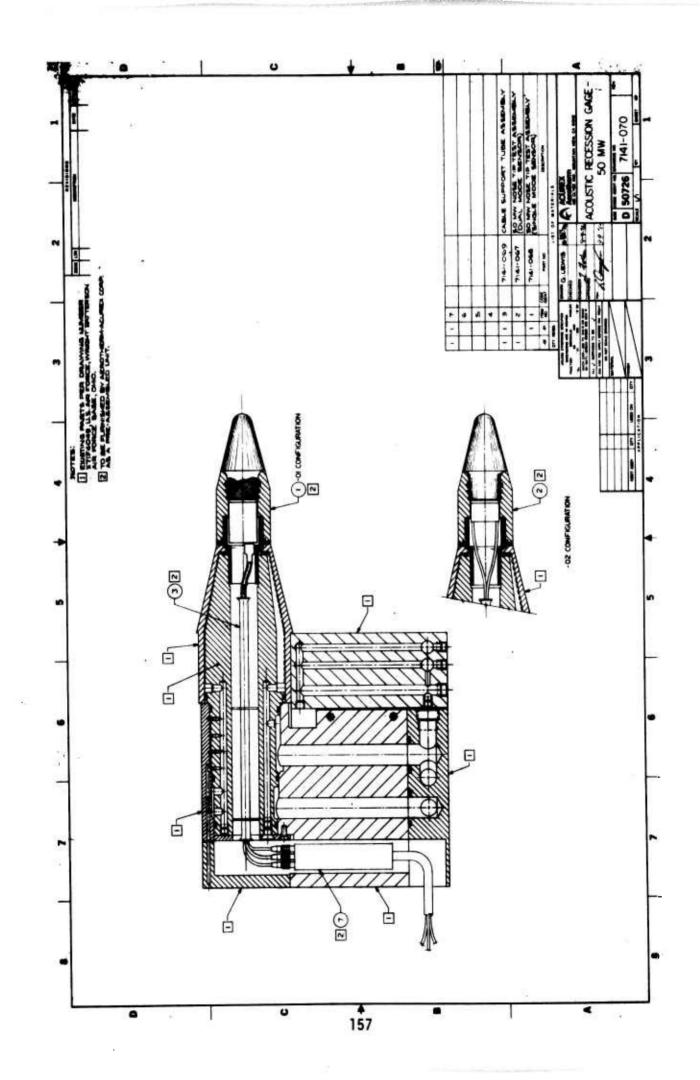


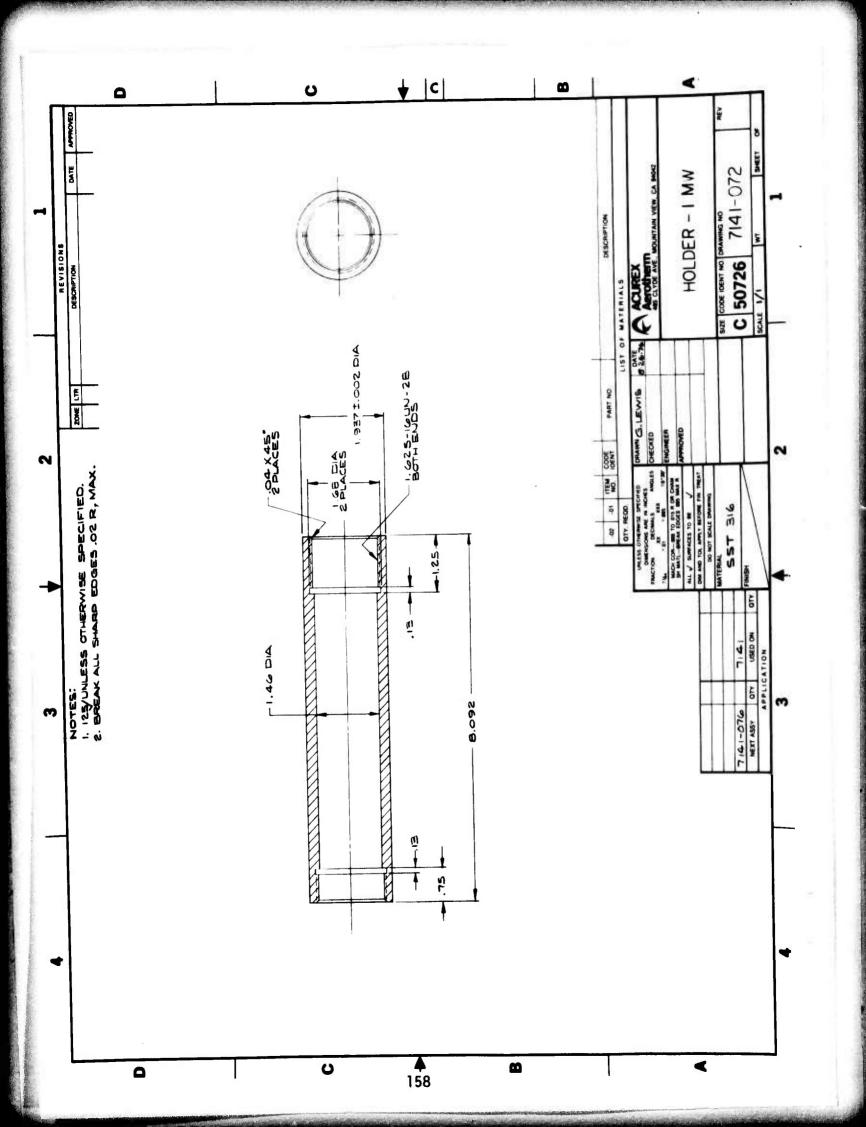


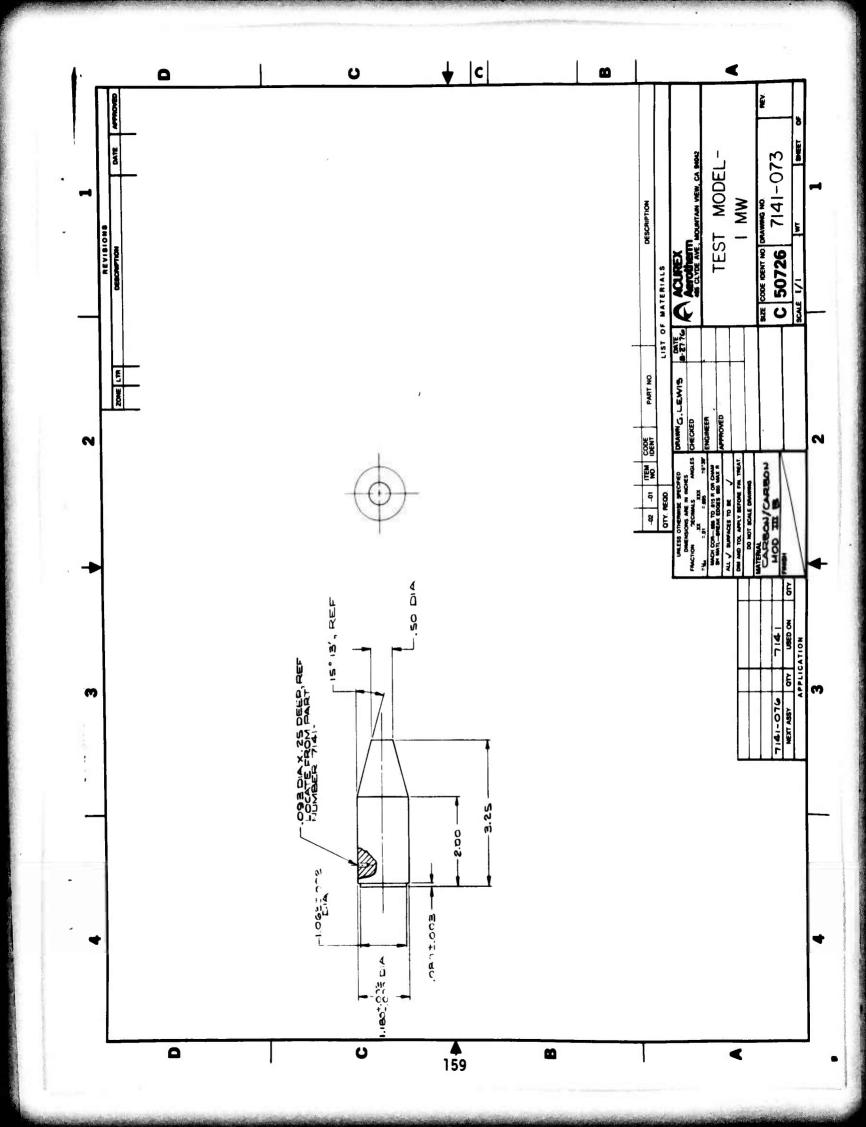


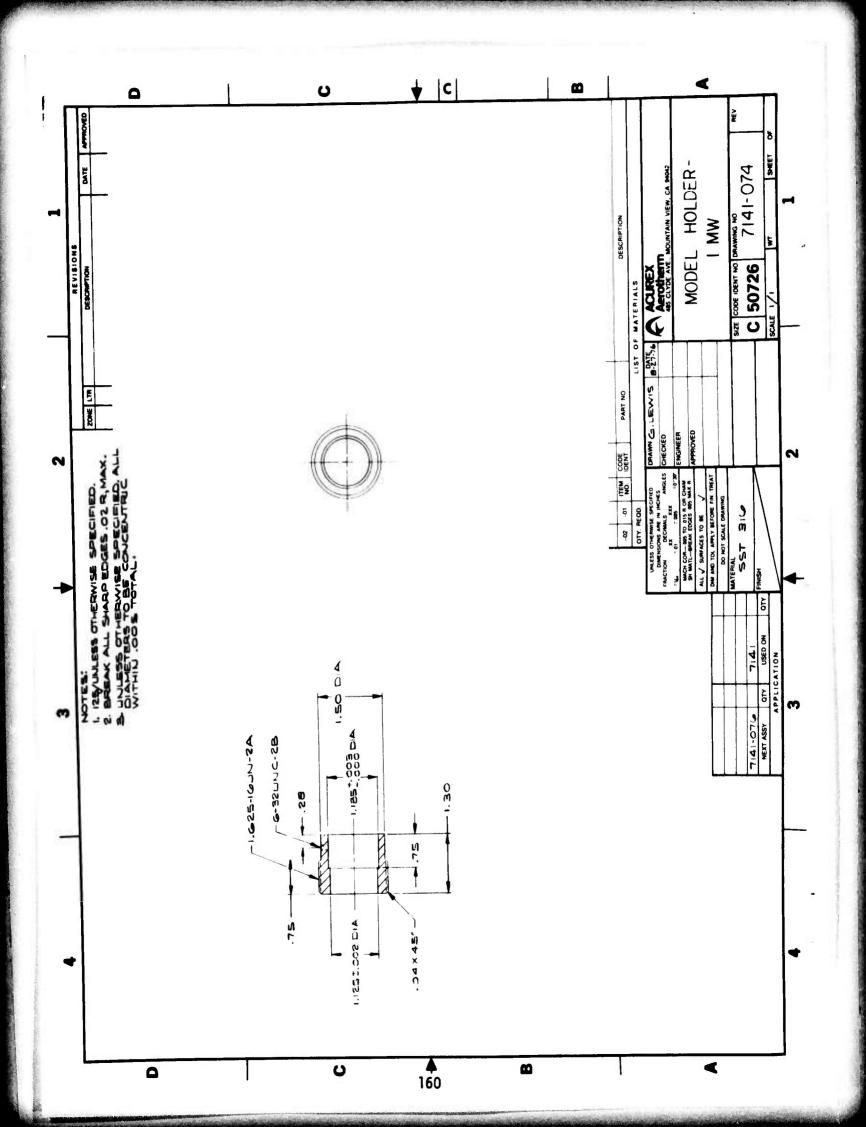


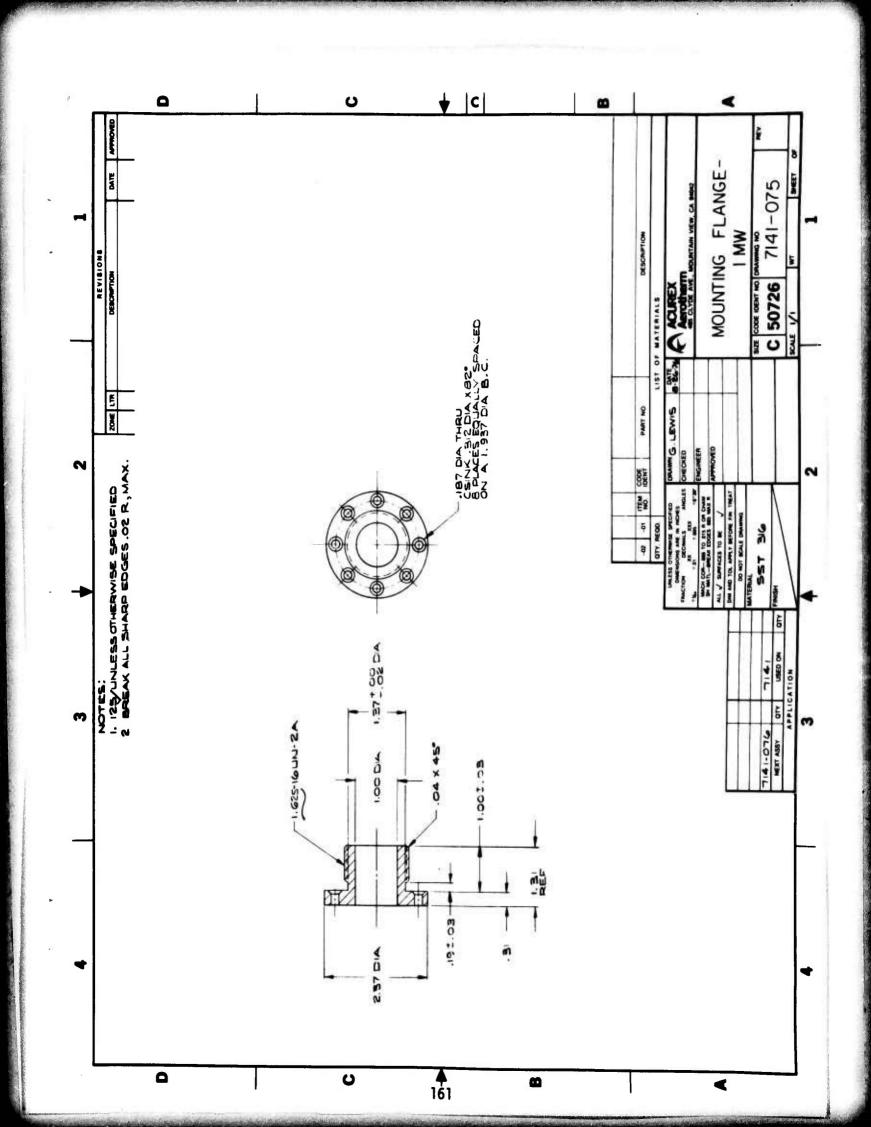


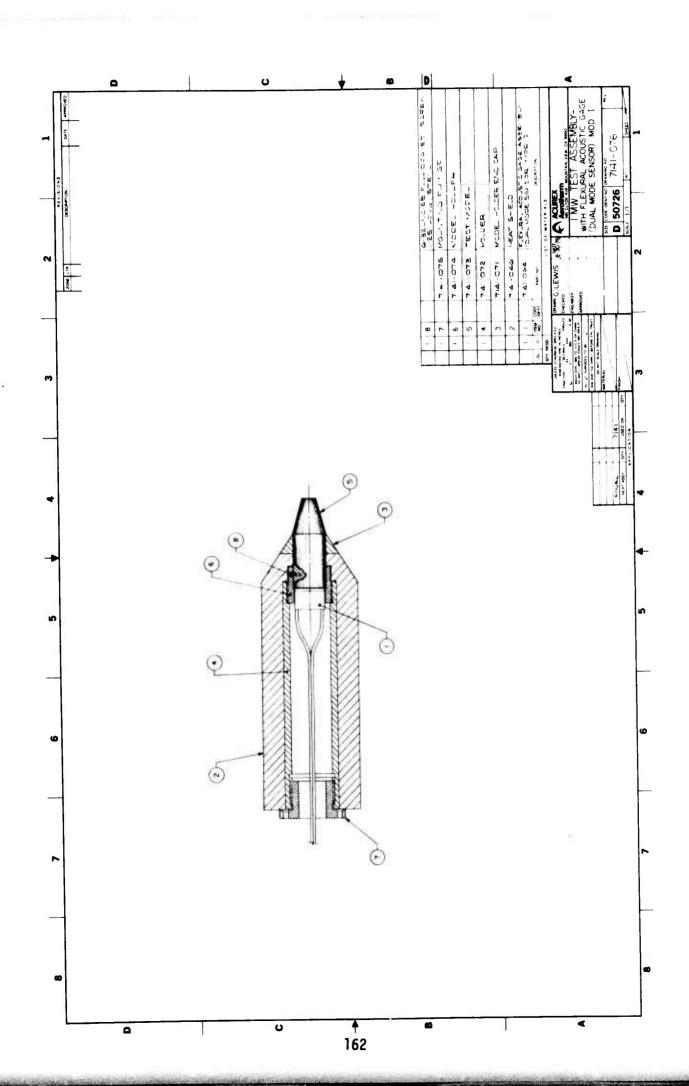


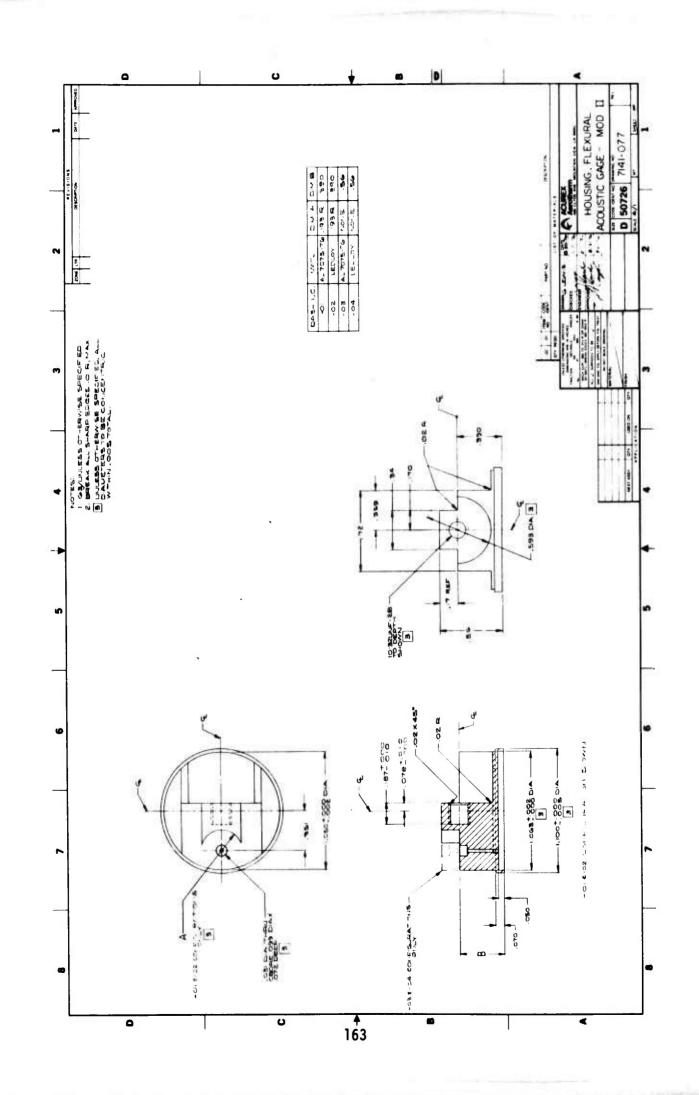


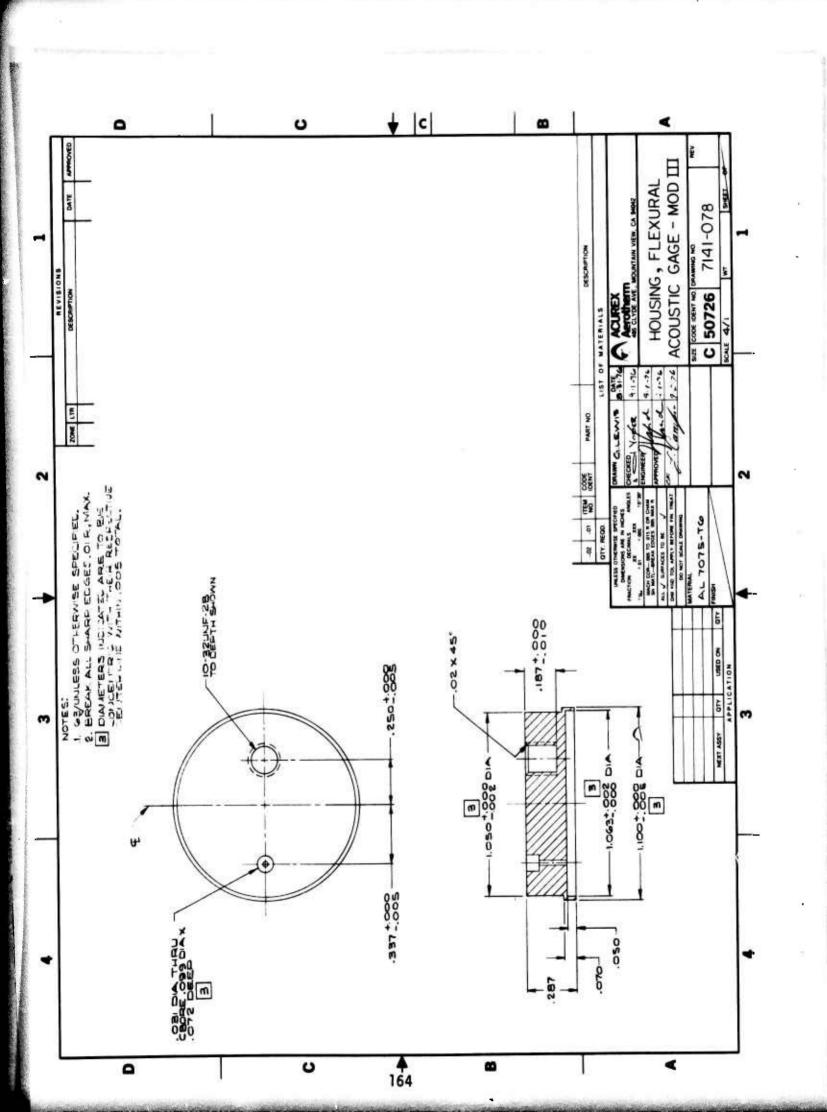


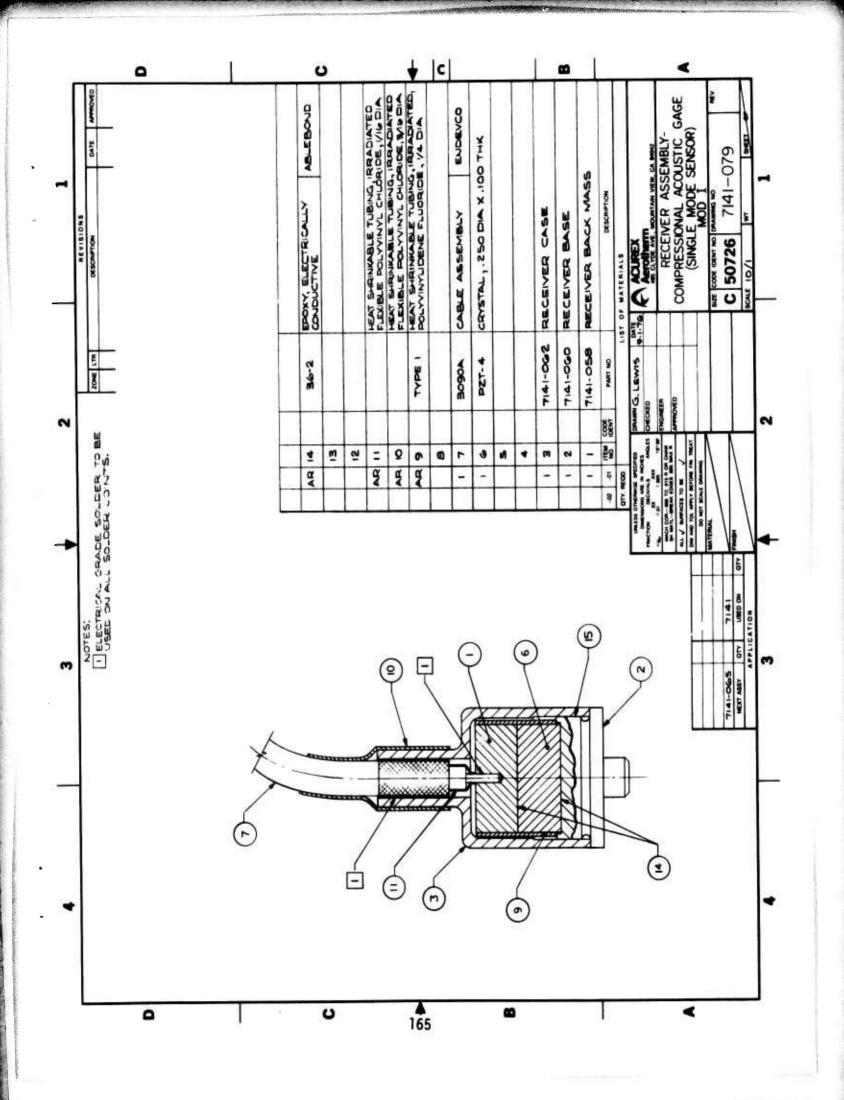


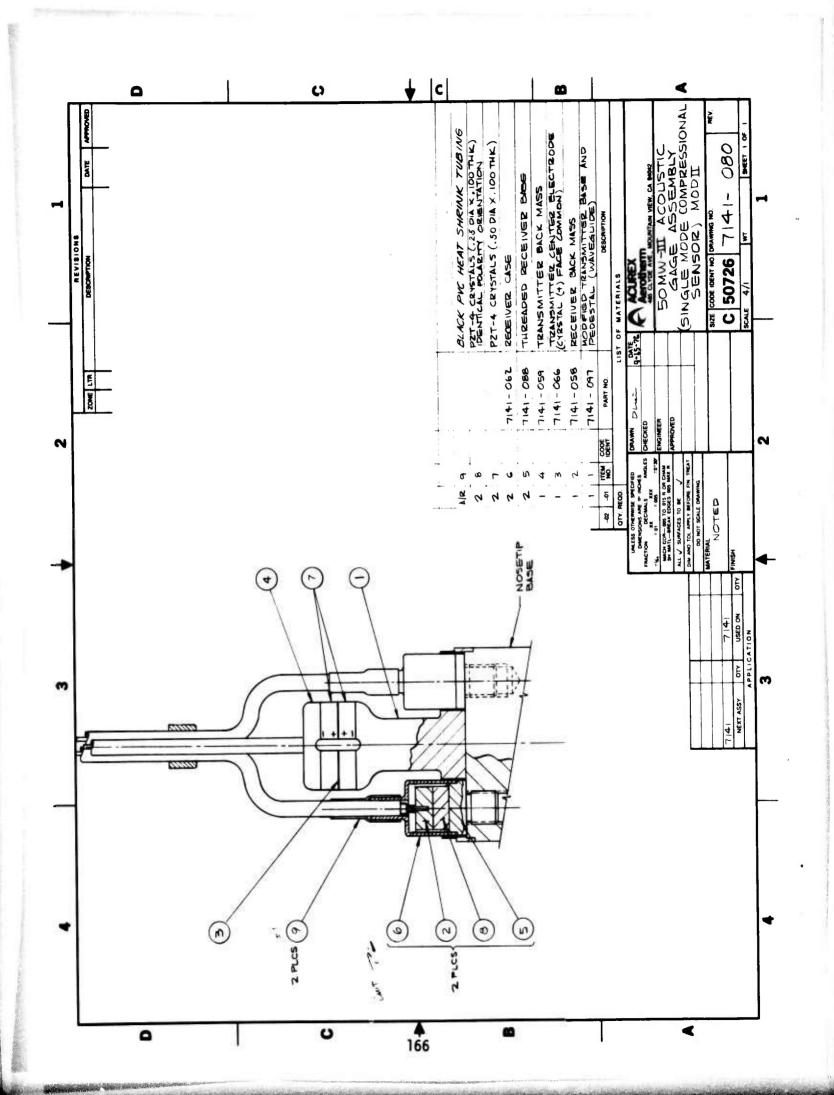


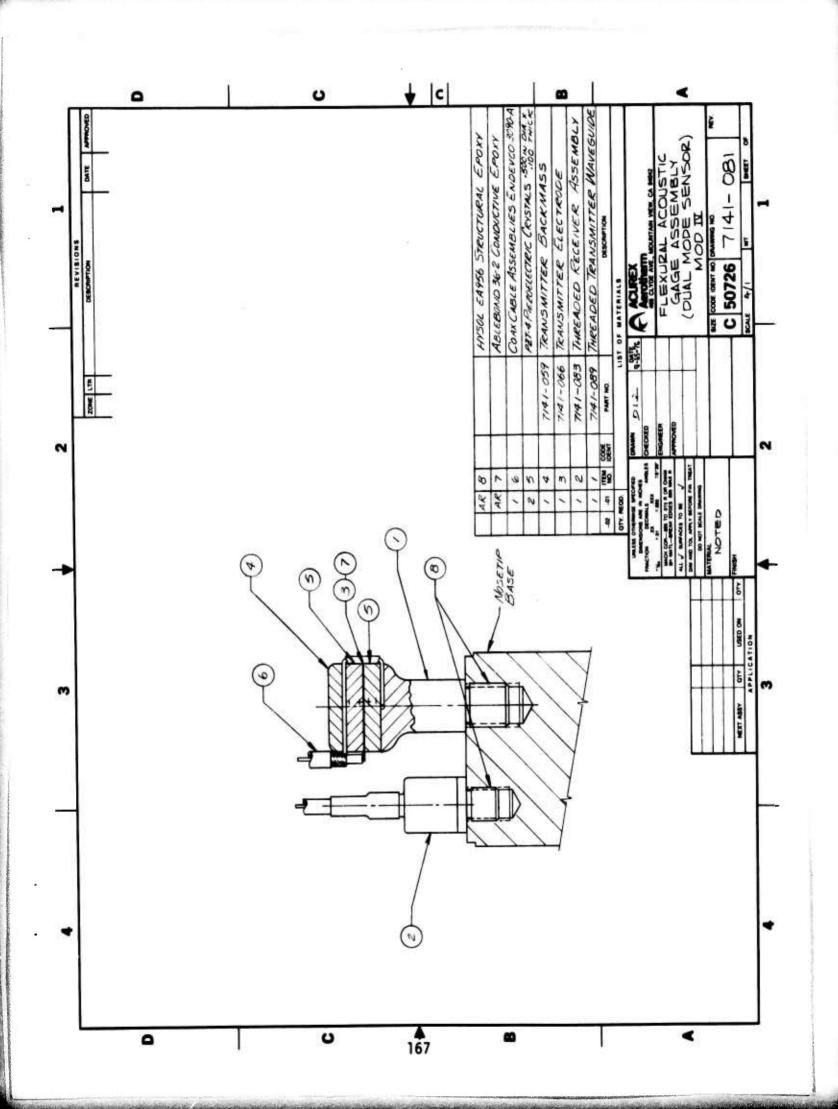


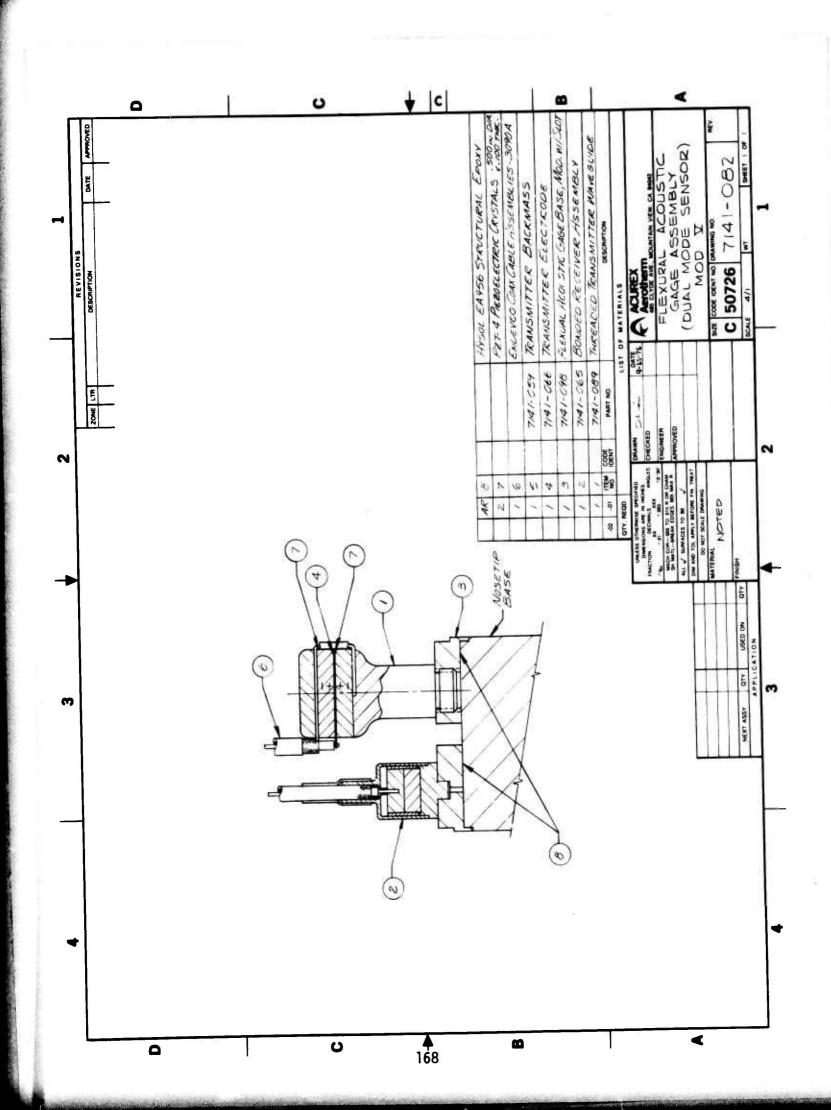


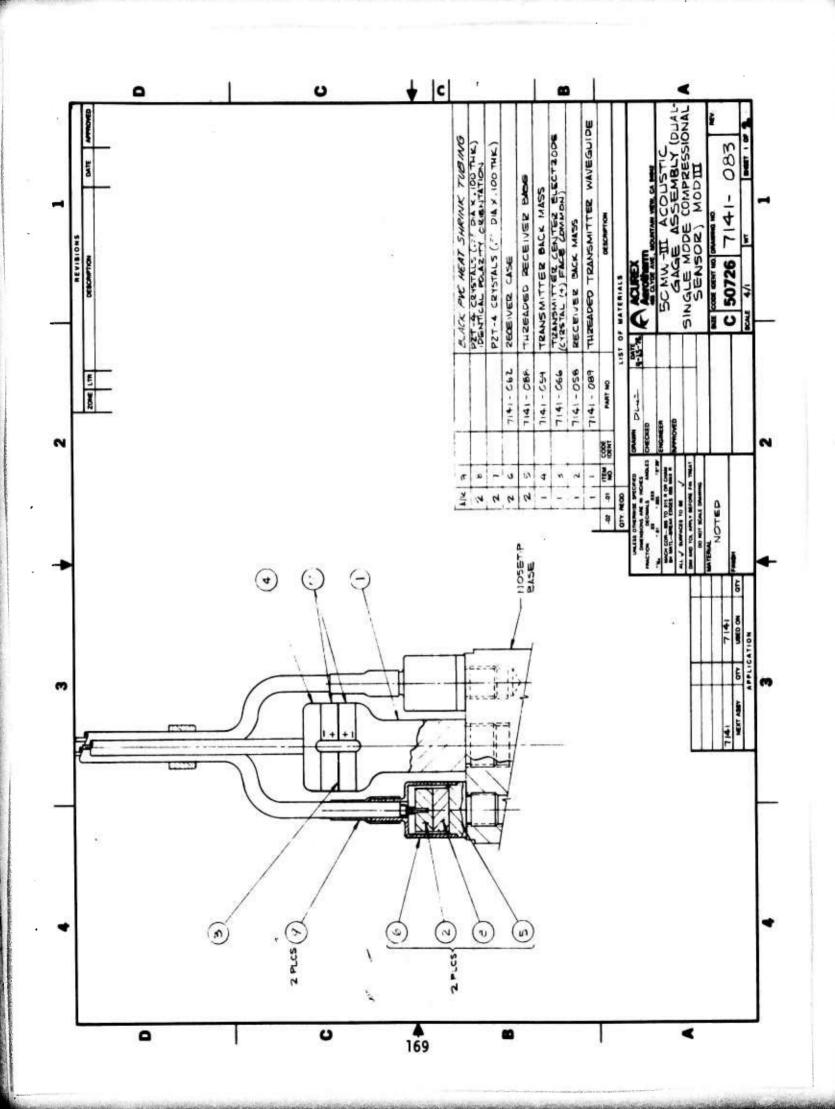


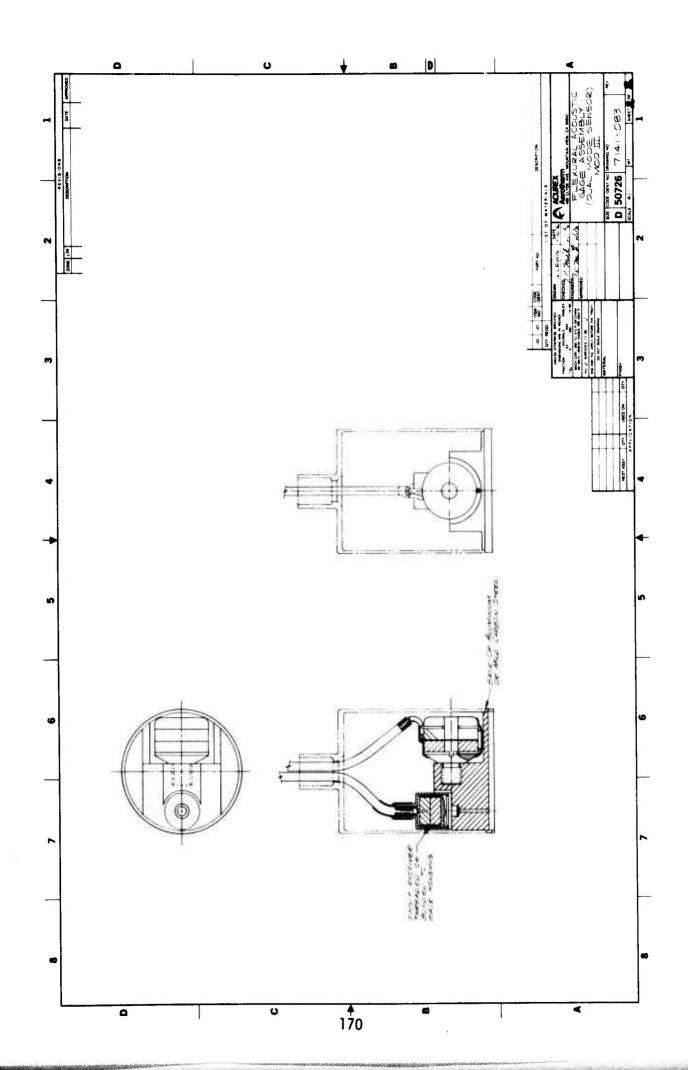


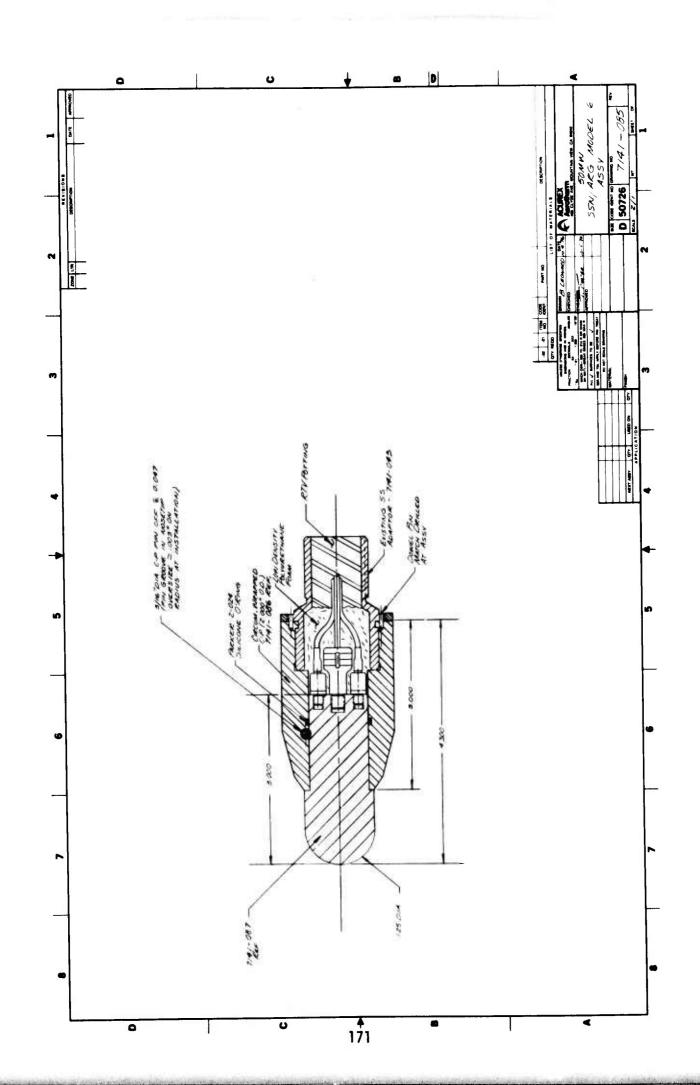


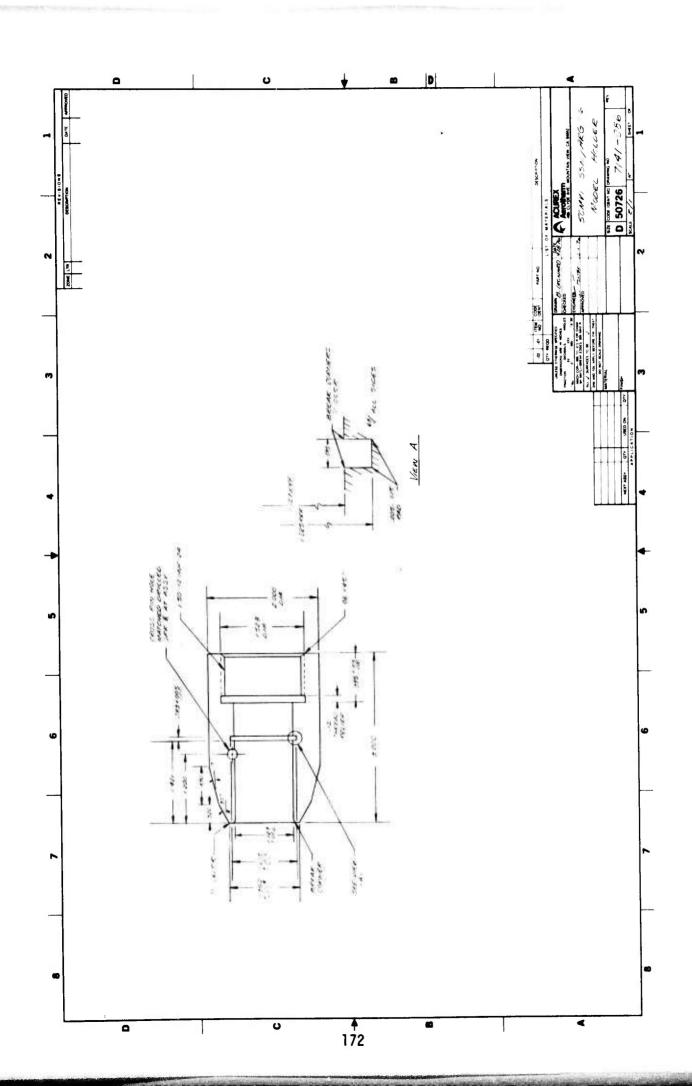


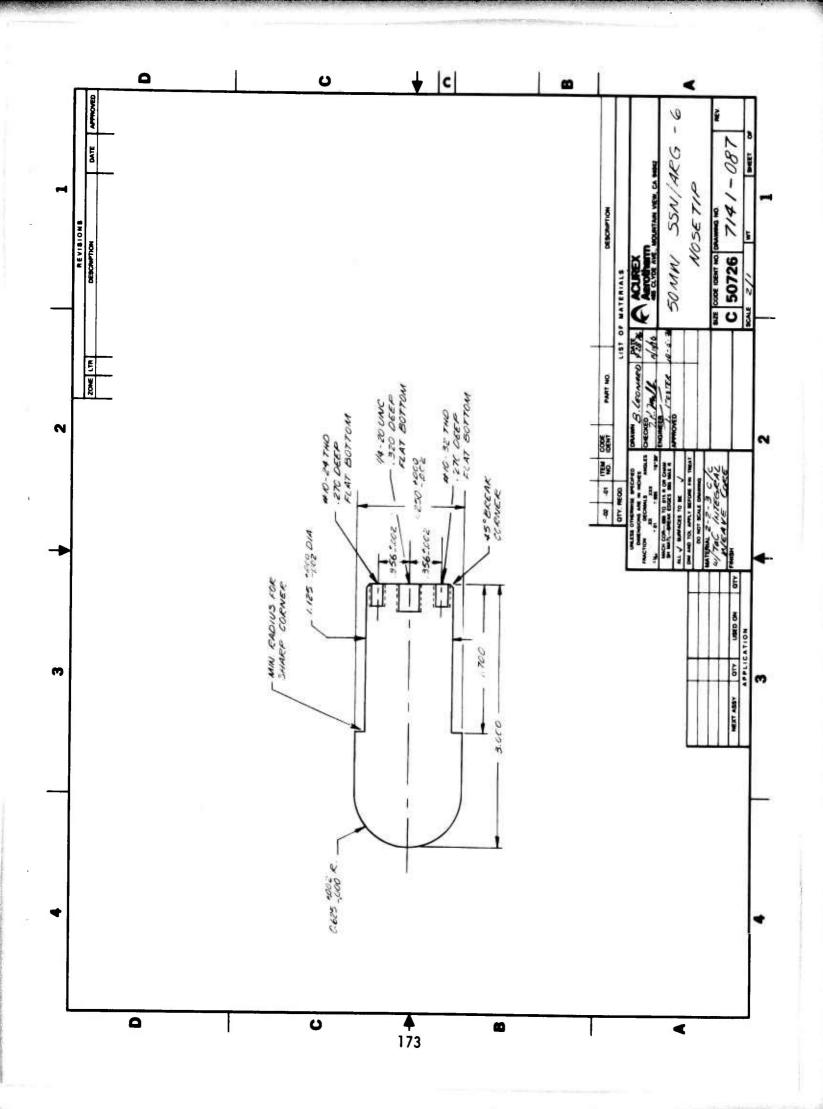


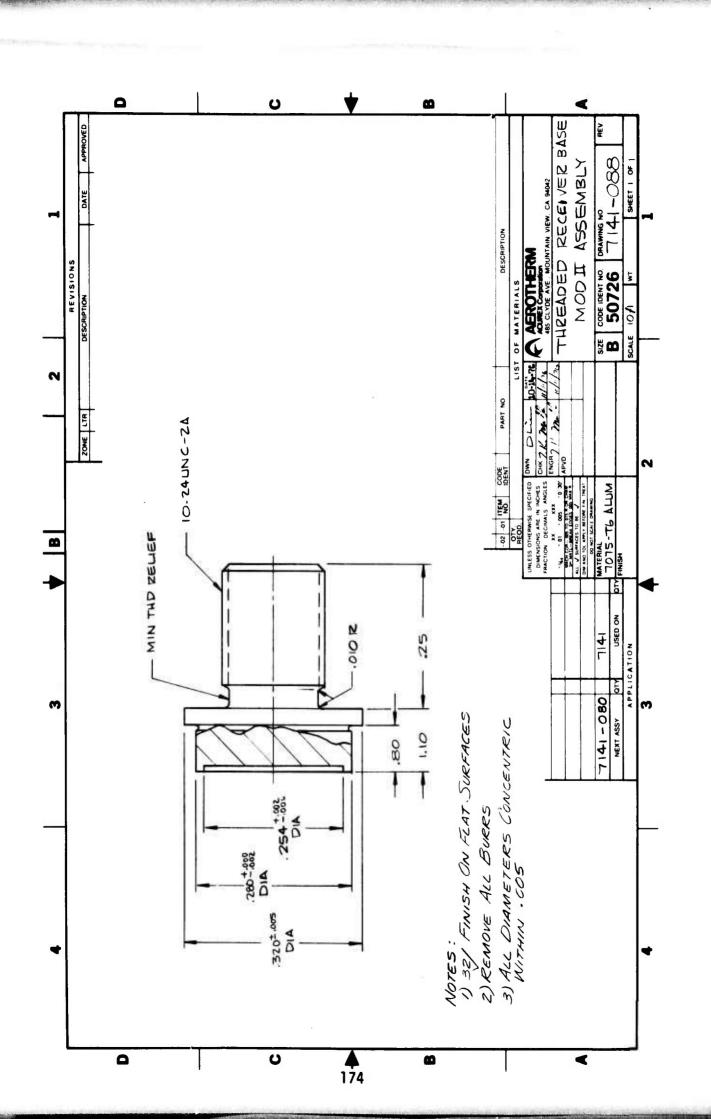


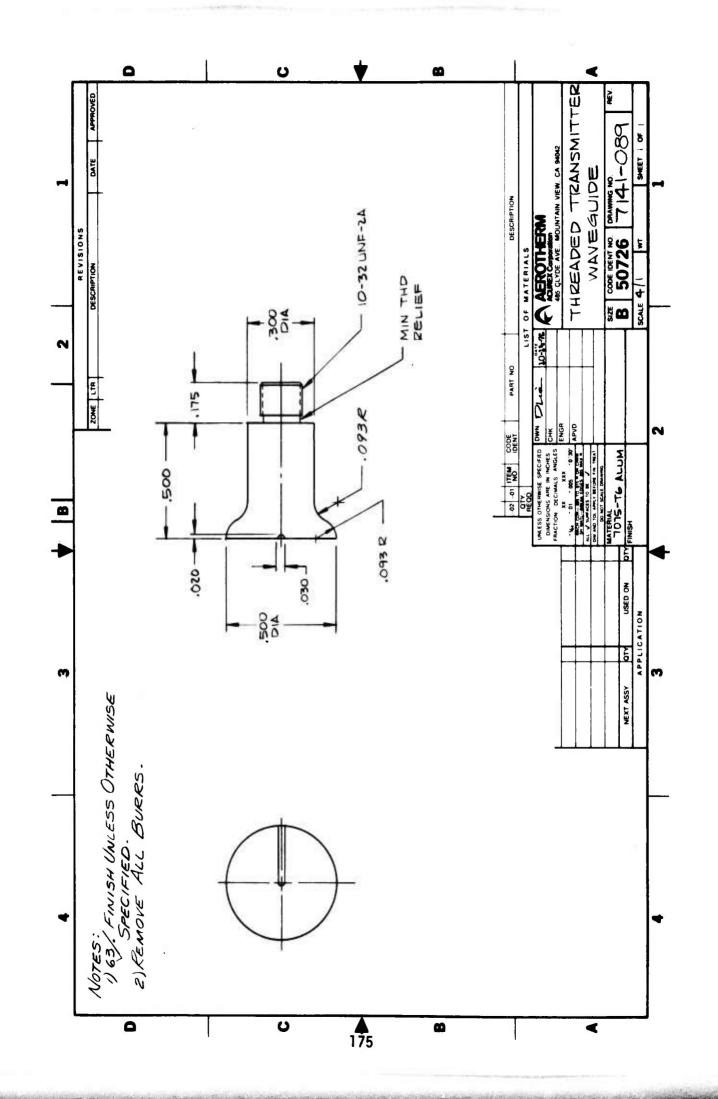


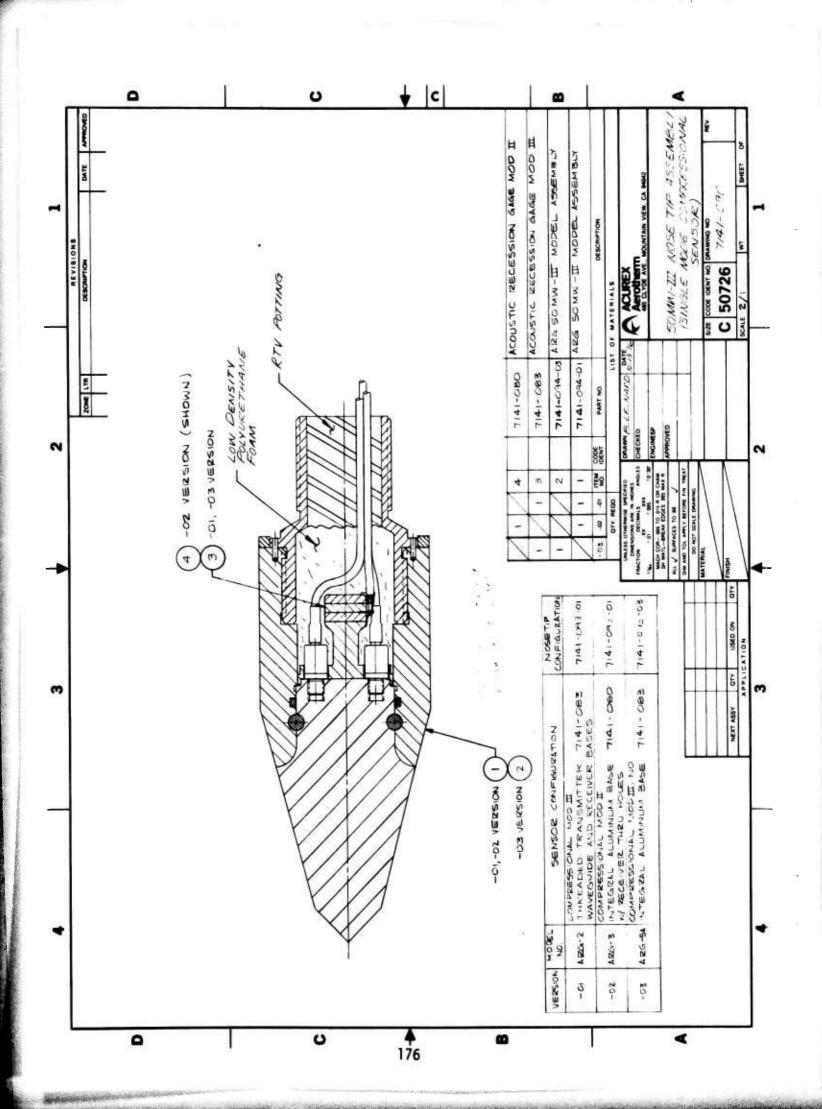


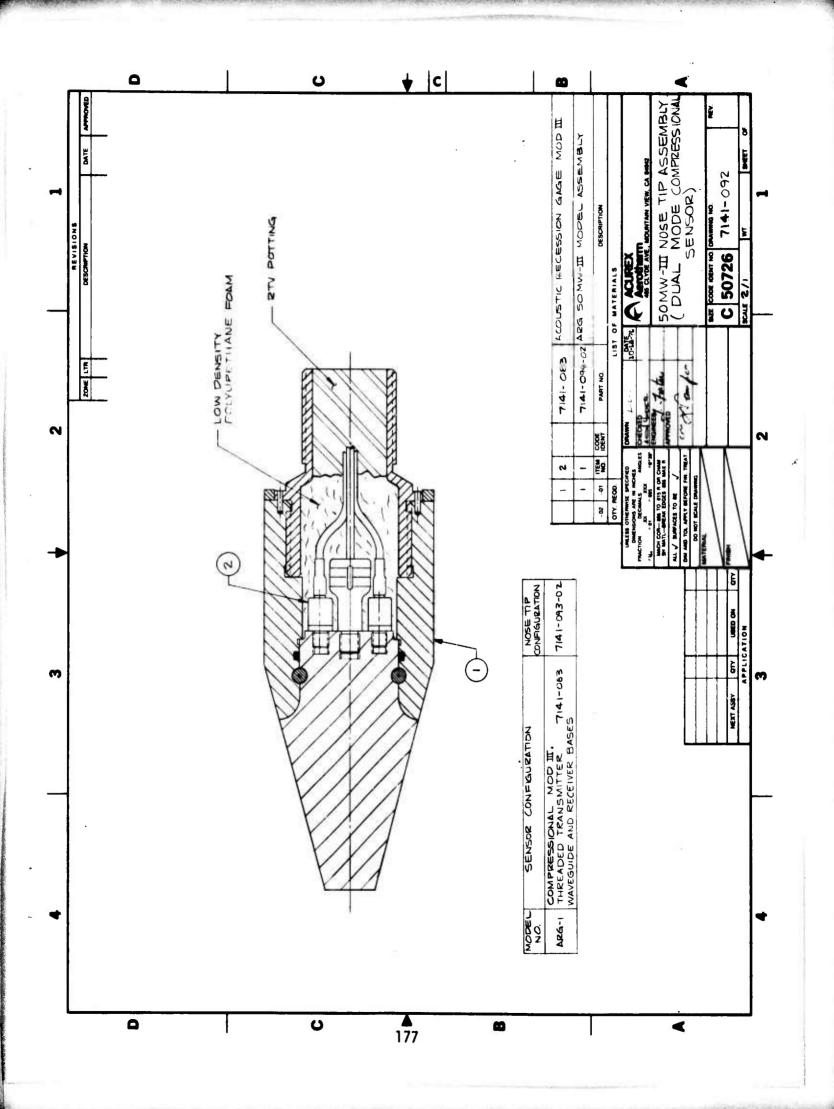


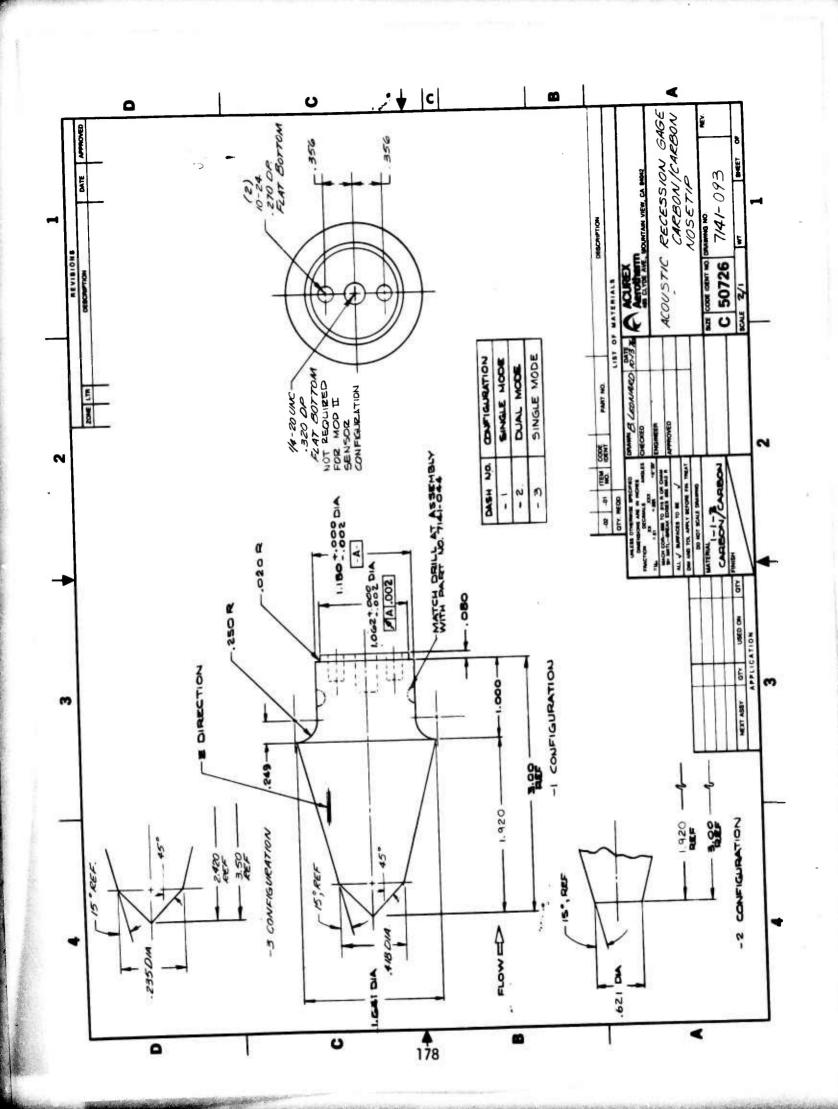


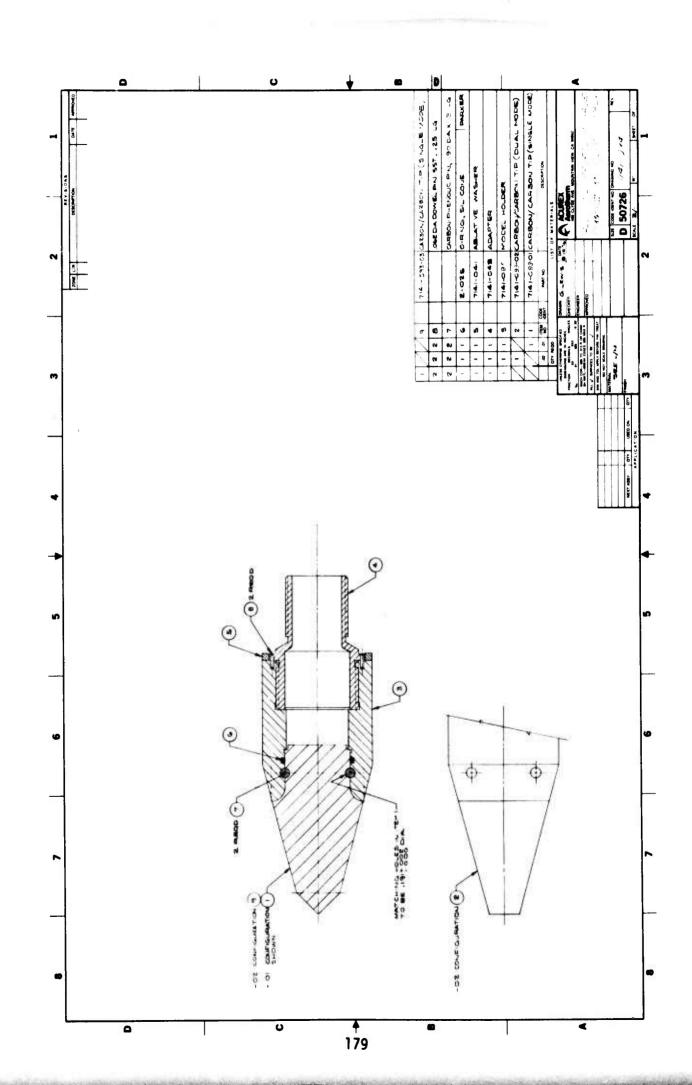


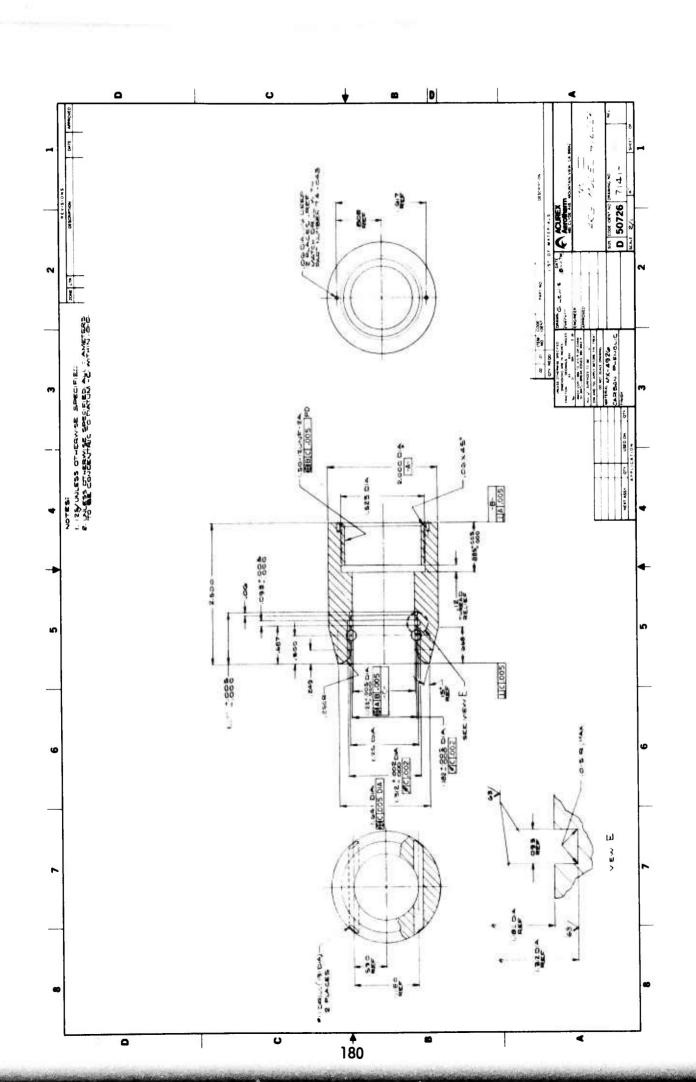


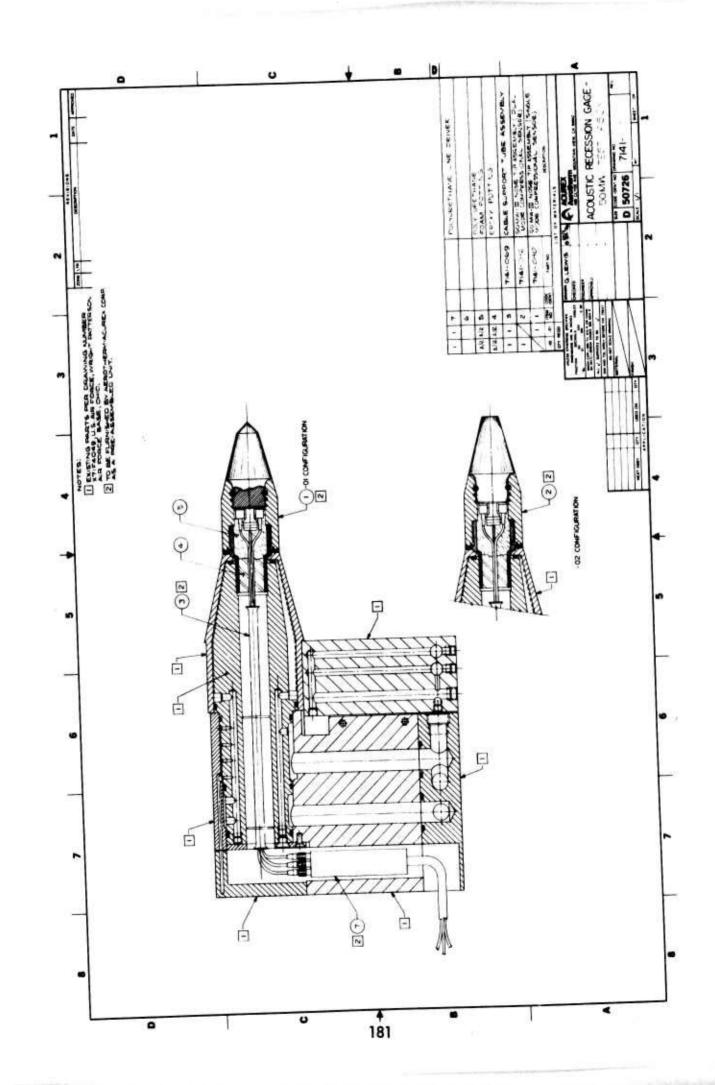


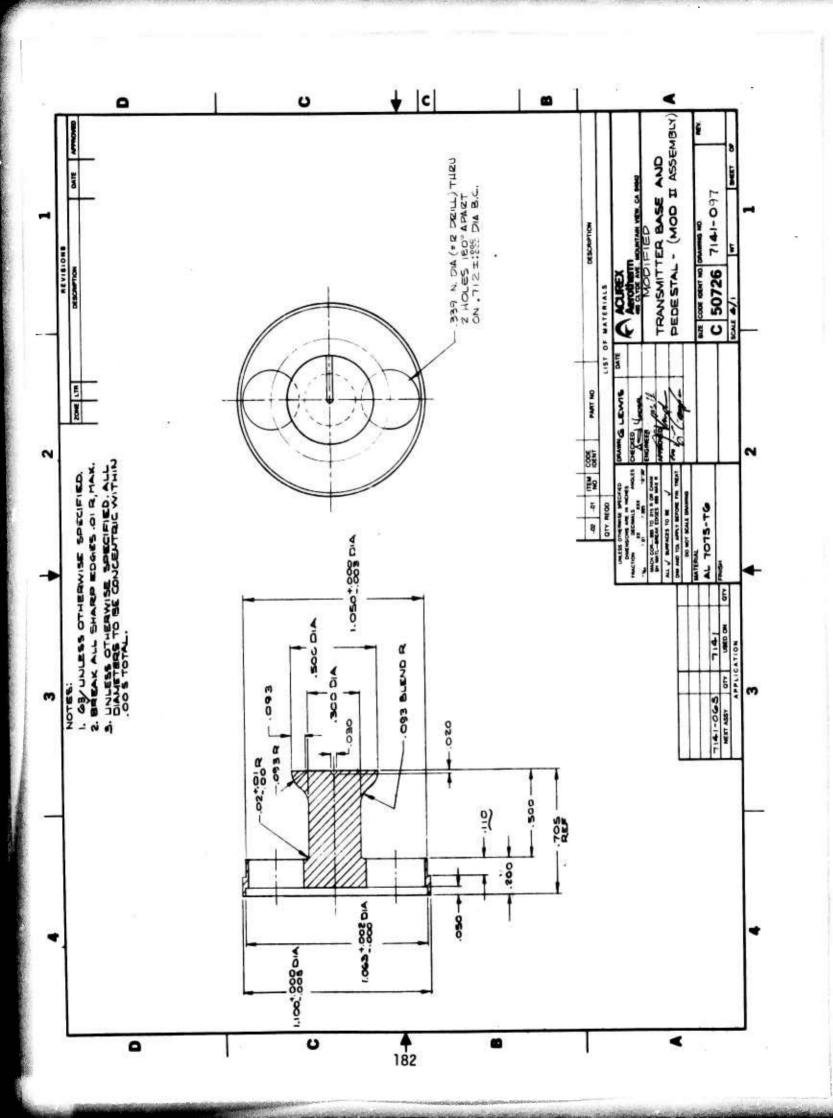


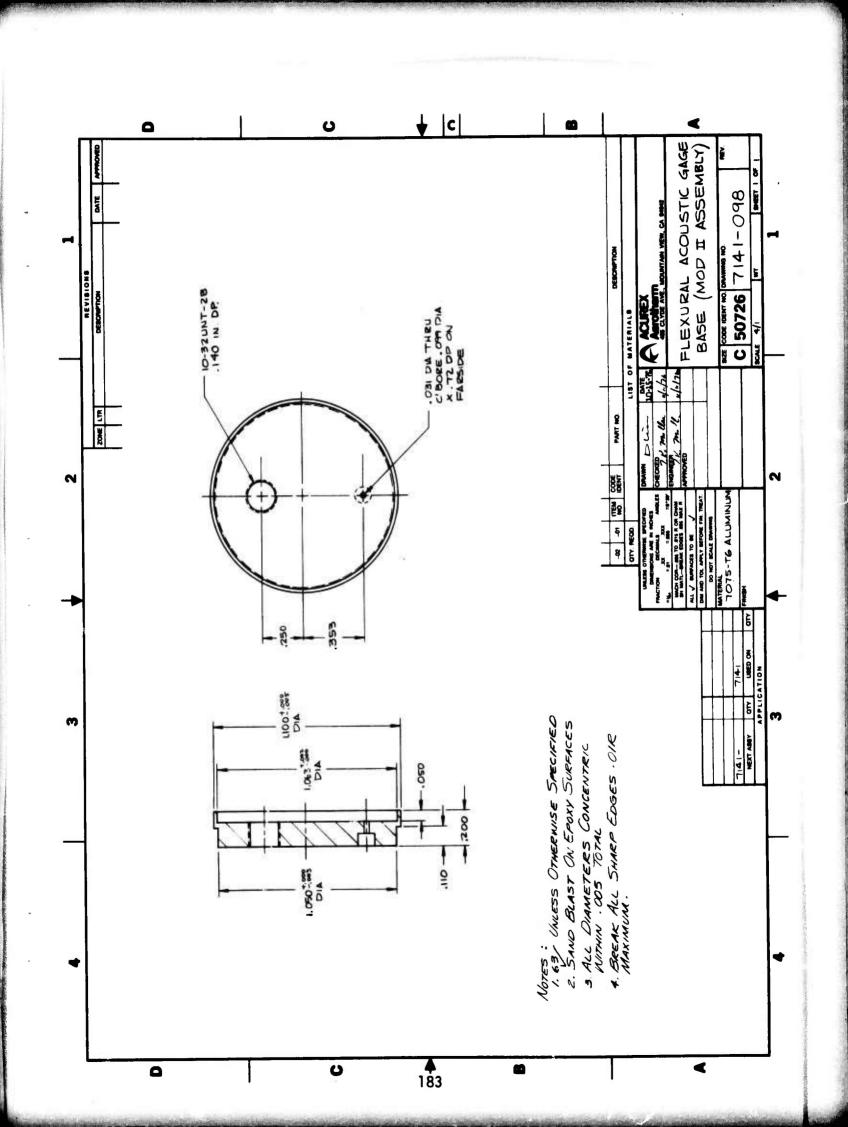


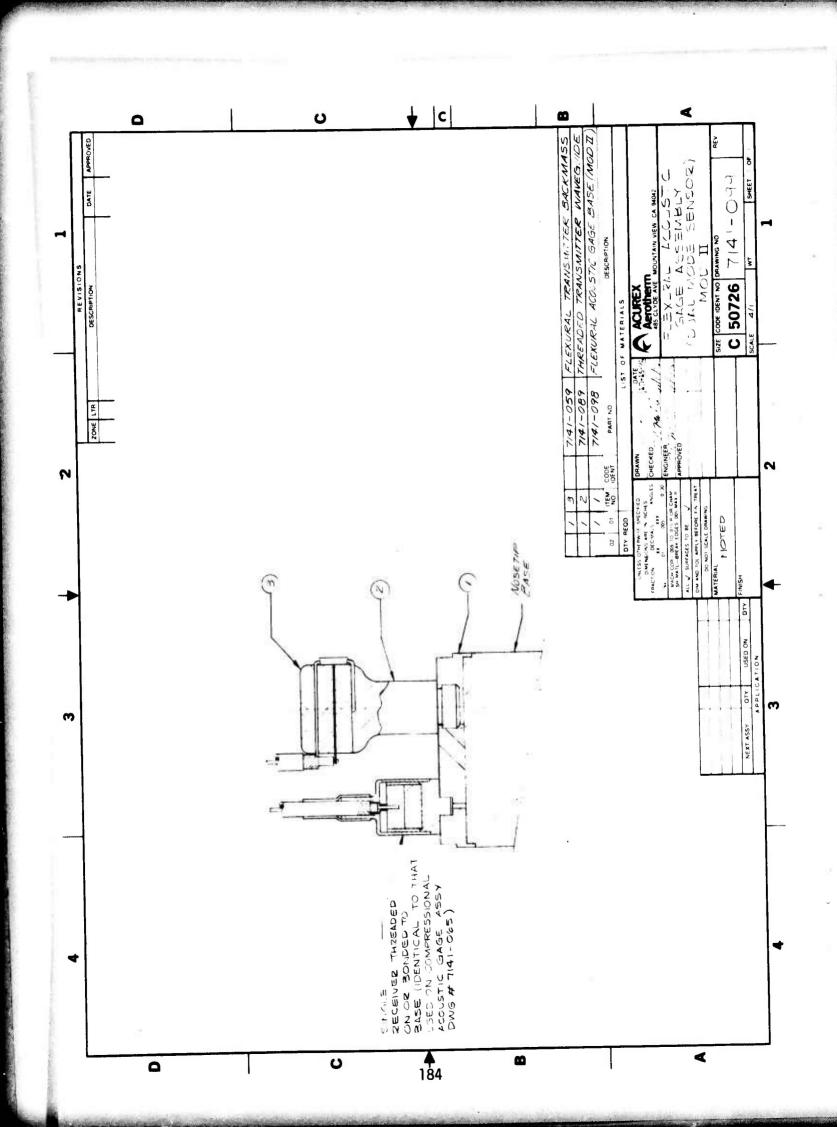








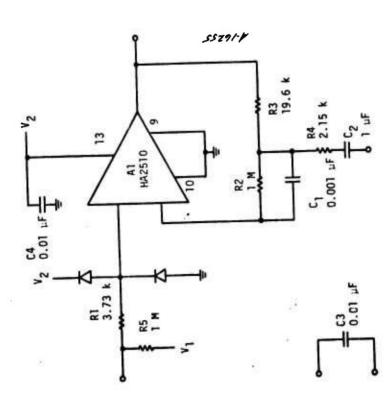




APPENDIX B ELECTRONIC SCHEMATICS AND WIRING DIAGRAMS

TABLE OF CONTENTS FOR APPENDIX B

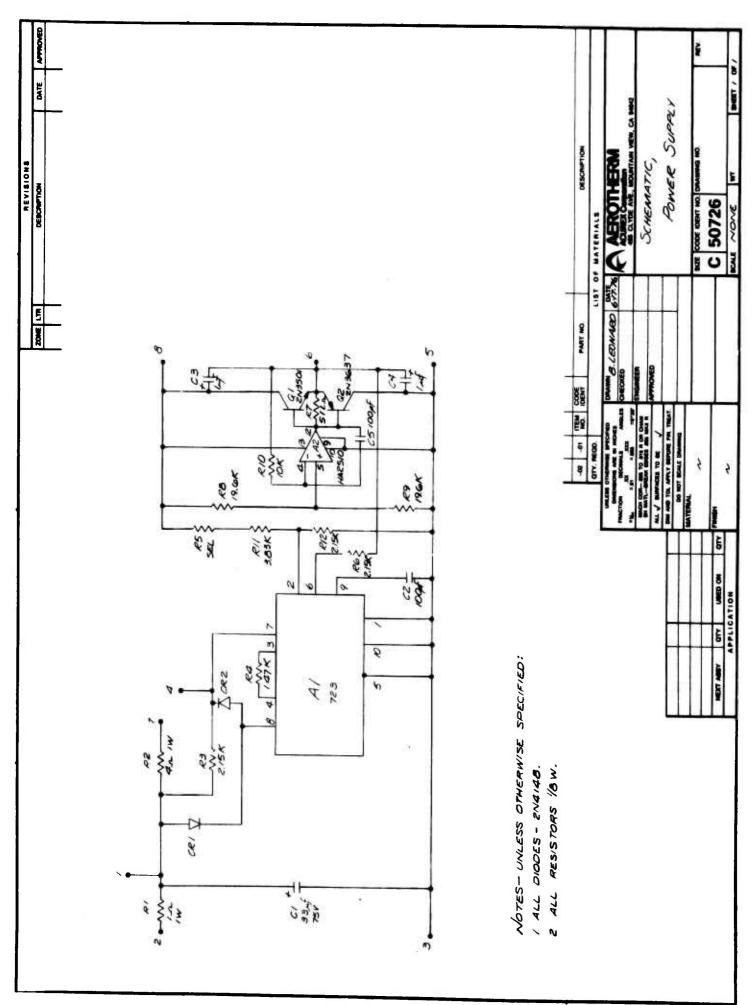
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Input Buffer and Start Circuit
Module #2 — Power Supply
Schematic, Power Supply
Module #3 Power Amplifier
Schematic — Power Amplifier
Module 4 — Phase Comparitor & Lock Detector
Schematic, Phase Comparitor & Lock Detector
Module 5 Integrator & VCO 196
Schematic — Integrator & VCO
Noise Detector
Input Buffer
Input Buffer
Module #2 — Power Supply
Module #2 — Power Supply
Module #3 Power Amplifier
Module #3 Power Amplifier
Module 4 — Phase Comparitor & Lock Detector
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Module #5 — Integrator & VCO
Module #5 — Integrator & VCO



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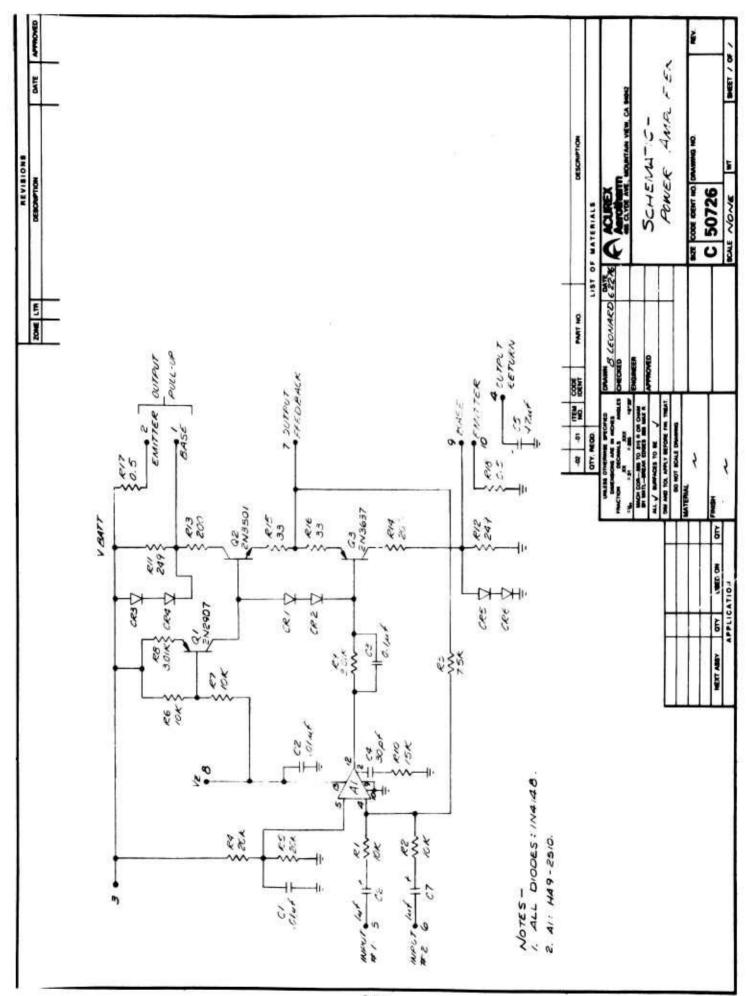
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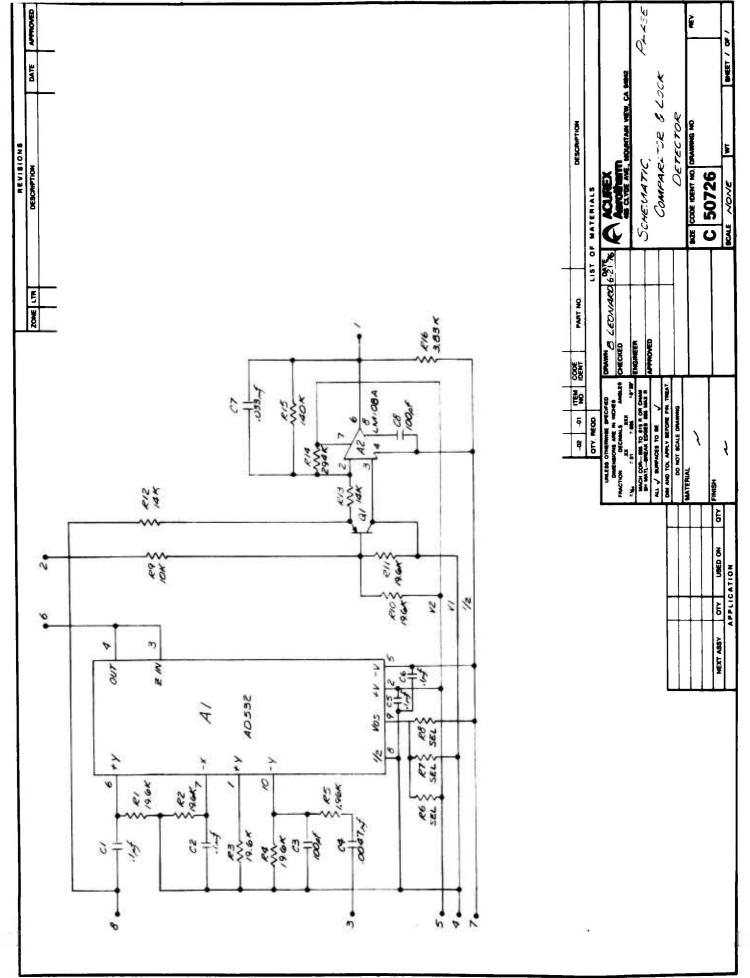
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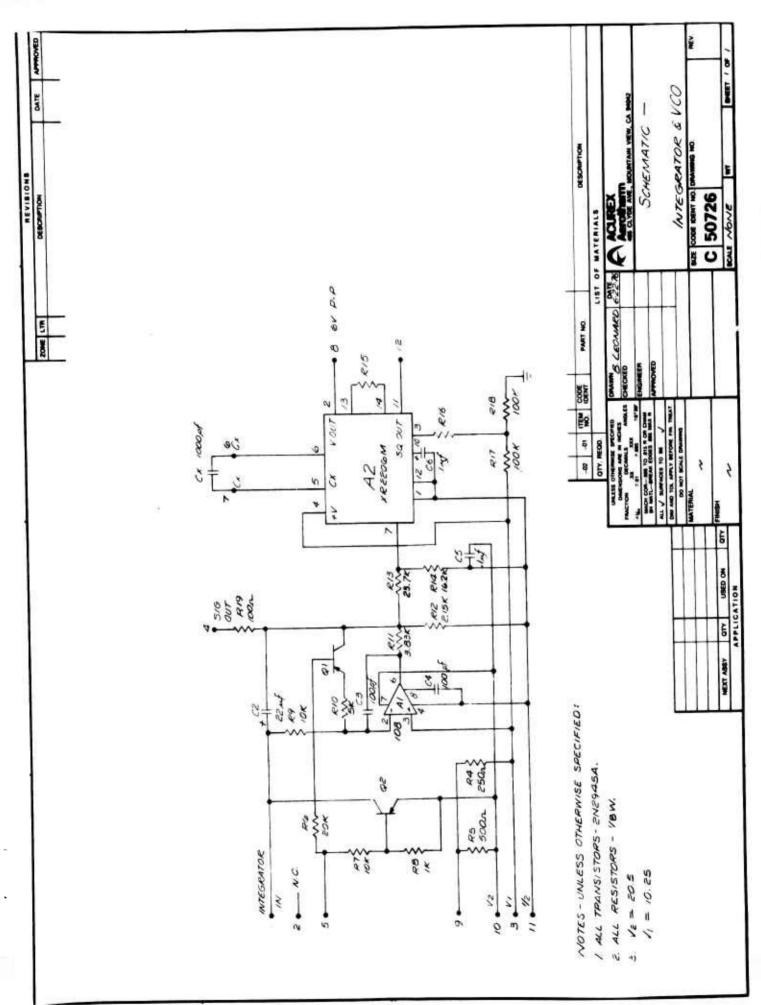
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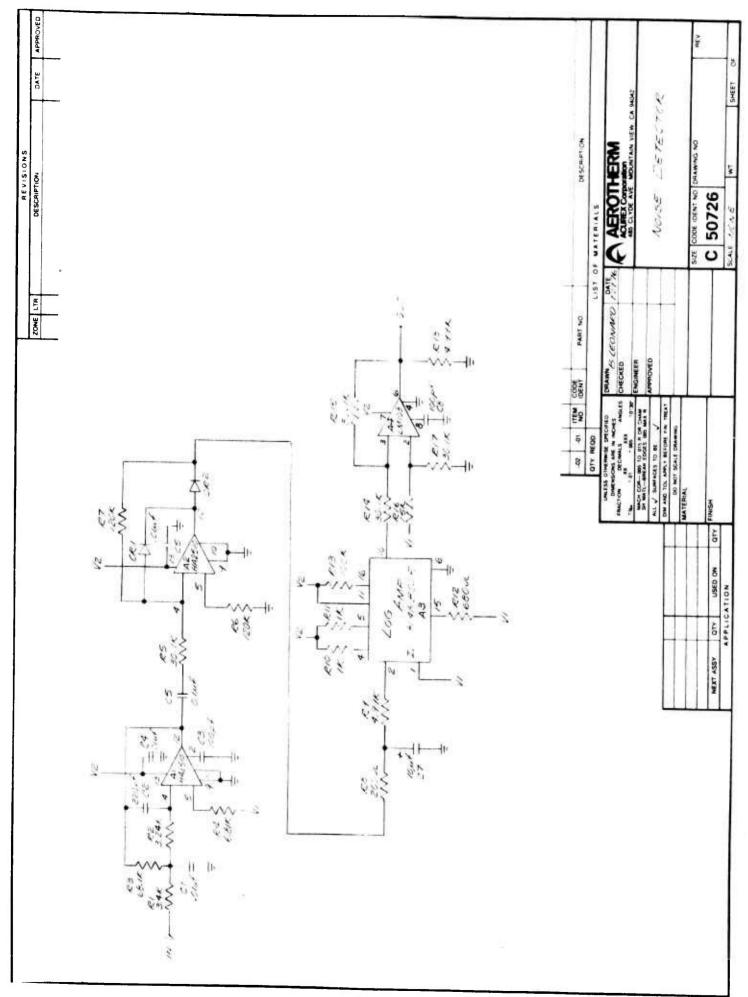
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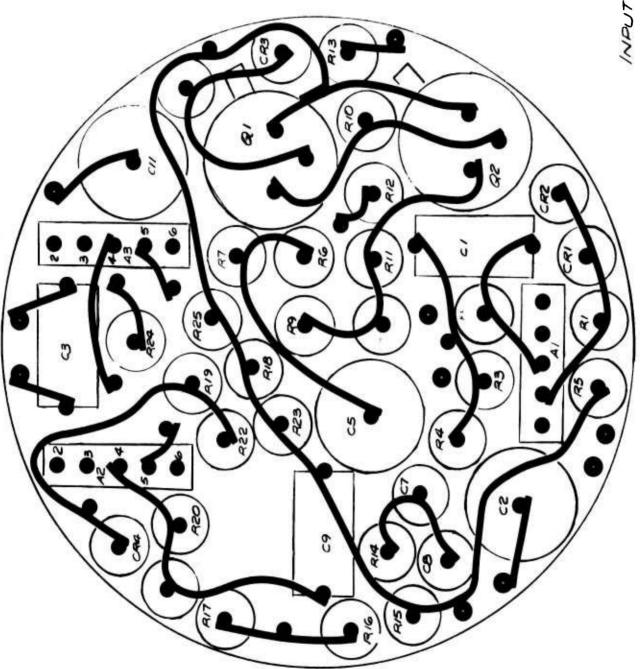


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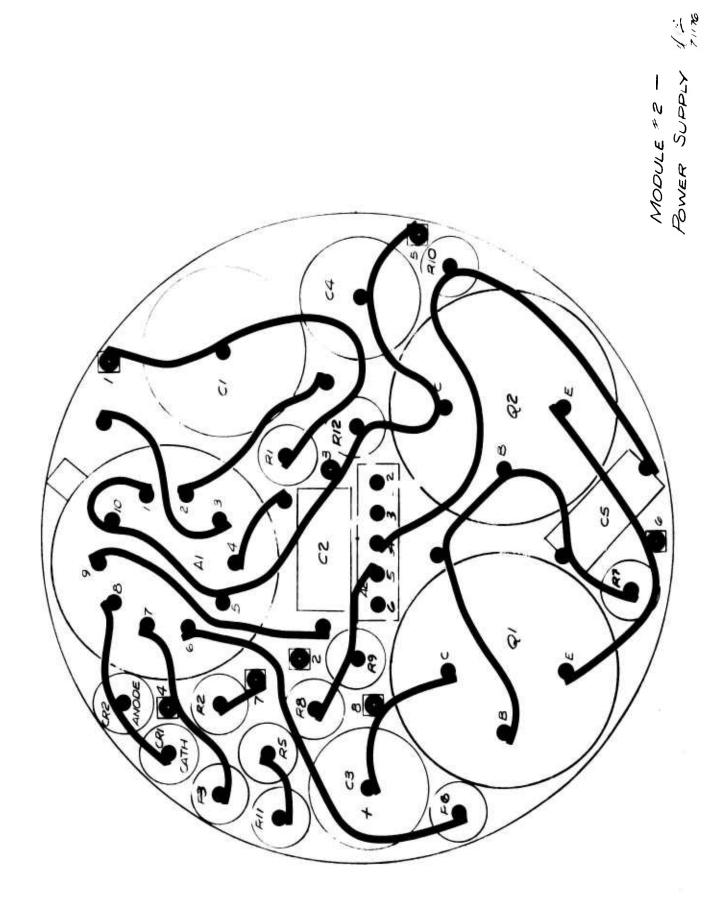
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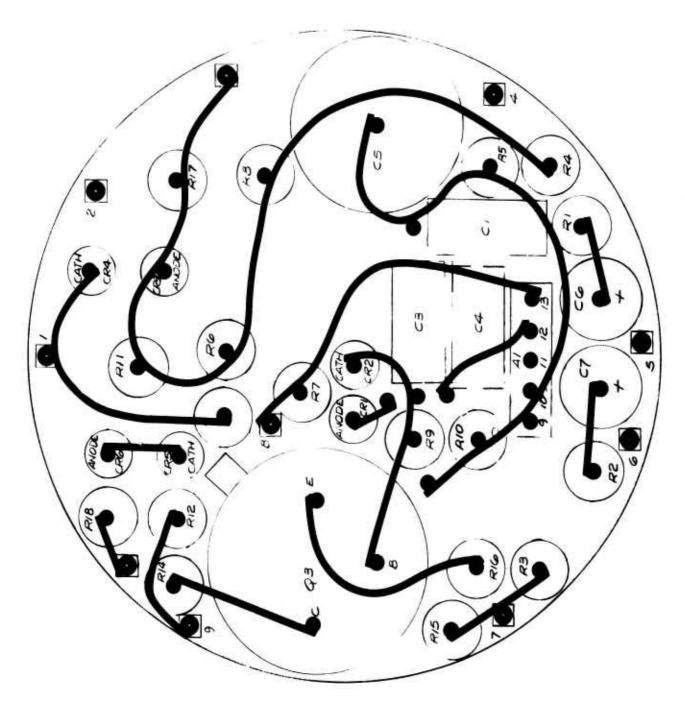






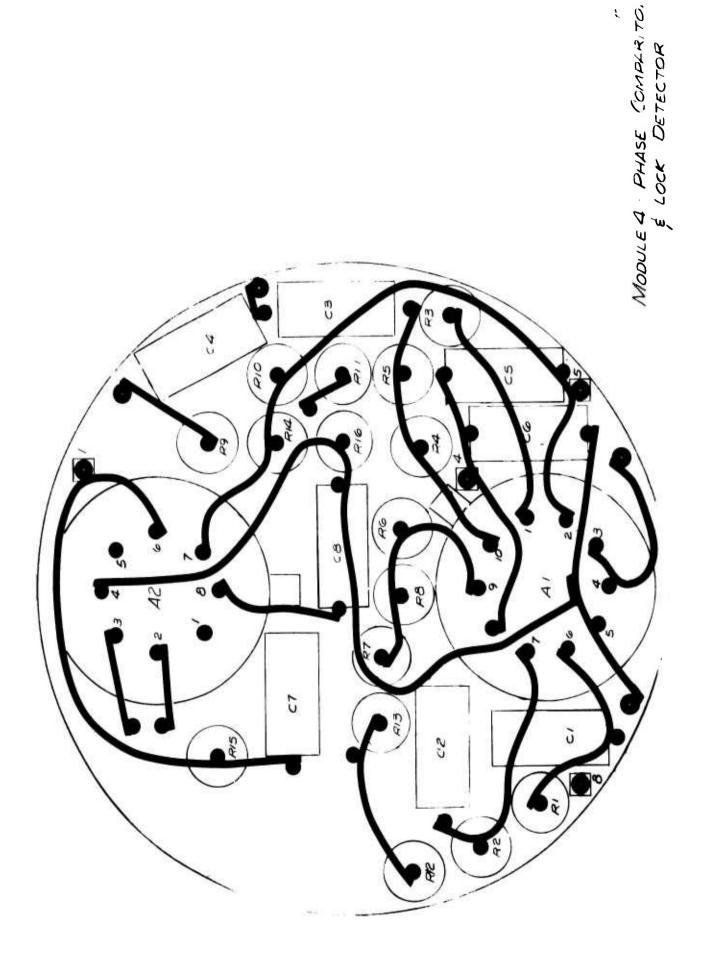


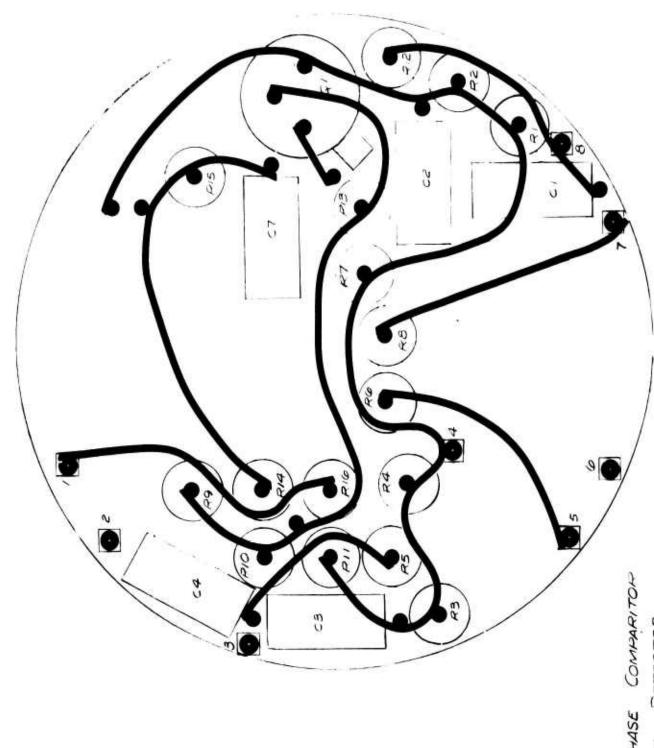
MODULE # 2 POWER SUPPLY (MG #1116



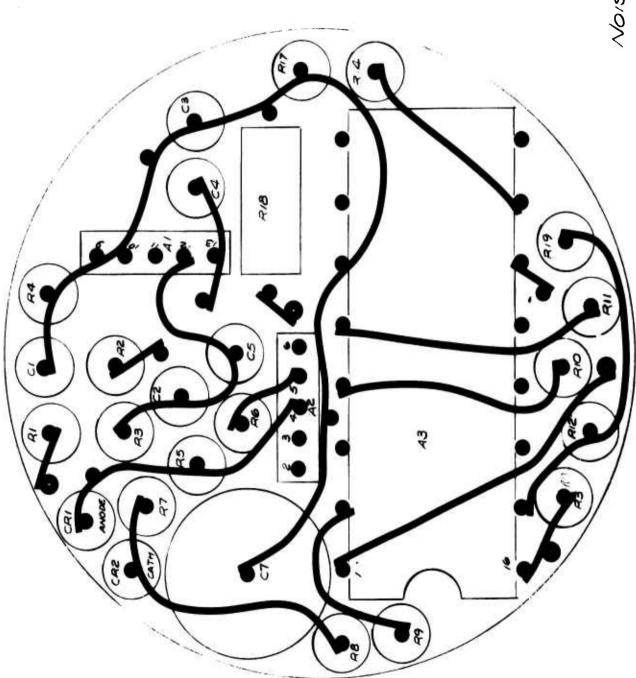
203

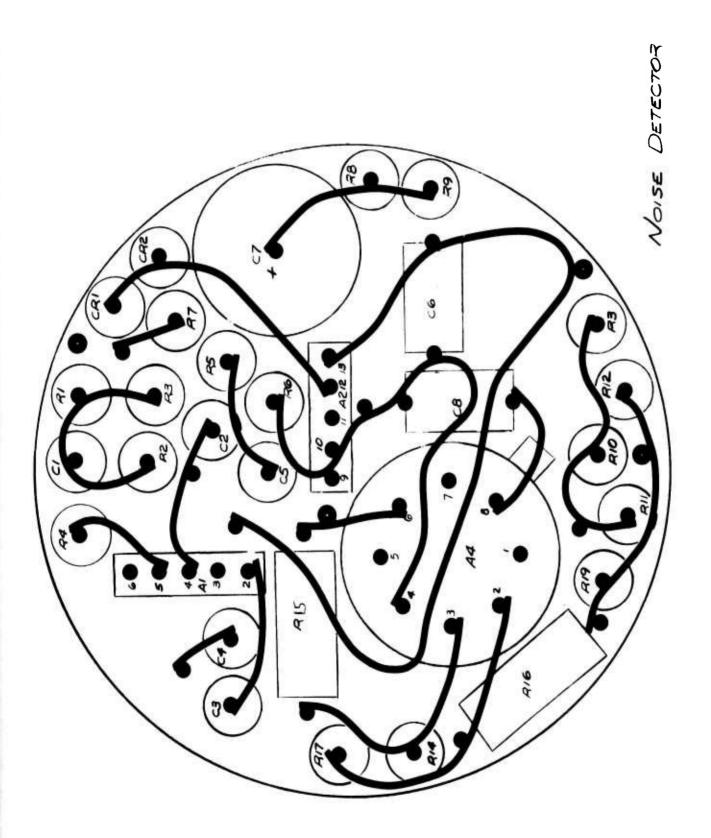
POWER AMPLIFIER

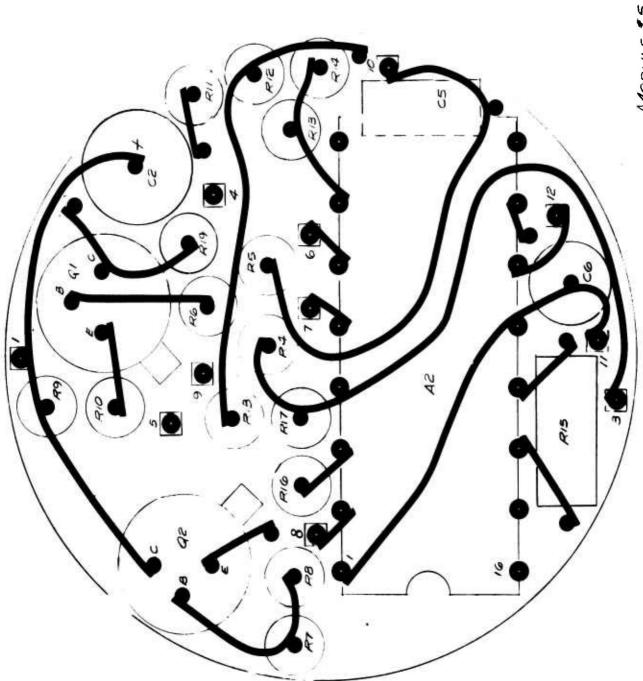




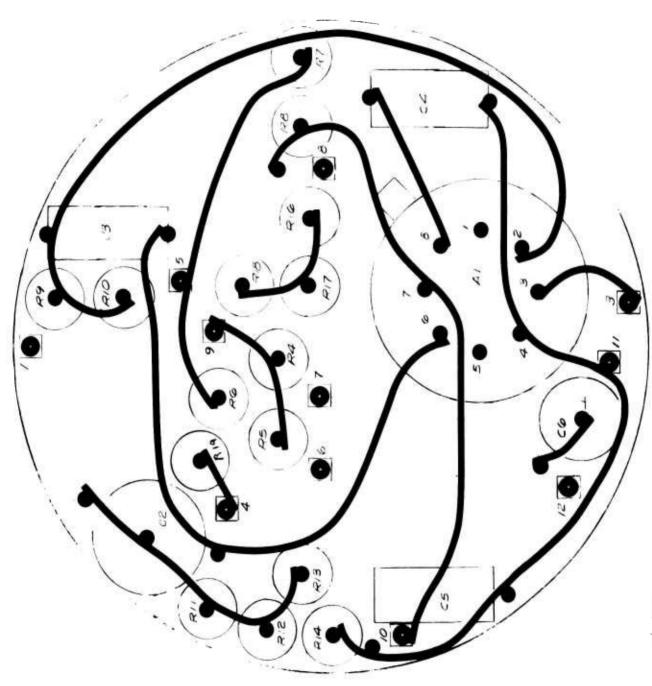
MODULE 4 - PHASE COMPARITOR







MODULE *5 - INTEGRATOR & VCO



MODULE \$5 - INTEGRATOR & VCO

APPENDIX C ELECTRONIC COMPONENTS PARTS LIST

ASSEMBLY RAM PART NO. PART NO. PART NO.

PREPARED BY R. EICHORN
DATE 7-26-76
SCHEMATIC

	Screening Requirements																		
	Maximun Duty Cycle Max Bulk Air Max Bulk Air Temp (°C)																		
	Tolerance Power Rating (watts) Actual Power Rating		52 14W	22 1/BW	22 1/ew	50, 1/4 W	22 1/8 ~	22 1/3~	22 /BW	52 /4 W	23 10 N	20. 1/ew	27 /3W	22 1/2 W	27, 1º W	22 /2 3	22 1/2	₹.	1/6/11
	Resistance (ohms)	3.83K	- R	19.6K	2.15K	/m	196K	7961	294 K	7	7001	19.6K	19.6K	10 K	3.524	14 K	F16K	19.6K	J.
	Manufacturen 1971	DALE EMF 55-22		BLE	11	4.8.	OALE	11	"	A. B.	DALE		11	u,	lı	11	Ц		ħ
	Wilitary Specification	78	MIL-R-39008	MIL-R-55187	И	A16-6-3900	M14-8-55182	11	1.	M16-6-39003	MIL-R-55162	11	1,	±	11	11	IJ		11
2 20	*sus ess																		
PAGE 1	Part Number Bna Construction	NRSSK/	/ CALBO	RNRSSK	RNRSSK	R CROJC	RNOSSK	RNRSSK	RNRSSK	RCROTC	RNR55K	RNRSS F	RNESSK	RNRSSK					•
	Circuit Symbol Number	RI	1.	R3 (84	├	213	27	₩-	 	810	R11	212	R13	RIT	Ris	200	RIJ	0/2

PROGRAM RECORDING

PREPARED BY E JEIN

201111														
Screening Requirements														
Temp (°C) Max. Bulk Air Duty Cycle				+	+	2	+	+						
Actual power (watts)		28		•	20	100	000		-					
eniter Rating (strew)	1,8%	M3.	3, 4	1.5	1	1.0	3							
Tolerance	%;	% 2	r.1	22.22		7.7	5.75		-	-	-			
Resistance (ohms)			101	0.7.0		7 . 1	337			-	+			
Manufacturer	17.87								1		1	L	_	
Specification Specification Manufacturer	1.8													
Status* Military Specification	ML-R 55/82 UM						-,							
Military Specification	ML-R 35/82 (ML)													

*See Figure 8 for code.

EICHORD

Ď.

Screening Requirements 6-21-76 Max. Bulk Temp (°C) Maximum Buty Cycle PREPARED BY SCHEMATIC 100 3 Actual power DATE 160 mW 304 7.25 . 6 . 6.0% 37.7 0 40 POWer Rating (strew) 2 3 3 2/ 8 18 To lerance 2% 27. 27. 3.83K 19.6K 19.6K Resistance (ohms) 2.15K SELUTE 2.15K 2.15 K 680 10 K 4 ENF SS- 22 Manufacturer DALE 25 PART MIL-R- 55/22 Mr. 17.55.72 MIL. K-51/10 MIL. P. Sint Military Specification A-55180 71. A. 53 SUPPLY Status* RAM SUB ASSY POWER Construction Part Number And PROGRA!! RNASSK SSK BNR SS M ANK JAGUNN TOGINVE 610 5 23 R4 47 3 RS Circuit a 0 0 a

215

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ASSEMBLY RACO PART NO. PART NO. PART NO.

PREPARED BY R. E. CHOR. SOLEMATIC

101111 4													 -				γ		
Screening Requirements			•																
Maximum Maximum Duty Cycle Max. Bulk Air Temp (2)	100%	100	160	000	700	700	00/	/00/	100	/00/	100	007	(C)	00/	CO)	uc.	(39	C;;	
Tolerance Power Rating (watts) Actual Power (watts)	20% V8 W																8 - B	2 1 0	
Resistance (onns)	10K 2	10<	6.911	19.6K	19.6K	/0 K	-0 K	3.22<	3.32K	14×	2 00	200	200	500	33.2	33.2	7.5	2.5	
Manufacturer	85																DALG A6:-	MI DALL AGS-	
Status* Military Specification	MIL-R- 55/82																M.L-R- 3907	m16-8-5900	
Part Number and Construction	ENR STH/P														-		RWP-81 / PS. Maria	RWE-81/wine some	0 60 m Code
Symbol Number	R1	22	23	24	RS	R6	27	28	R9	R10	Ril	212	R13	R14	Ris	216	RIJ	R18	3

216

RESISIORS PROGRAM RESONANT ACOUSTIC GAGE

ASSEMBLY RAM SUB ASSY OSCICE ATOR

PART NO. __

PREPARED BY R. EICH OR DATE 6-

IOIHI-A	1		1			,	}	,						,		 ·	
Screening Requirements																	
Maximum Duty Cycle Max. Bulk Air Temp (°C)																	
Actual power (watts)																	
Folerance Rating (watted)																	
Acesistance (conno)	19,6K	101	2.15 K	6802	200Z	10 K	4.99.K	3.83K	23,7K	16.2 K	2002	725	735	10K	100K		
Aenufac turem																	
Military Specification																	
Status*																	
Part Number and Construction	NCSSK			RWR BIW6810FP					RNCSSJ	RNCSSJ							
Circuit Symbol Number	12	22	R3	124	25	200	62	28	Ra	RIO	RII	212	RI3	P14			

PART NO. __ SUB ASSY PHASE PROGRAM

PREPARED BY R.E. C. 102. J. DATE 6-21-70
SCHEMATIC

Screening Requirements																	
Maximum Duty Cycle Max. Bulk Al Temp (°C)	100%	100	/00/	790	**	00/	00/	90/	700	90/	00/	90/	/00	100	/00	(13)	
Actual power	S. m.N	Sa'	;	1.4	61.1				12 0	75.	•	7.07	727.	1.52	1.64	i.	
Power Rating (Watts)	-	-	7	7	+	-		-								-	
Tolerance	73.	4	+		+		-				+					-	
Aparistance (smile)	19.CK	-		7	2.15K	SELECT		~	10 K	19.6K	7	16.0K	14.0*	20th	140K	3,834	
Manufacturer																	
Military Specification	M11-R-55182	-														7	
Status*																	
oart Number and noitourtion	RNRSSK / MOLOGO	1														_	
Circuit Vinbol Number	RI EN	+-	R3	64	SS	66	67	68	89	9	2 2	0,7	50	613	Sid	RIB	

218

*See Figure 8 for code.

RESISTORS

Acoust 6And

R EICHOLD

PREPARED BY

Screening Requirements 7-28-16 Maximum Duty Cycle Max. Bulk Air Temp (°C) SCHEMATIC Actual Power (watts) POWER Rating (Strew) W8, Tolerance Resistance (ohms) 6.21K 30.1K 202 SELUT 4.99K SELCLT 190K 1.X/K 140K 30.1K 190K 100K **1** 089 EMF SS-23 Manufacturer PART NO. BE MIL-R-55102 Specification Specification DE TECTOR 1 Status* RESONANT ASSEMBLY RAM SUB ASSY NO!SE Part Number and Construction PROGRAM RNRSSK Circuit Symbol Number RIS 212 RI 23 24 RS 127 28 8 219 219 RZ N

IUINI-V

*See Figure 8 for code.

RIJ

619

4.99 K

30.1K

30. IK

RIF

RIS

RIC

SELLIT

PROGRAM RESONANT ACOUSTICE - PLE

PREPARED BY F UMPJ 370 . ref

	10200	101111	_	 		 		 	 	 	r	 	 \neg	
1/28/70		Screening Requirements			•		•							
DATE ZZ	-	Maximum Maximum Iemp (°C) Temp (°C)	0											
- AG		Tolerance Matis) Actual power (watts)	3											
		Agasis tance (Smido)	-72 Stitet											
PART NO.	:	Manufacturer	MIE											
20 3. 5. 5.7	1	Status* Military Specification	MI-K-55/22											
Rem	PAGE	Part Number Sonstruction												
PROGRAFI ASSEMBLY		Circuit Symbol Number	MRS											

220

*See Figure 8 for code.

Screening Requirements Max. Bulk Air Temp (°C) PREPARED BY Duty Cycle DATE Z Operating/ Voltage/ JY Peak Эq Rated Voltage Tolerance Capacitance (bin) CAPALITORS 1,00% 3,34F DOOF 220/2 270° £ 270rt 100 100. 0.1 39 10. Manufacturer PART NO. PART NO. 3+ VC) Military Specification or SCD BVEFG *sn₁e₁s PROGRAM RESOLATASSEMBLY RAM Part Number Sonstruction CKRII こなし CKRII ニャメン CKROS or 5 CKROS 22 CKROS & C5213 CSR13 CKAOS C 5 R A SUMPORTING NAMES 5 C4 | Sinonio 9 20 5 5 67

40141-Y

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221

*See Figure 8 for code.

CALALITORS

PART NO. PART NO. - 1015 SUB ASSY. POWCE PROGRAM

R. C PREPARED BY
DATE 6 - ...
SCHEMATIC

50141-A	-т		_	_	_	_	1	7			\neg		7	1	
Operating AT Screening Voltage Cycle Buc Cycles Requirements Daty English Daty Eng								55							
9) Parence Bettown Bettown Be Sold	7.7	7007	25./	251	2007										
epacitance (bim)	35 26	10001	0.1	1.0	100 pf										
Manufacturer															
iilitary pecification or SCD	MIL. C-39006	M16-6-39014	MK-C-39003	PH. C.39003	MIL.C -39014										
Status*															
art Number and onstruction	2 R65/2	CERI	C5 R 13 / 53410		1CEBAN										
ircuit Mumber	15 0	C2	53	47	CS		22								

*See Figure 8 for code.

CALACITORS

PREPARED BY R. EICHORY
DATE 6-21-76
SCHEMATIC PART NO. PART NO. ASSEMBLY RAM AMPCIFICAL SUB ASSY. POWED AMPCIFICAL

70141-4									 ,		 	 				
Screening Requirements																
Duty Cycle			+	-		-	_									
Operating Voltage Voltage	-															
96 PT TON	_	100	50	200	20	20	50									
Tolerance	6	100%	102	10%	70%	20%	20%						•			
eaneditance (bim)	10.	10.	10	30pf	47hr	IMF	1145			_						
ManufactureM																
Military Specification or SCD	410-C-3014			_	mic-6-39006	MIL -C-39103	MIL-C-39003									
suses												_	-	-	-	
art Number and onstruction	CKROS / CERAMIC	Soci	Soci	205	.65	13 / 504:0	4									
Vouit Vounber	CI CKE	7	-	+	CS CLRGS	+-	+=	┿	+		•					
<u> </u>	<u>. 1 . U</u>	12		<u>. </u>	ست. ا		223		 							

*See Figure 8 for code.

CALHCITORS

PART NO. PART NO.

COMPARTOR

ASSEMBLY RANGE SUB ASSY. PHAGE

PROGRAM

PREPARED BY

V. Er. M. DATE C JUIMI-V

Screening Requirements Max. Bulk Air (2°) qual Duty Cycle Operating/ Voltage/ AC Peak Эq Rated Voltage 20 200 001 es 50 20 20 20 Jolerance 10% 1,02,34 espacitance (bym) 100pt 100 pt 1400. 0. 0.1 o' ö Manufacturer Military Specification or SCO MIL-C-39004 *susess CERAMIC Part Number and Construction CKROS Circuit Symbol Number 87 04 9 Ū

8 for code. *See Figure CAPACITORS

R. EICHDRA PREPARED BY
DATE 6-2
SCHEMATIC

_	4-1410E			7	,	_	_	1	T	_	Т	T	1	T		T		7
DATE 6-21-76 SCHEMATIC	Capacitance (operating voltage Voltage (or Requirements of Voltage Voltage (or Requirements of Voltage of Volt	78 <i>D</i>	100pf 10% 200		0.1 10% 50	1.0 20%50												
PART NO.	Manufary Manufacturer			9	>	. c. 39.w3												
ATOR	*sujaj2	Ē	Ą			PIL												
ASSEMBLY RAMSUB ASSY. OSCILL	Symbol Number Part Number and Construction	0121	Creos Cour		CKROS	_		NPO										
	Circuit	13;	2 6	2	S	9		7							\perp		L	

*See Figure 8 for code.

225

CALACITORS

PROGRAM IZELOGIA IN ANDE ASSEMBLY SINGLE MODE SUB ASSY, NO IN DETECTOR

(SN:

PART NO. PART NO.

PREPARED BY R. E. C. 13...)
DATE 7-23-70.
SCHEMATIC

70141-A									 	 	 	- 1	 - 1	 _
Screening Requirements														
Duty Cycle			+											
Operating Voltage Voltage Voltage														
Capacitance (mfd) Tolerance Rated Volt	45	'n	4	ĄŤ	4	JF.	作	4-						
	10.	220	100 pF	.01 MF	0.1MF	401 UF	101	100 pt						
Manufacturer														
Military Specification or SCD														
Status	11					=,		CKAII						
Part Number and Construction	CL05 12 C			7	CKROS	CKROS SE CKRII	CLEGS	KR05 02						
Circuit Symbol Number	-	22	3	47	153	1		187						

*See Figure 8 for code.

PREPARED BY F. WW CALLUME TO DATE 43476

)	Screening Requirements													14				
DATE (/30/74.	<u> </u>																	
11. 105.11	Maximum Buty Cycle		1										_					1
21	Max. Amblent		1	1	1	+	4	4	+	+	-		_	_			-	1
DATE SCHEMATIC	Rated Power (Watts)	+	+	+	+	+	+	+	+	+	+		H					
. a s	Actual PIV	+	+	+	+	+		+	+	+	T		\vdash	T				1
	Rated PIV			1		7	25	75	25									1
1.1	BV EBO					\parallel	\prod	\parallel	\parallel	-						_	_	
	Actual Rated	+	+	+	+	#	H	H	+	-	+	-	-	-		-	\vdash	
	No bestea GBO FeutoA	+	+	+	+	H	H	\dagger	$\dagger \dagger$	+	+	\dagger	\dagger	t			\vdash	
8 8 9 9	McE0	1	1	1	1	\parallel	\parallel	\parallel										_
PART	Rated						1			1		-	-	-	\perp		1	
(A)	Manufacturer																	
1301	Specification Specification	162/656	162/20561	19300/255	19500/382	11/005/116	411/00561	17500/11.	19500/110									
RAM	*sulais			3														
PROGRAM ASSEMBLY SUB ASSY	Part Number and Construction	A 2507A	2~29074	A ELLE M	2N 2975A	SAL TAN	8414M	SHIPME	ANT-ME									
	Circuit Symbol Number	Ø,	qż	43	*	Ces	E	ŝ	Se.									

*See Figure 8 for code.

14	א־ומוטת	
# 12.2.24 IE	Screening Requirements	
12 / 12 / 12 / 12 / 12 / 12 / 12 / 12 /	Maximum Buty	
PREPARED BY F. WAN GALLINE DATE 7/28/72 SCHEMATIC	Actual power (2°)	
PREPARED DATE SCHEMATIC	TOWOR DO O	
	VId Fated PIV	
	Rena Actual	
	Les Rated	
	Se Sed Sed Sed Sed Sed Sed Sed Sed Sed S	
PART NO. PART NO.	By bated & C	
1	Manufacturer	
POWER SUPPLY	19 Soo / 1 Specification Specification	
11.	*sujejs	
PROGRAM	1837 Series Construction and Construction	
	Jaquin Loquing & S & S	

*See Figure 8 for code.

												İ		ĺ		
Screening	Requirements															
	CACIE Walmum		+				+					1				
MATIC	Actual PC (Watts) (Watts) (C)			1	-		-	+	+	1	1		-			
SCHE	Matted Pow	4.0	0',	1.0	150	140										
	Rated PI	1	4	4	1	#	10	10	101			~	_			
BV _{EBO}		1	1	1	1	-	75	75	75	75	75	13	+			
BV	Rated	6	9	70	7	7	\dagger	\dagger	H	H	1	\parallel	1			
BVCBO	1 EutoA															
	'	60	150	175	60	150						-				
BVCEO	138						4	\perp	Щ	4					_	
L L	Rated	60	120	7.5	3	30	J	1	1	1		-			_	
Ampurica ion	Manufactu _i															
11	Military Specificat	19500/291	19500/36	1750 /357	19500 1379	1950/439 (USAF)	1950 /11c			-		_				
Pou Ce	*sujejs		, S	5		2		2	S	5	\$	2				
ة ال [*]	Part Number Construct	127			JANTKU ZN3792	6				_	143	_				
	Circuit Vmbol Numb	Ó	70	83	_	SO	CRI	C22	63	43	Ses	280				

*See Figure 8 for code.

	ر.،،	Screening Requirements
	~ 14	Agreed Power (Waltes) Wated Power (Waltes)
	PREPA DATE SCHEN	Ald pated Vid bated
SELICOMOGENE	NO.	B CEU32A Sed
	Compar (13)6. PART	Wated Manufacturer Specification Specification Military
	PROGRAM RAM ASSEMBLY RAM	*suisis
	PRC	S CIrcuit Nomiber A Standon Number A Standon

*See Figure 8 for code.

R. EICHORN

PREPARED BY

1/01/1

Screening Requirements Maximum Duty Cycle -21-70 Actual power ("Watts") SCHEMATIC Rated Power (Watts) DATE Actual PIV Rated PIV BV_{EB0} 1 Eugs Rated leusoA /BV_{CB0} Rated BV_{CE0} leu32A PART NO. Rated Manufacturer ASSEMBLY RAM SUB ASSY. OSCILLATOR Specification specification *snzezs Part Number Construction 2H 2945A JANTED Circuit Symbol Number 02 ব

8 for code. Figure

	MIIN V			 							 	 	
	Screening Requirements						•						
12	Maximum Duty												
,1 and 1	Juai dina qual	<u> </u>											
PREPARED BY DATE 7	Rated Power (watts)				-								
	Actual priv												
	Mctual My	75	5/										
	Rated Rated I have												
	Rated BV CBO												
NO.	Actual Actual		,										
PART N	Rated								-				
30.	Manufacturer												
4 4 5 2020	Military Specification	145 DOLE .	0 11.0			 							
3 7 6	Status*												
PROGRAM ASSEMBLY SUB ASSY	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	14 011						k					
	t tusy ts	187	CRZ					=					

*See Figure 8 for code.

MICROELECT..JAICS

\	€01hI-¥						1			γ						 - 1	 —
76	Screening Requirements																
PREPARED BY <u>た</u> DATE <u>フース ら</u> SCHEMATIC	Max. Ambient Temp (3°) Max. Ambient Max. Buty Cycle (3)													-			
PRE DAT	Current Voltage Actual Rated Actual																
	Military Specification and Manufacturer Rated																
	alvis as																···
Acoustic Gans PART NO.	ABUM AYED	70-01	TO 5%	70-36													
	sustus	7		1						-							
PROGRAM PCSSNAST ASSEMBLY CANS SUB ASSY. INPUT BUFF	Part Type and Construction	9-2510-8	9-2510-8	9-25,0-8													
	J. V. Cu J. E. Mumber	A1 H4.9	12 149-9-	A3 HA	-	_		2:	33			-	-		_		

*See Figure 8 for code.

MICROELECTRUNICS

PREPARED BY R. E. HOZ.

-	E0141-A					 		11	_	٦
PRE DAT SCH	Military Specification Specification Manufactured Noltage Duty Specification Specification Specification Manufactual Manufactual Max. Buty Max. Bated Actual Max. Buty Max. Bated Morting Morting Max. Bated Morting Morti									
PART NO.	Part Number and Case Style	CO1-07 25CAM								
Kadars	*Suj PjS		\Box	\sqcap	\Box	П				
NE BY	Circuit Winbol Number Bart Type and Construction	TAP.								
	41hou10	4 5		\perp	234					

*See Figure 8 for code.

MICROELECT MUNICS

Screening Requirements PREPARED BY R. EICHDEN DATE 6-21-76 HARRIS (S) Cycle Max 1 Ambrent (3°) SCHEMATIC_ у х Гетр Electrical Stress Voltage Retual basea Current leu32A Rated S Specification and Manufacturer 10-06 Part Number and Case Style PART NO. PART NO. 149-2510-8 DUNG *susess PROGRAM ASSEMBLY RAM SUB ASSY. POWAR America Part Type Construction OPERATIONAL Circuit Symbol Number

A

235

EOIHI-A

*See Figure 8 for code.

PART NO. PROGRAM
ASSEMBLY RAM
SUB ASSY. PUAJE COMPOSITOR

PREPARED BY R EICHDERS
DATE 6-21-76
SCHEMATIC

€0141-A				 		 		 -	 -	 		 1	1
Screening Requirements	ANALOL DE JUES				-								
Cycle (c)													
Temp Ambient													
Stre													
Rated													
Electr Current Actual							-						
Raturacturer	2		 _										
Military Specification and Manufacturer	N 5092 ARG-007	M38513/ 10104 BGD		•									
Part Number and Style	-10	LM108A											
*su ^{ses}													
Part Type and Construction	17	OPERATIONA AMPLIFICA											
Circuit	Ā	AZ		2	36								

*See Figure 8 for code.

EOIHI-A

MICROELECTKUNICS

Screening Requirements PREPARED BY R. EICHUR 21-70 Duty (%) Cycle 3 no i dmA · x 6M (3°) qmo I **SCHEMATIC** Stress DATE Voltage 1 Eus JA Electrical bas ted Current 1 Eus 2 A Rated Specification and Manufacturer M38510/ 10104 BGD NSPAR ARE -16 AN Case Style PART NO. PART NO. XR 2206M, LM108A ASSEMBLY RAM SUB ASSY. OSCILLATOR *susess *BENBATOR* OPERATIONAL AMAJETA Part Type bnb Construction PROGRAM FUNCTION Number Circuit Symbol N AZ A

237

*See Figure 8 for code.

MICROELECT. ICS

PREPARED BY F VAN GILLUME Acoustic GALF

n	⊊olhI-∀				1 1		1			1 7				 	1
7/28/36	Screening Requirements														
	Temp (°C) Max. Duty (°C) (°C)	000	20%	Ś											
DATE SCHEMATIC	Voltage Actual Good (3°)	206	9	20.6	++				-			-			-
	Rated <	2 2	2	73											1
	Electri Actual								_	-		\perp			
11	PATPA		-	-		-	-	$\left \cdot \right $	-		$\left \cdot \right $	+	+	-	_
	Military Specification and Manufacturer														
ART NO.	Part Number and Case Style	70-36		8A TO.79											
ACOUSTICE P		PAH 9	16 8	780 /W7											
K	Status*														
PROGRAM RESUMANT ASSEMBLY RAM SUB ASSY. NOISE D	Part Type and Construction	1 1	00-AMP	OP-AMP	21										
	Circuit Viibol Number	₩.	42 00	1	2	38									

*See Figure 8 for code.

APPENDIX D NONSTANDARD PARTS APPROVAL REQUEST



C/N 7141.223

NON STANDARD CAPTS APPROVAL REQUEST

(1)	NSPAR No. ARG-002	(2)	Date: 5/21/76	
(3)	Prime Contractor: Acurex	(4)	Contract No. F0470	141-75-C-0164
(5)	Part Nomenclature: Multiplier	(6)		
(7)	Circuit Symbol: N/A	(8)		_
(9)	Mfgr. Part No. AD532SH	(10)		
	. •			
(11)	Justification for Use:		,	
	•			
•	See Page 2			
(12)	Application Data:			
,				
(13)	Test Data/Remarks:			
				•
	* 2			
_	ared by Flower E. Vyse		Requested by RL	5.1
Prep	Signature Signature			nature
				,
<u>Part</u>	s Control Board Action:			
	Step 1 - NSPAR	`	Step 2 - SCD	
Appr	oved Chancell	An	proved	
Inte	rim V(5/K4/1/2) Aerospace	In	terim	Aerospace
Disa	pproved	Di	sapproved	
	SAMSO	1	-	SAMSO
	Laur lambe	-		·
	Acurex	7.5	-	Acurex
STep	I e attached Comments			
Sc	e attached Commerce			

ARG .002

- (11) There is no standard part available to perform this function. Approximately 14 transistors, 15 resistors, and one non-standard operational amplifier would be required to replace this device. (A schematic using mostly standard parts can be supplied upon request.) Engineering judgement indicates that reliability would be sacrificed by attempting to implement this function with standard parts.
- (12) This circuit will be used as a phase comparator, and one will be required per system.

In the circuit configuration which is planned, the device will be used under the following conditions:

Condition	Rated <u>Maximum</u>	Max. Circ. Stress	% of <u>Rating</u>
Supply Voltage	<u>+</u> 22V.	<u>+</u> 11 V.	50% 13%
Power Consumption	500 MW.	66 MW.	136

(13) Acurex Products Division has used this device of this family type in standard products used in severe environments. Since they do not keep failure records, no specific data is available. However, the devices are not known to be a problem.

Devices of this same family have been used in the Acoustic Gage for the past year / with no failures or performance degradation. (Befashome & GROWN TEST ELECTRICAL)

Several other microcircuits (non-standard) are available to perform this function. This one has been chosen because it requires a minimum of external parts. Other / devices also require variables resistors for trimming, which are definitely restricted on this program.

ARG-002

- There was no indication that an alert search had been conducted.

 There is a recent alert (3/31/76) GD-A76-02 which specifies internal corrosion in AD532 device. Also there are several other alerts on Arms 10-2 500 series devices reporting bonding/open metallization problems and photolith deficiencies.
- 2. What is the qual status and environmental capability of the part?
- 3. Has the supplier any records of other military program on which the part has been used and its track record?
- 4. Is there just one part used per vehicle?

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5. Any special handling plans required for this device?



NON STANDARD PARTS APPROVAL REQUEST

(1)	NSPAR No. ARG-003 (2)	Date: <u>May 21, 1976</u>
(3)	Prime Contractor: Acurex Corporation (4	Contract No. <u>F047041-75-C-0164</u>
(5)	Part Nomenclature: Operational Amplif(6)	Part Used In: <u>Recession Gage</u>
(7)	Circuit Symbol: N/A (8)	Manufacturer: Harris Semiconductor
(9)	Mfgr. Part No. <u>HA-2510-8</u> (10)	Specification: MIL-STD-883 Level B
	70-86 Package	
(11)	Justification for Use:	
•	None of the allowed group I operational for adequate circuit operation. A disc transistors, 8 resistors, and would con	amplifiers have the required power bandwidth rete substitute would require at least 10 sequently be far less reliable.
(12)	Application Data:	
	See Page 2	
(13)	Test Data/Remarks:	
	Acurex has been using the commercial gra have proven themselves to be quite relia	de of this amplifier for years, and they ble.
Prep	ared by Fhomos G. Vyfe Signature	Requested by RL Silon Signature
<u>Part</u>	s Control Board Action:	
	Step 1 - NSPAR	Step 2 - SCD
Appro Inte Disa	rim / (3/25/76) Aerospace I	pproved Aerospace isapproved
	Samso Compo	SAMSO
م مر اب	Acures	Acurex
tep	eattached Comments	

(12) Application Data

The HA2510-8 will be used several places in the circuit.

1. As the input buffer amplifier.

In the 800 KHz noise detector as a 20 db amplifier.
 As a basic amplifier in the transmitting crystal driving amplifier.

Worst case circuit usage will be:

Condition	Rated	Max	% of
	Max	Circuit Use	Rating
Absolute voltage V+ to V- Differential input voltage Peak Output Current Internal Power Dissipation	40.0V + 15V 50 MA 300 MW	92V (20'b) < 1 Volt 10 MA 192 MW (47 Jan) 12 4	90% 527. < 10% 20% 54% 41%.

ARG-003

- 1. Justification for not maintaining at least a 50% derating on power dissipation required.
- 2. A thermal transfer analysis shall be provided showing maximum junction temperature.
- 3. There was no evidence that an alert search had been made. There have been several alerts written against the part. Basically it was for slew rate induced errors. GIDEP Report No. N7A73-01.
- 4. What is qual status and environmental capability?
- 5. How many parts per system are used?

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NON STANDARD PARTS APPROVAL REQUEST

	(1)	NSPAR No. ARG-004	_ (2)	Date: May 21, 197	6	
	(3)	Prime Contractor: Acurex	_ (4)	Contract No. F04	7041-75-C-0164	
	(5)	Part Nomenclature: Op Amp	_ (6)	Part Used In: Reces	sionGage	
	(7)	Circuit Symbol: N/A	_ (8)	Manufacturer: Fairc	hild Semi. Mt. View, (Ca.
	(9)	Mfgr. Part No. <u>UA108AHMQB</u>	_ (10)		<u>ue 38510 proces</u> sed Class B	
	(11)	Justification for Use:				
		None of the group 1 operational and meet the required circuit performa	•	ers have low enough i	nput bias currents to	
	•					
	(12)	Application Data:				
		Will be used as an integrater to cappropriate derating. In use the (Continued on page 2)				
	(13)	Test Data/Remarks:				
		This operational amplifier has per It is included in Part 2 of QPL385 highly reliable part.				
	Prep	ared by Thomas G. Nys	c	Requested by Requested by Sig	L Eilen nature	
	Part	s Control Board Action:		•		
		Step 1 - NSPAR /2	_	Step 2 - SCD		
		Step 1 - North	11)	·	`	
1	Inte	rim \(\(\frac{3/25}{3/25/76}\) Aerospace pproved	Ti	oproved nterim isapproved	Aerospace	
		SAMSO	2/	,	SAMSO .	. •
s :	tep.	Acurey (Mi	120	·	Acurex	
ی	ee.	I Hached comments				

Page 2

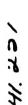
ARG-004

Condition	Maximum <u>Rating</u>	Voltage	Rating
Condition Supply Voltage Interval Power Dissipation Differential Input Current	+ 20V 500 MW + 10MA + 10V	+ 10V 12 MW <+ 1MA + 5V	50% 3% <10% 50%
Input Voltage	_	T	

ARG-004

- 1. What would the penalty be if standard parts were used?
- 2. Was an alert search performed?
- 3. Has the part been used on other military programs and was it satisfactory?
- 4. What is the environmental capability of part? 38510
- 5. Any special attention plans for handling and assembly this device into hardware?

1) Deff par low current level, parather transitor 1/2 Parene Parts. 4/19/08 low him





NON STANDARD PARTS APPROVAL REQUEST

(1)	NSPAR No. ARG-005	(2)	Date: 0-21-76	
(3)	Prime Contractor: Acurex	(4)		
(5)	Part Nomenclature: Capacitor	(6)		
(7)	Circuit Symbol:	(8)	Manufacturer: VITRAMON	
(9)	Mfgr. Part No. CYR41E102G	(10)	Specification:	
(11)	Justification for Use: The gage measurement accuracy is for the voltage controlled oscil rature coefficient. No known state	lator.	dant upon a stable RC time constant Thus a capacitor with a low temper- part meets the requirement.	
(12)	Application Data: Used as the timing capacitor for Rated Voltage: 100 V Actual: 21 V	dC	voltage controlled oscillator.	
(13)	Test Data/Remarks: Temperature coefficient ± 25 P.P function are CCRO5 ceramic (MIL-	.M., o	other capacitors available for this	
	€			
Pre	pared by 2000 L-Sil Signature	<u>-</u> -	Requested by Royald Englishment Signature	•
Par	ts Control Board Action:			
	Step 1 - NSPAR		Step 2 - SCD	
Int	erovedAerospace		Approved Aerospace Disapproved	
	SAMSO aug come	ho	SAMSO Acurex	



NON STANDARD PARTS APPROVAL REQUEST

25%	(1) (3) (5) (7) (9)	Prime Contractor: Part Nomenclature	Acurex Transistor TX 2N5038	(4) (6) (8)	Date: 6-22-76 Contract No. I Part Used In: Manufacturer: Specification	Power Ar	in the terms of th	F)
1416	(11)	The power ampli	r Use: fier requires high in order to avoide standard parts do no	exce	essive currents	at high	ith fast frequencies.	
	(12)	Application Data Will be used in KHz (see page 2).	the power amplifier	driv	ing a reactive	load at	10 KHz to 100	
	(13)	■1 xx 3 € xx ■ 1x ■	<u>s:</u> ble JTX and is thus	a Gr	oup II part			
			jnature		Requested by	Sign	WI La	L.
	Par	Step 1 - NSPAR	Action:		Step 2	- SCD		
•	Int	oroved	Aerospace		Approved Interim Disapproved	And Angus and An	Aerospace	* === +
			SAMSO (_	SAMSO	
			Acupex /	A CO			Acurex	and the second

(12) Application Data:

	Rating	Ł	Actua	1
Collector Base Voltage	150	٧	32	٧
Collector Emitter Voltage	90	٧	32	٧
Emitter Base Voltage	7	٧	2	٧
Continuous Collector Current	20	Α	.5	Α
Peak Collector Current	30	Α	1	A
Continuous Base Current	5	Α	.05	A
Power Dissipation	140	Α	4	W



NON STANDARD PARTS APPROVAL REQUEST

	(1)	NSPAR No. ARG-007 (2)	Date: 6-21-76	
	(3)	Prime Contractor: Acurex (4)	Contract No. F04701-7	75-C-0164
~	(5)	Part Nomenclature: Function Generator (6)		Recession Gage
5	(7)	Circuit Symbol: N/A (8)		
25	(9)	Mfgr. Part No. XR2206M (10)		D-883A Level B
	(9)	MIGI. Tare no. MELOGI.		
1416	(11)	Justification for Use:		
		SEE PAGE 2		
	(12)	Application Data:		
		SEE PAGE 2		
	(13)	Test Data/Remarks:		
		SEE PAGE 2		
	Pre	pared by Royald L. Signature	Requested by Sign	ld L. Cilmature
	Par	ets Control Board Action:		
		Step 1 - NSPAR	Step 2 - SCD	
	In	provedAerospace	Approved Interim Disapproved	Aerospace
	Dis	sapproved		SAMSO
		Acupy Climb		Acurex



NON STANDARD PARTS APPROVAL REGULSI

	(1)	NSPAR NO. ARG-008	Acurex	(4)	Contract No. FO4	701-75-C-0174	
Ç	(5)	Part Nomenclature:	Transformer	(6) (8)	Part Used In: Acc	oustic Recession Gaye ality Transformer	
141 Dec	(7) (9)	Circuit Symbol: Mfgr. Part No <u>No</u>		(10)		IL-I-27D	
1116	(11)	The Acoustic Re an acoustic sig voltage (about the maximum pow required to pro Application Data: Transformer will be tuned using	cession Gage uses a nal in the RV Noset 100 volts RMS) to p er supply available vide the high volta	orovione is of the second seco	inis crystal required sonly 28 volts D.C with a maximum of indutance. Rati	c crystal to induce uires a high excitati ignal/noise rate. Si ., a transformer is	
	(13)	Trnasformer des	ign is not complet	nd An	a torroid core.	tion of piezoelectric ferroxcube series mately 1000 microhen	
	Pre	epared by Roma Sig	ld 1. Euchon	•	Requested by	Rignature Signature	In
	Par	rts Control Board A	ction:		Step 2 -	ccn	
		Step 1 - NSPAR				300	
	In	proved terim sapproved	Aerospace		Approved Interim Disapproved	Aerospace	*
~	U	ankhi o roa	SAMSO ()		11	SAMSO	•
			Taling the	1/2-		Acurov	

(11) Justification for Use:

There is no standard part which will perform this function. The requirement is for a precision voltage controlled oscillator with a sine-wave output, capable of operating from 10 KHz to 100 KHz with a linear, repeatable, and stable voltage to frequency relationship.

A circuit to perform this function using only standard parts would be quite complex. A preliminary investigation indicates that 39 transistors, 24 resistors, and one operational amplifier would be required to replace this one microcircuit. Although no reliability calculations have been made, engineering judgement is that the circuit made from standard parts would be far less reliable. (A sketch of the circuit using standard parts is available upon request.)

(12) Application Data:

This microcircuit is the key element which translates resonant frequency to voltage. It will be used once per system. The unit will be used in a circuit which will provide the following maximum stresses:

Parameter	Rated Maximum	Max. Act. Voltage	Percent of Rating	
Power Supply Voltage Power Dissipation Timing Current (Pin 7)	26 V 750 MW 6 MA	20.6 V 10.3 350 MH 169 0.2 MA	3% 40% 3% 22%	

(13) Test Data/Remarks:

16.3 MA MAK I

Exar Integrated Systems Inc is a well established semiconductor manufacturer in Sunnyvale, California. Acurex does not have a large amount of experience in using Exar parts, and no problems related to that manufacturer are presently known. Exar is set up for, and they actively screen parts to MIL-STD-883A. All classes.

There are several other microcircuits on the market which nearly meet the requirements buttonly one other circuit which could replace it (Intersil 8038-See ARG001). This particular microcircuit was chosen because of less power supply sensitivity and fewer external parts when used in the configuration necessary for performing the recession gage function.

The XR2206M does not use any processes listed as restricted in the parts control program plan, whereas the Intersil devices uses film resistors. This NSPAR supercedes and cancels ARG-001.